

Occupied Bandwidth

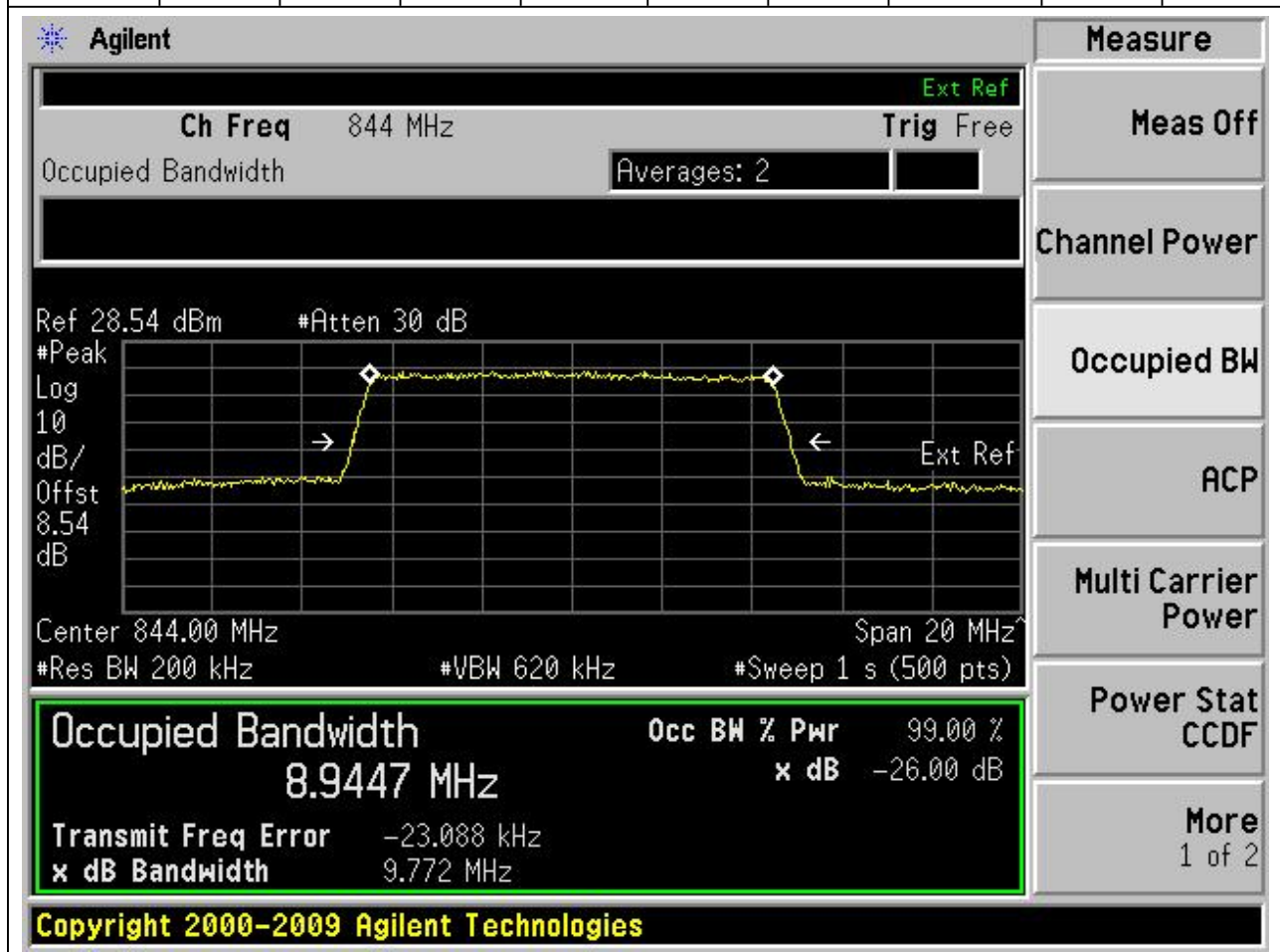
3.24. LTE Occupied Bandwidth_Part22-24-27(Channel:20600, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
844	99	26	0.2	Peak	8.54	8.94	9.77	10	Pass



4. LTE_Band7

EUT Sample No.:	
EUT Name:	
EUT Manufacturer:	
EUT Model:	
EUT Serial Number:	
EUT Hardware Version:	
EUT Software Version:	
Low Temperature(LT):	-10 °C
Normal Temperature(NT):	+25 °C
High Temperature(HT):	+55 °C
Low Voltage(LV):	3.6 V
Normal Voltage(NV):	3.8 V
High Voltage(HV):	4.2 V

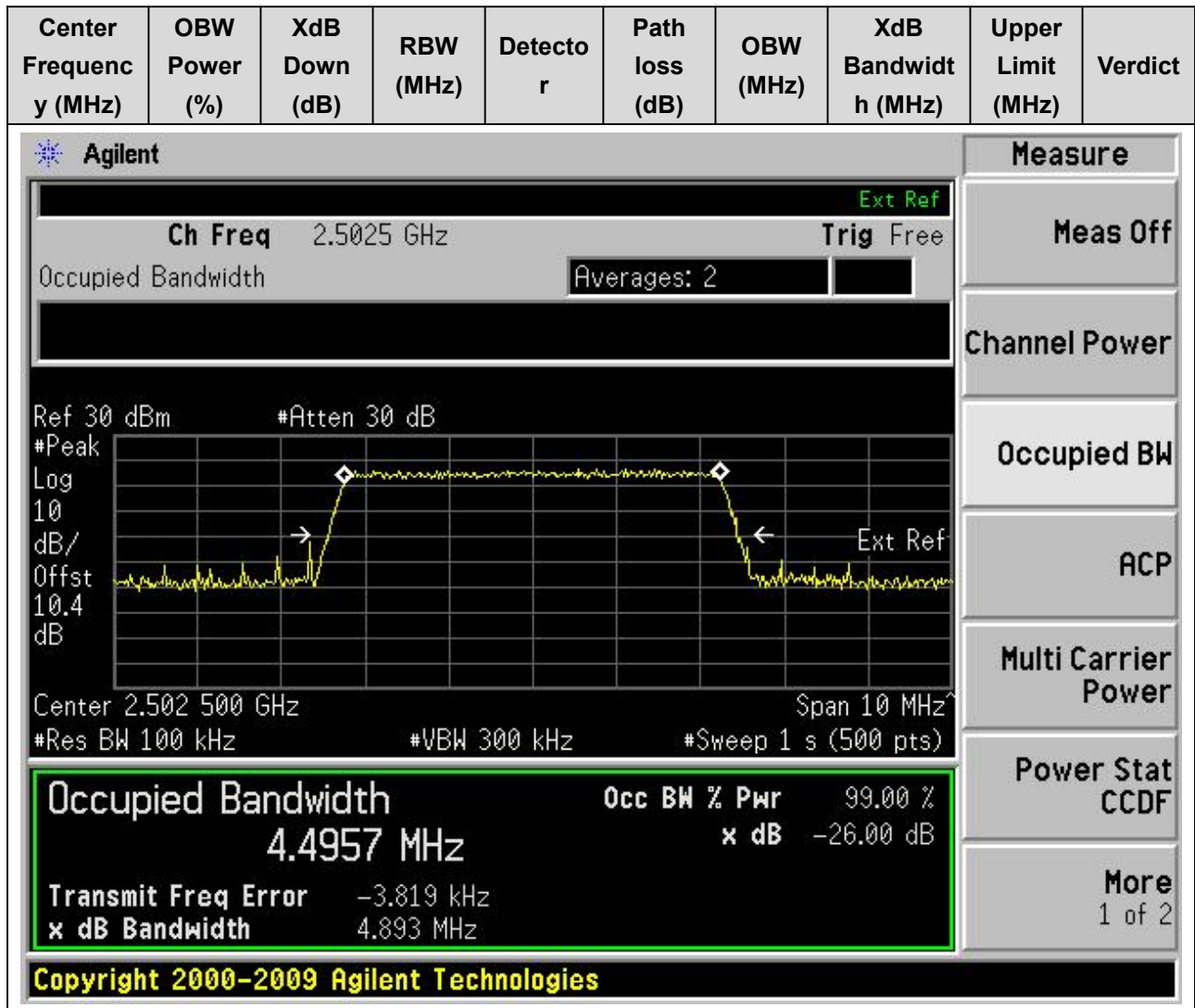
4.1. LTE Occupied Bandwidth_Part22-24-27(Channel:20775, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2502.5	99	26	0.1	Peak	10.42	4.5	4.89	5	Pass



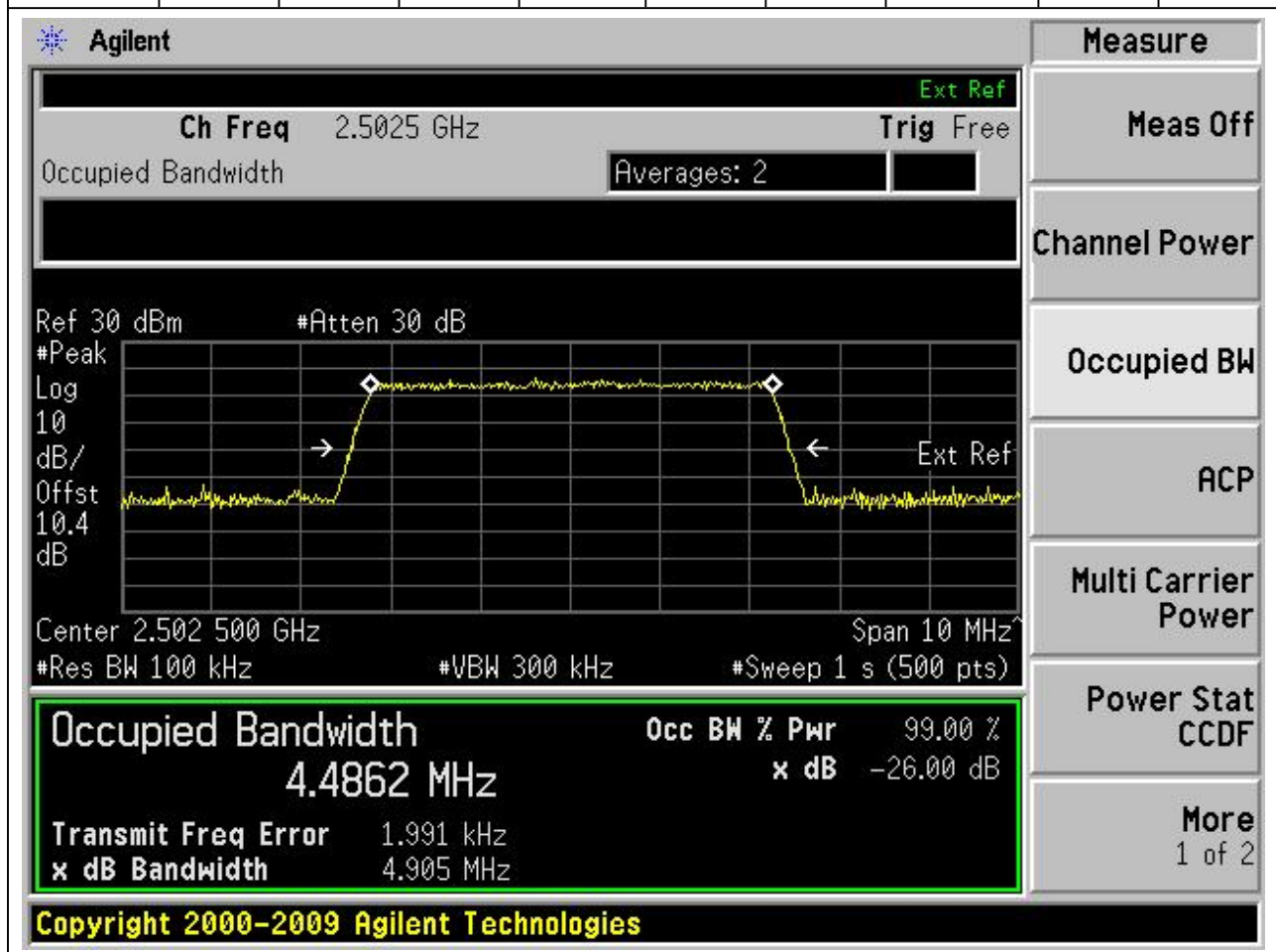
4.2. LTE Occupied Bandwidth_Part22-24-27(Channel:20775, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2502.5	99	26	0.1	Peak	10.42	4.49	4.9	5	Pass



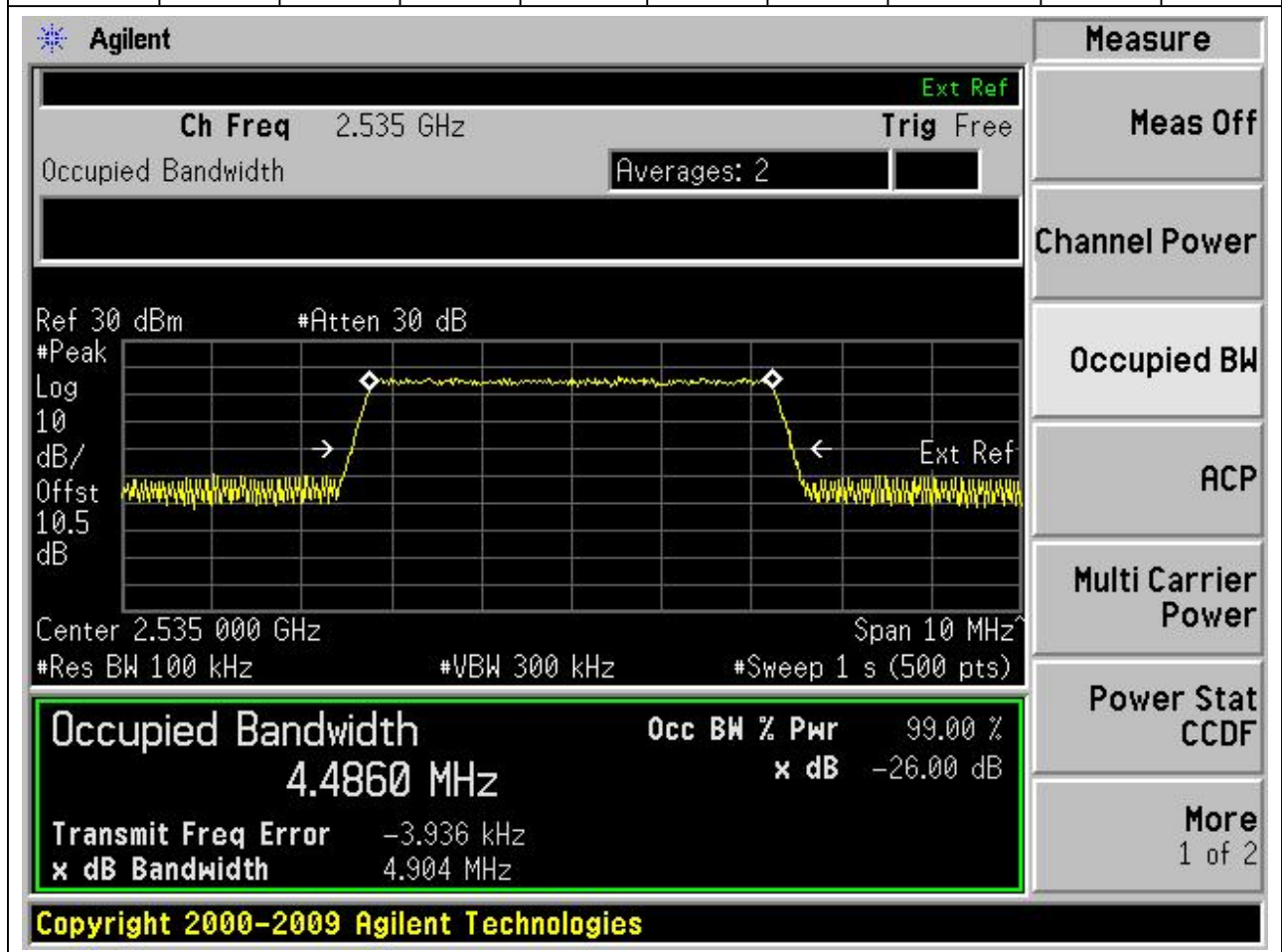
4.3. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.1	Peak	10.46	4.49	4.9	5	Pass



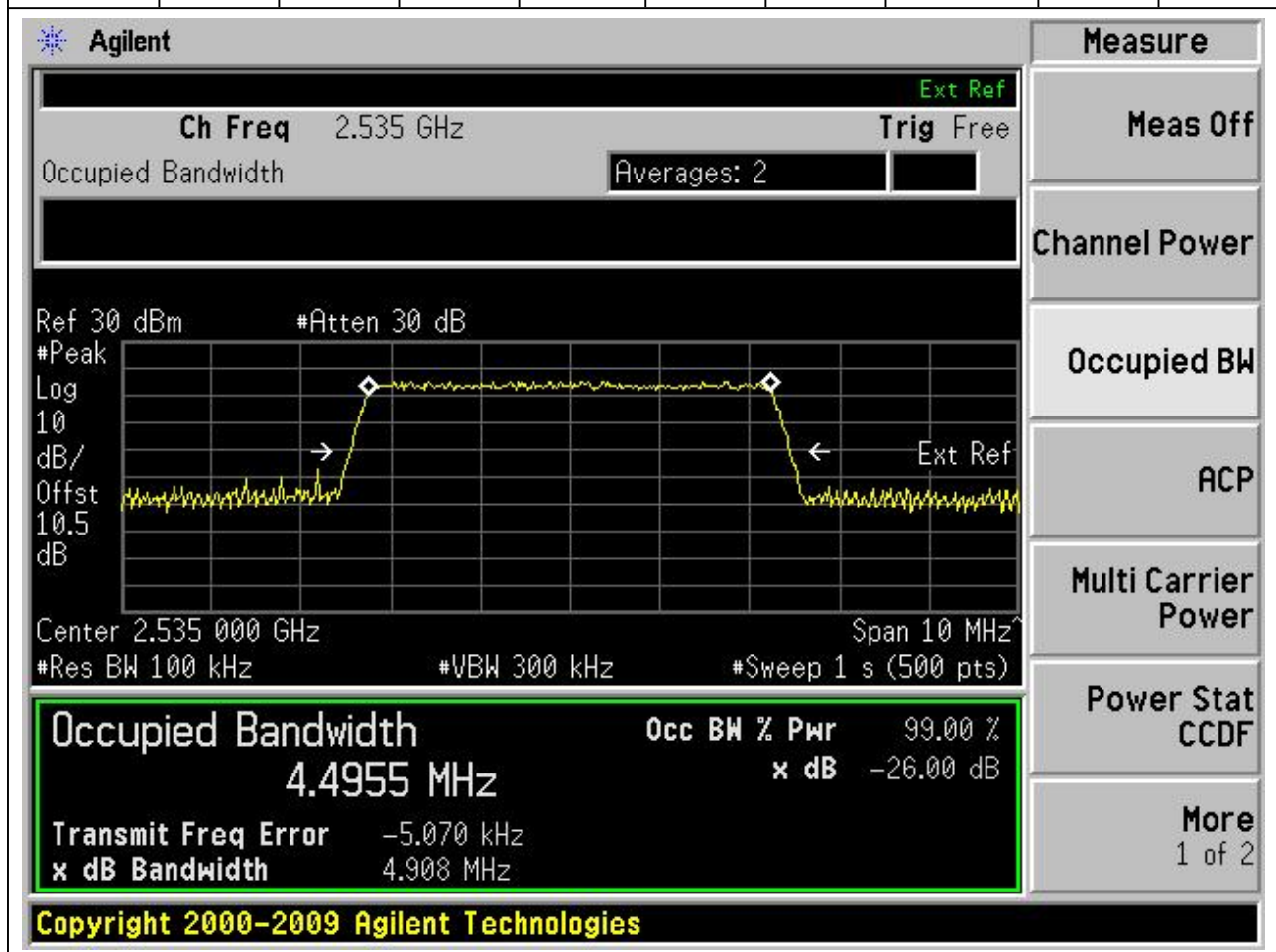
4.4. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.1	Peak	10.46	4.5	4.91	5	Pass



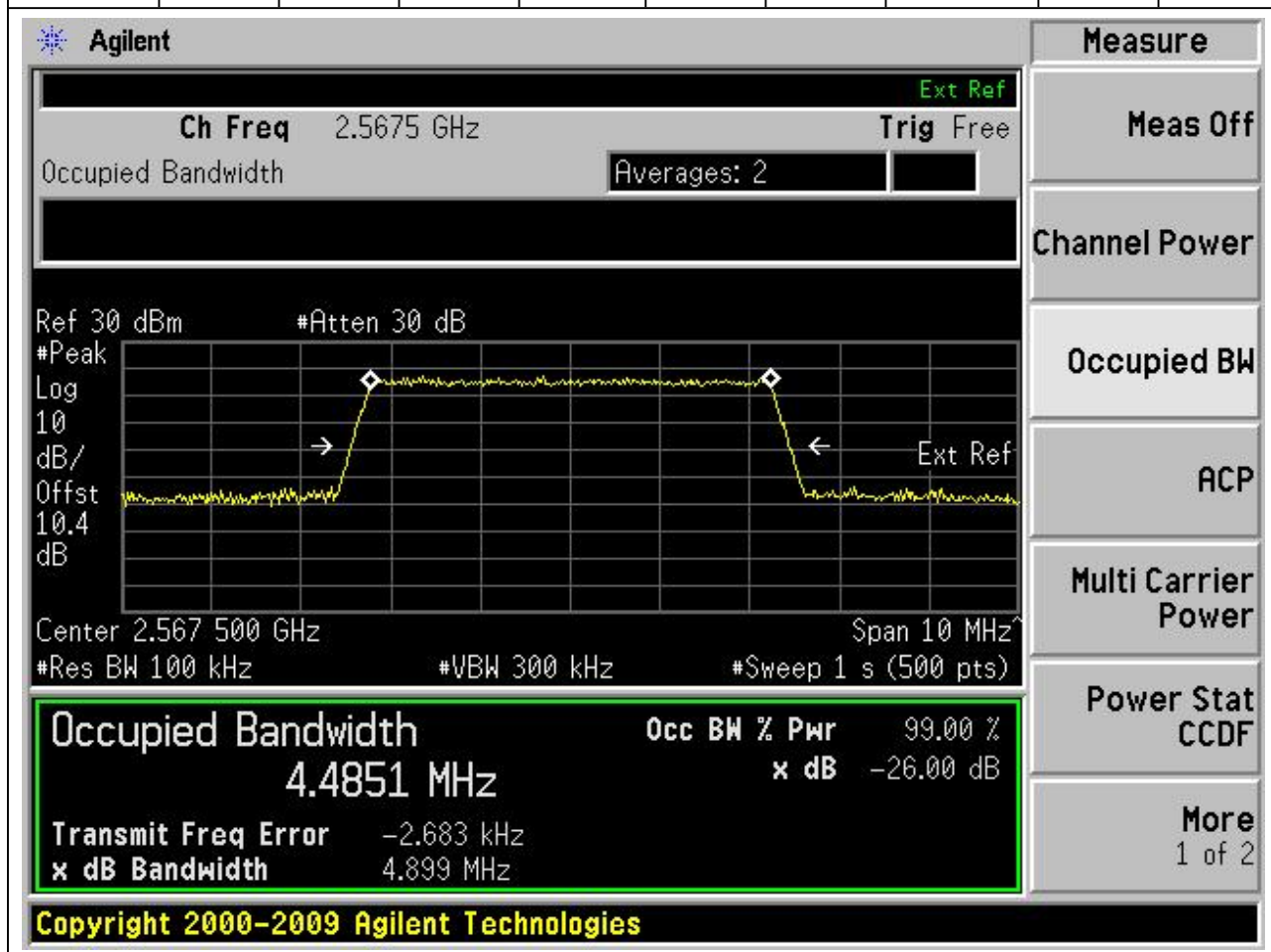
4.5. LTE Occupied Bandwidth_Part22-24-27(Channel:21425, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2567.5	99	26	0.1	Peak	10.42	4.49	4.9	5	Pass



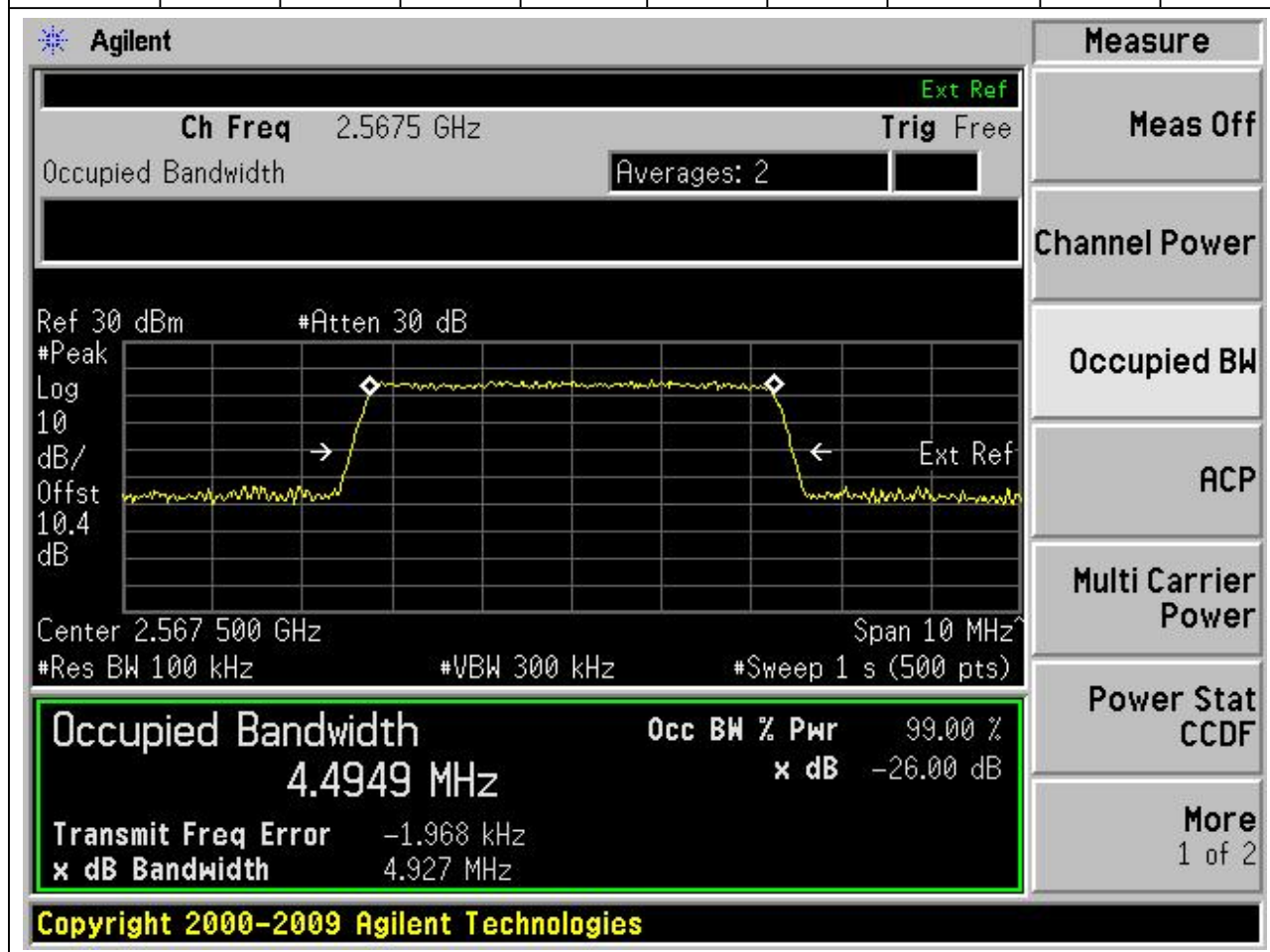
4.6. LTE Occupied Bandwidth_Part22-24-27(Channel:21425, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2567.5	99	26	0.1	Peak	10.42	4.49	4.93	5	Pass



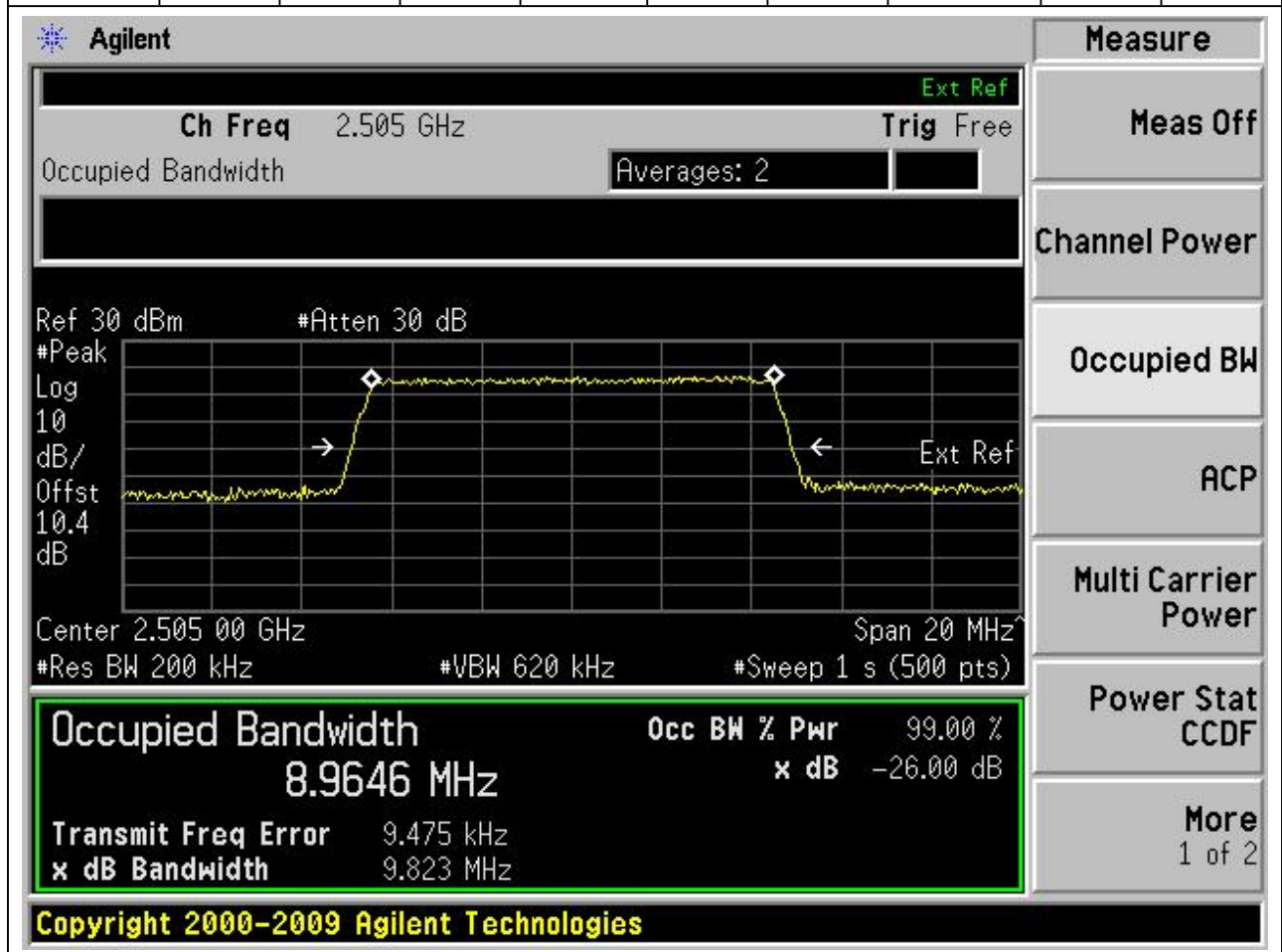
4.7. LTE Occupied Bandwidth_Part22-24-27(Channel:20800, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2505	99	26	0.2	Peak	10.41	8.96	9.82	10	Pass



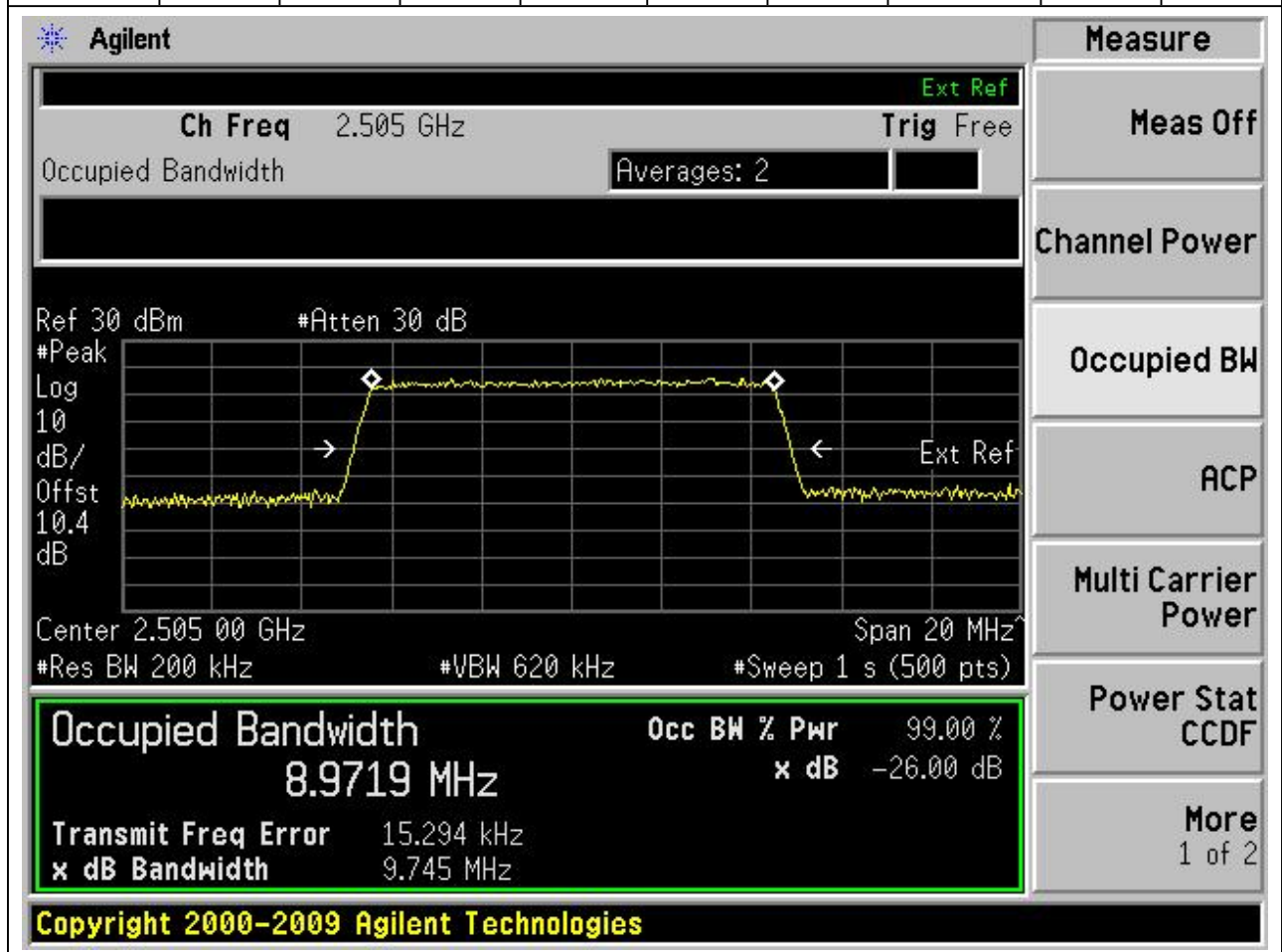
4.8. LTE Occupied Bandwidth_Part22-24-27(Channel:20800, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2505	99	26	0.2	Peak	10.41	8.97	9.74	10	Pass



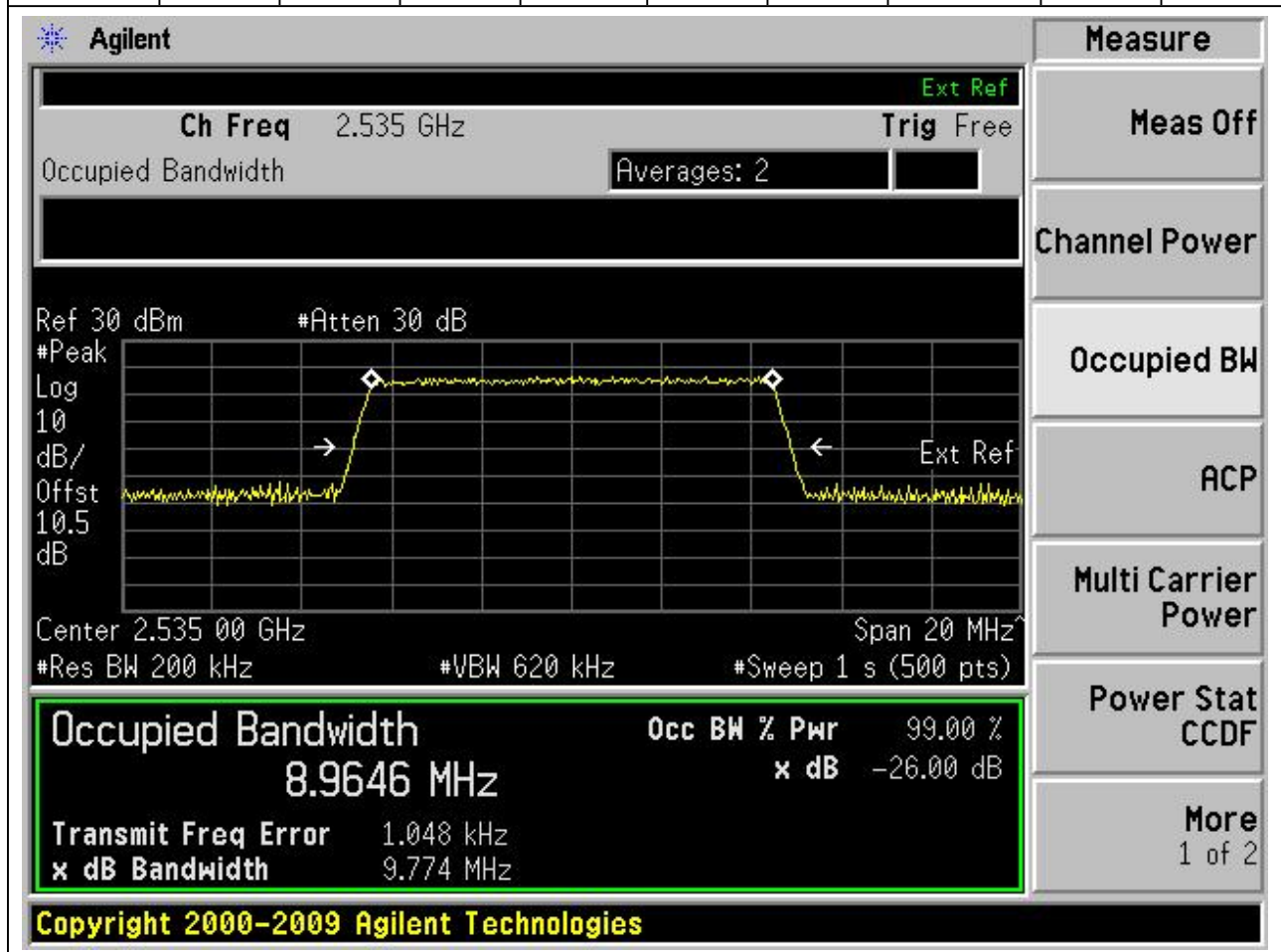
4.9. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.2	Peak	10.46	8.96	9.77	10	Pass



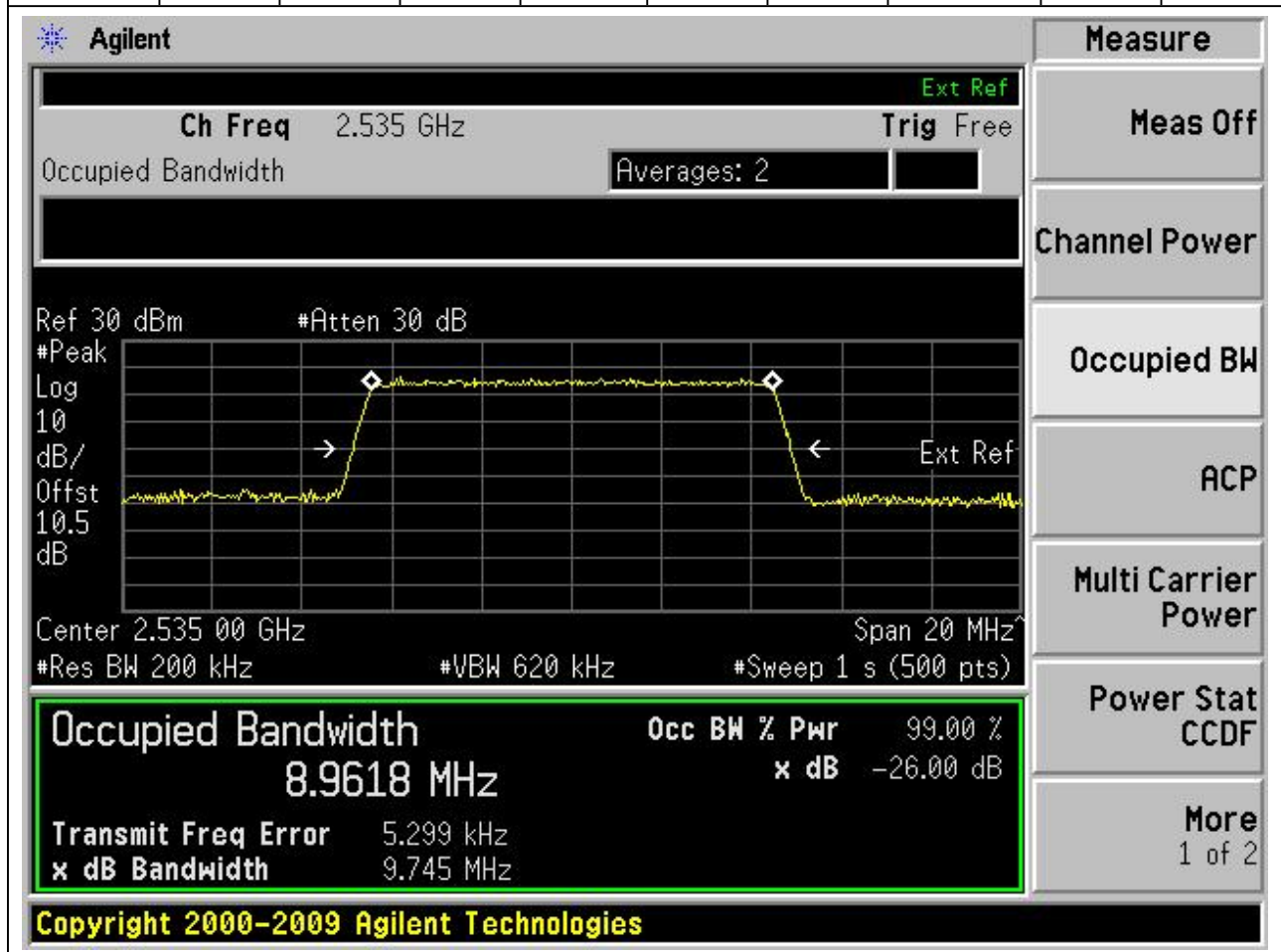
4.10. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.2	Peak	10.46	8.96	9.74	10	Pass



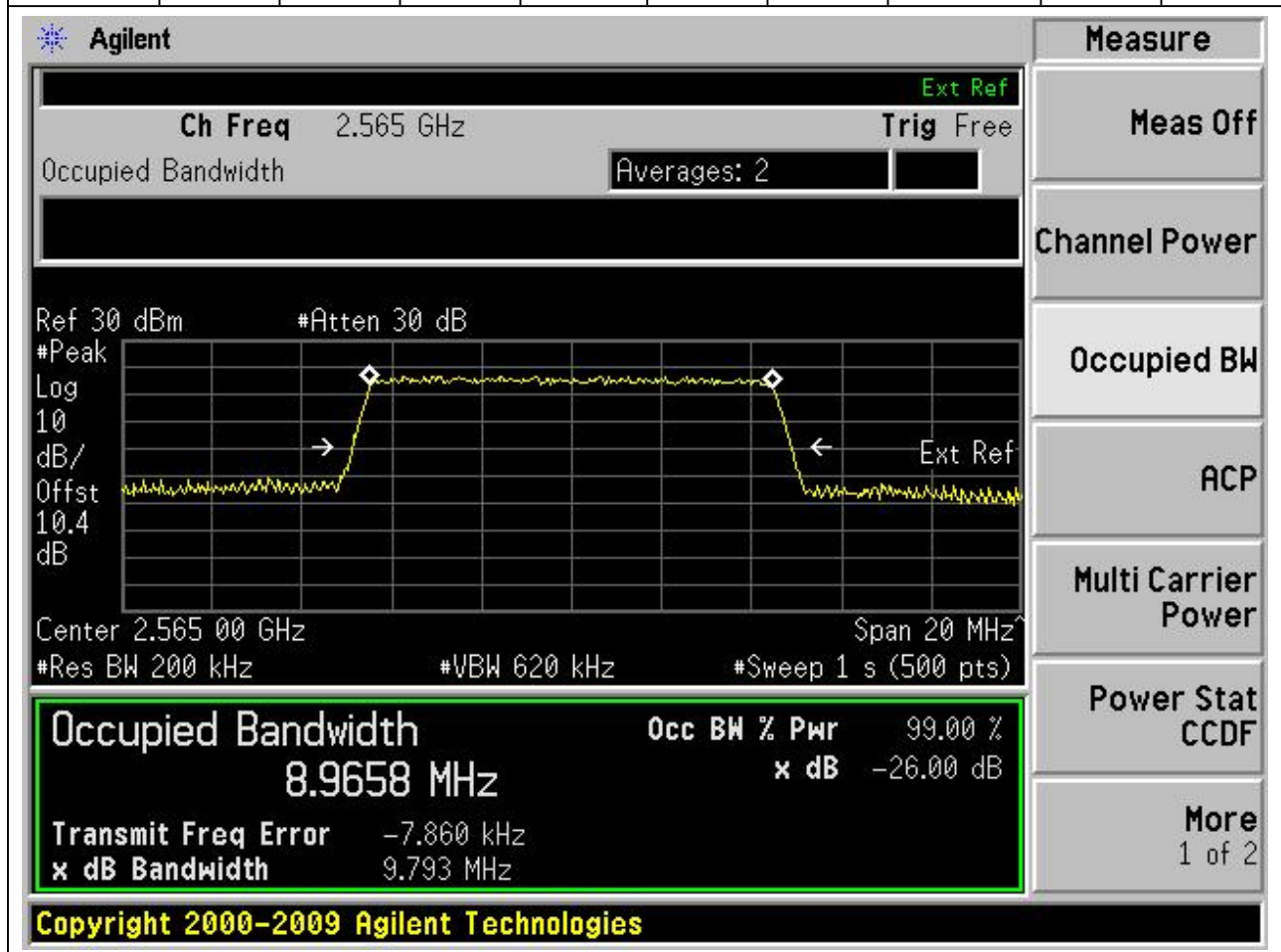
4.11. LTE Occupied Bandwidth_Part22-24-27(Channel:21400, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2565	99	26	0.2	Peak	10.41	8.97	9.79	10	Pass



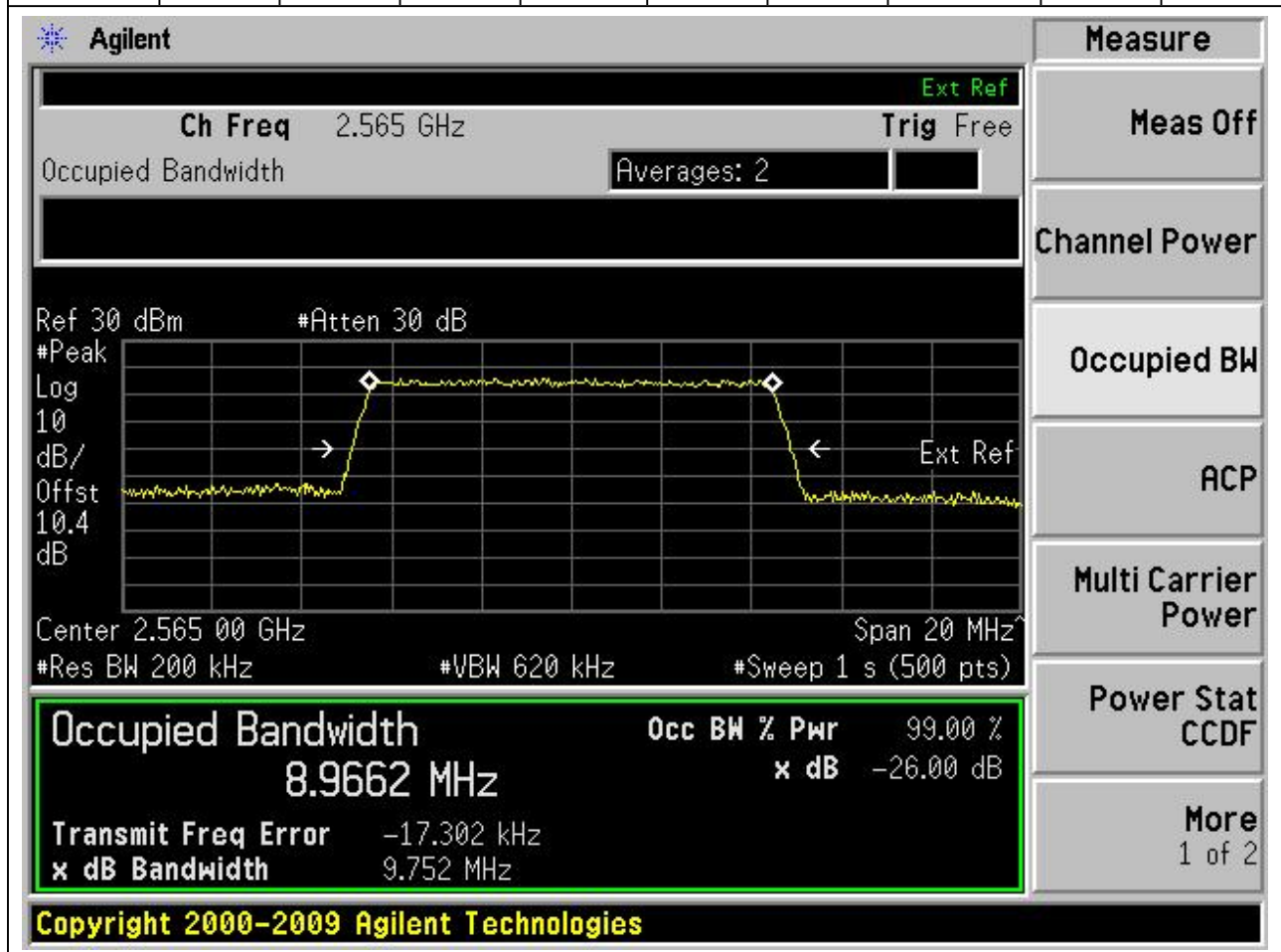
4.12. LTE Occupied Bandwidth_Part22-24-27(Channel:21400, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2565	99	26	0.2	Peak	10.41	8.97	9.75	10	Pass



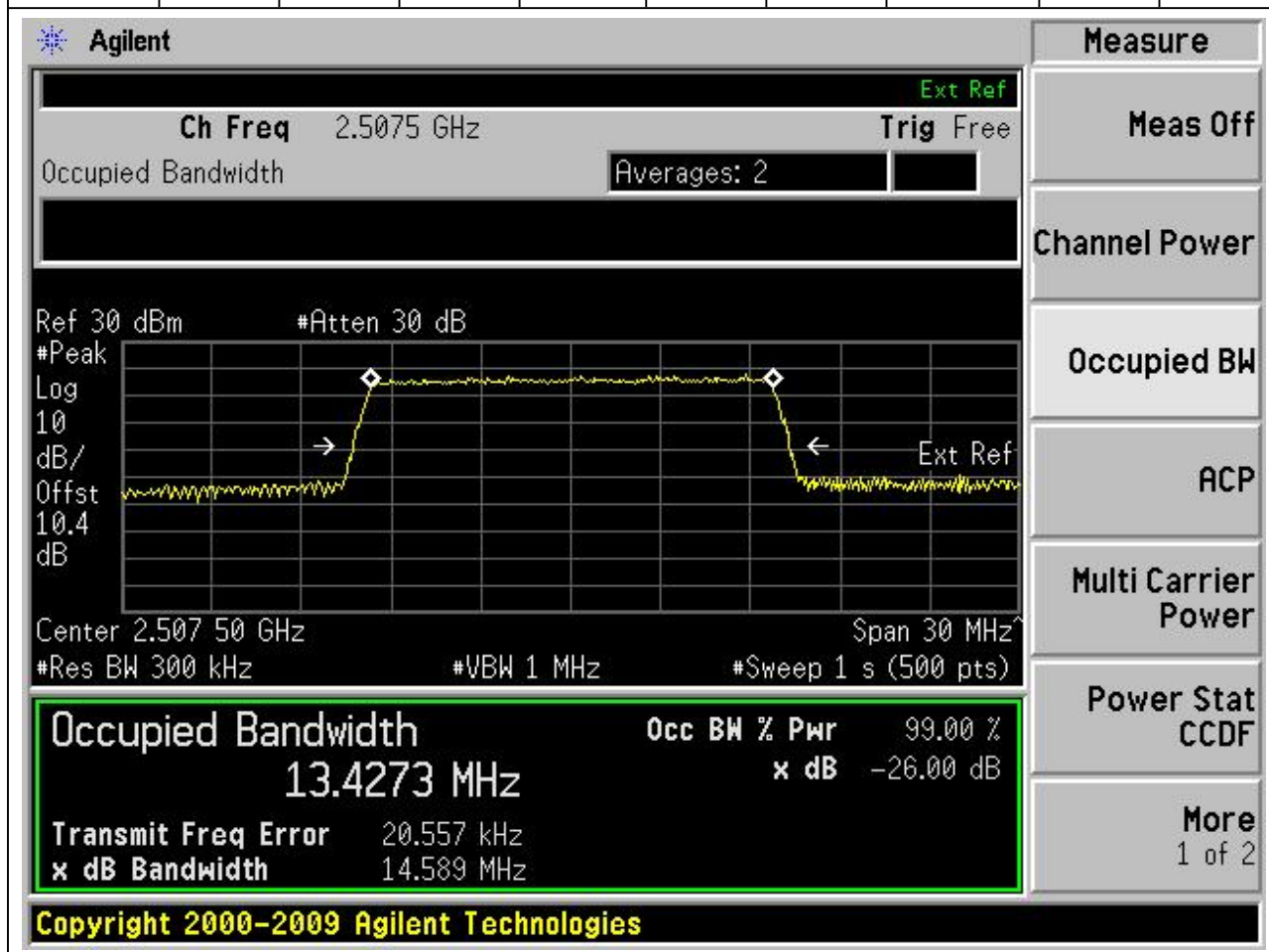
4.13. LTE Occupied Bandwidth_Part22-24-27(Channel:20825, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2507.5	99	26	0.3	Peak	10.41	13.43	14.59	15	Pass



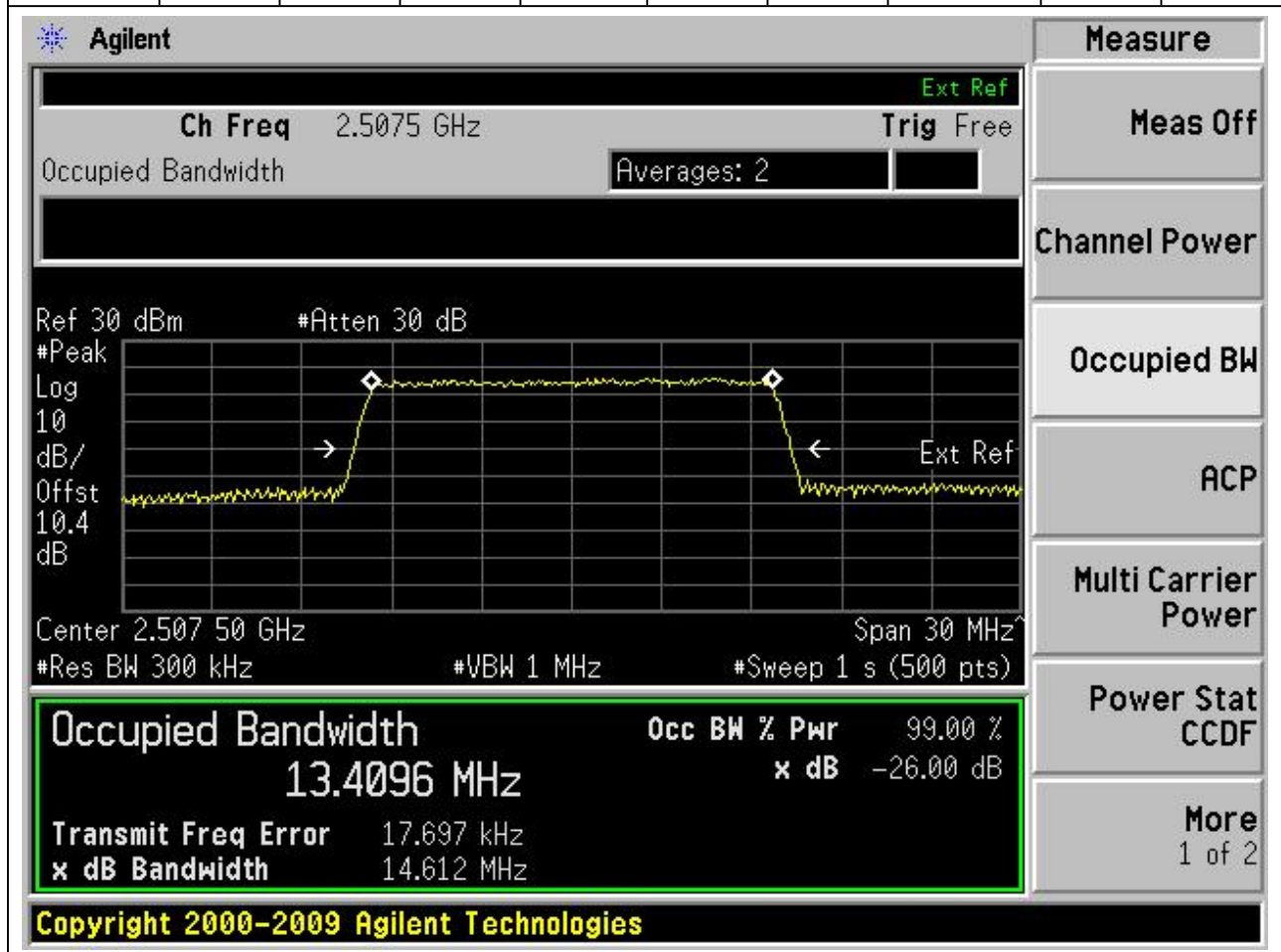
4.14. LTE Occupied Bandwidth_Part22-24-27(Channel:20825, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2507.5	99	26	0.3	Peak	10.41	13.41	14.61	15	Pass



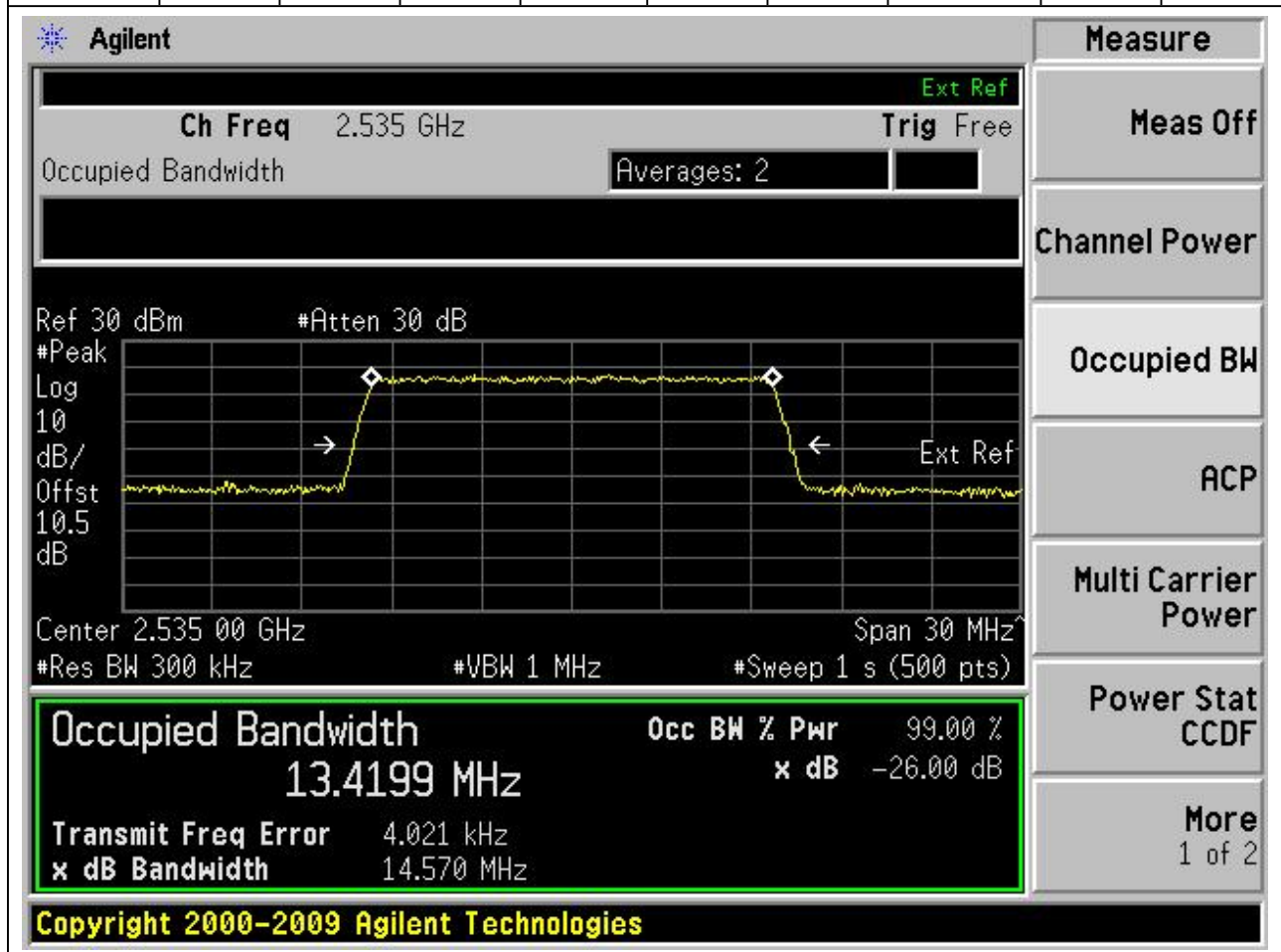
4.15. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.3	Peak	10.46	13.42	14.57	15	Pass



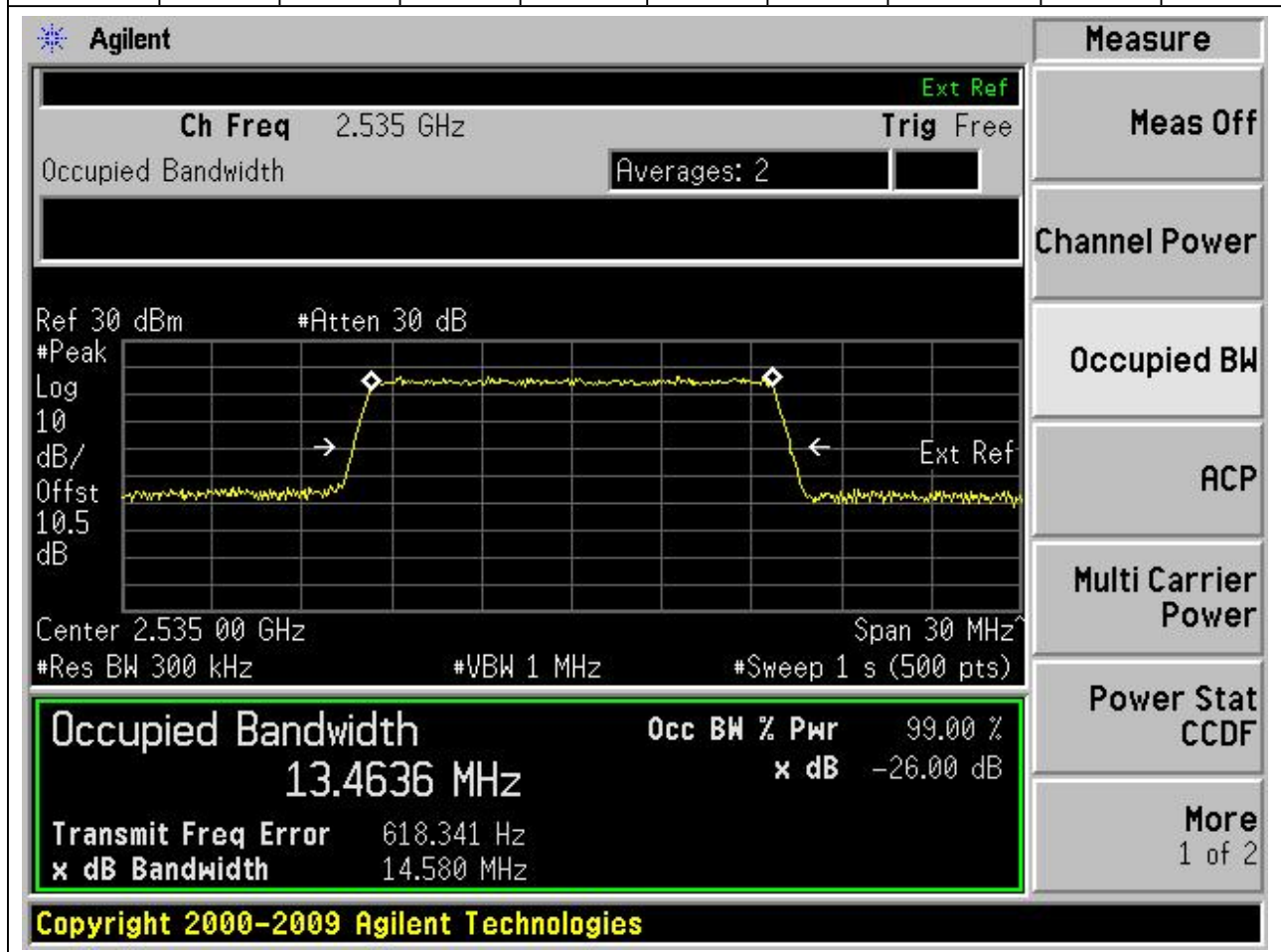
4.16. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.3	Peak	10.46	13.46	14.58	15	Pass



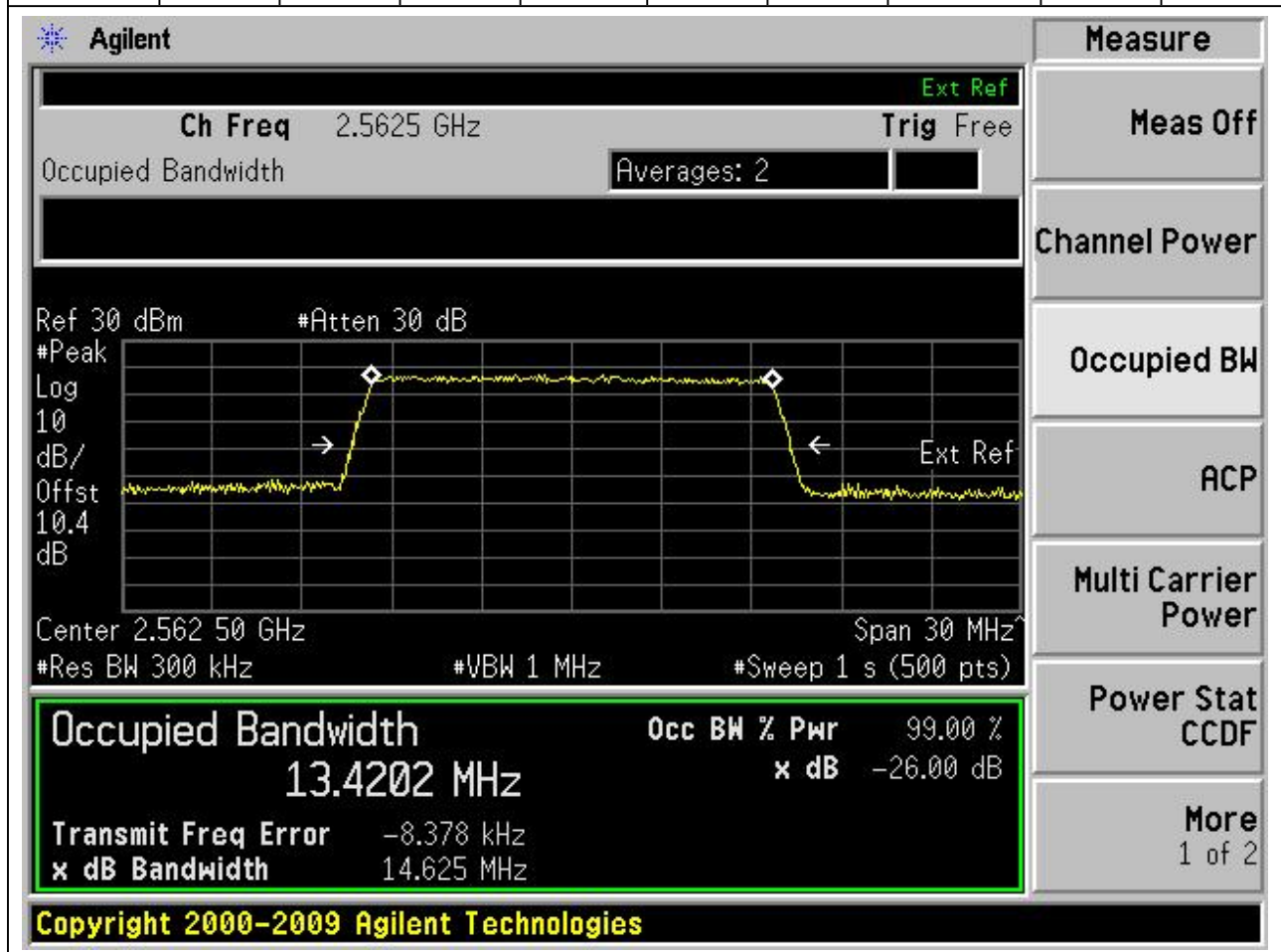
4.17. LTE Occupied Bandwidth_Part22-24-27(Channel:21375, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2562.5	99	26	0.3	Peak	10.41	13.42	14.63	15	Pass



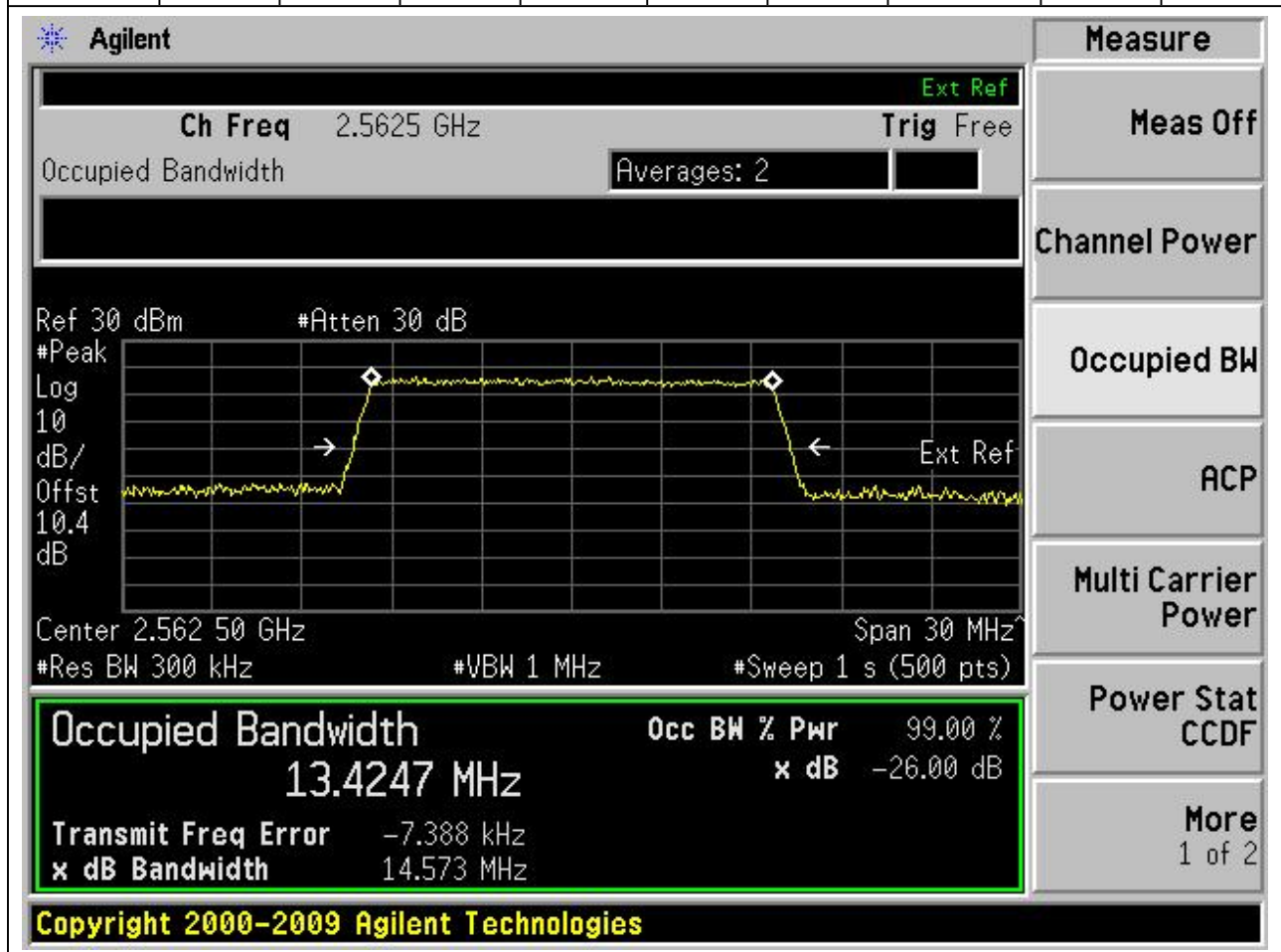
4.18. LTE Occupied Bandwidth_Part22-24-27(Channel:21375, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2562.5	99	26	0.3	Peak	10.41	13.42	14.57	15	Pass



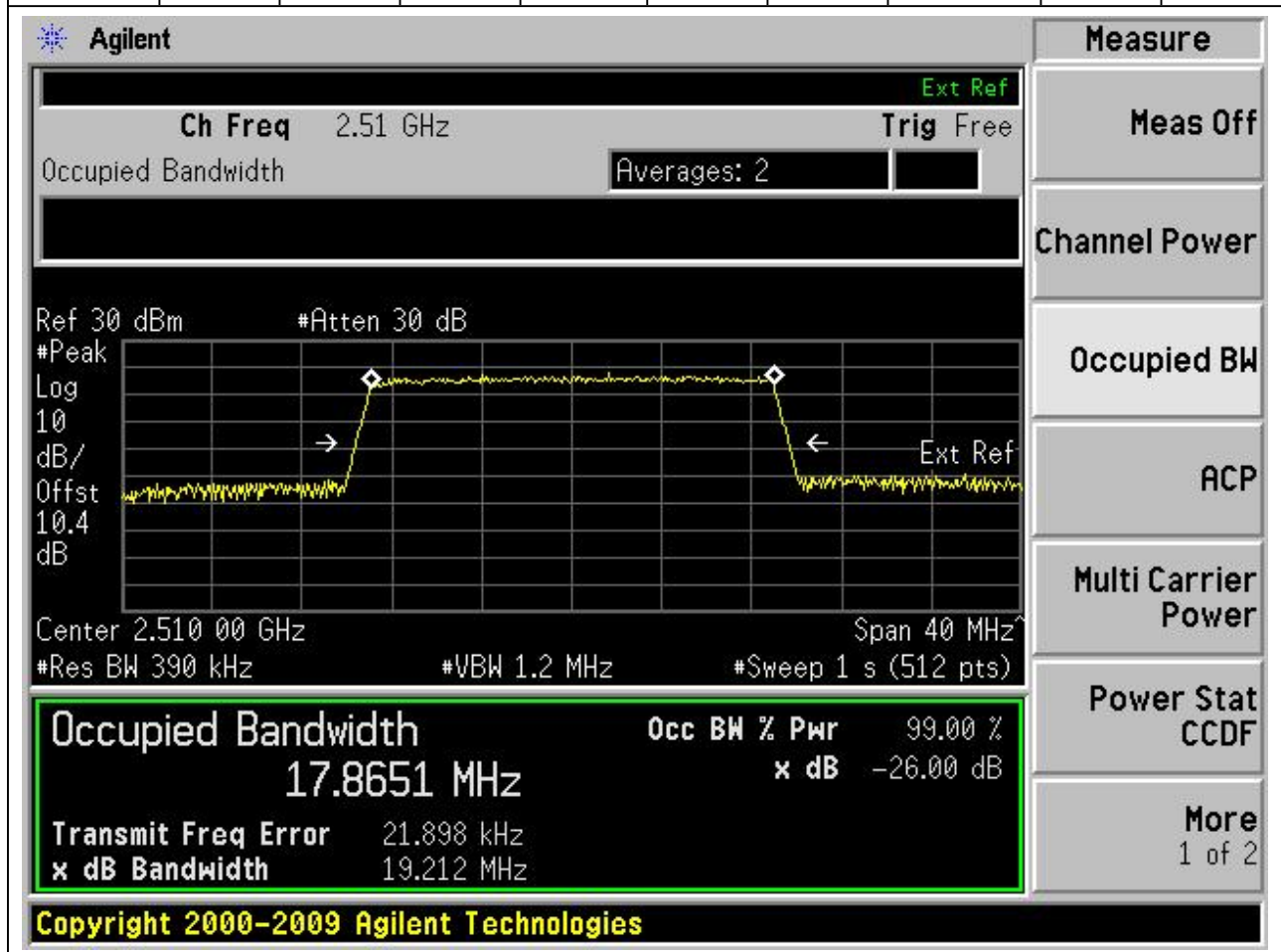
4.19. LTE Occupied Bandwidth_Part22-24-27(Channel:20850, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2510	99	26	0.39	Peak	10.41	17.87	19.21	20	Pass



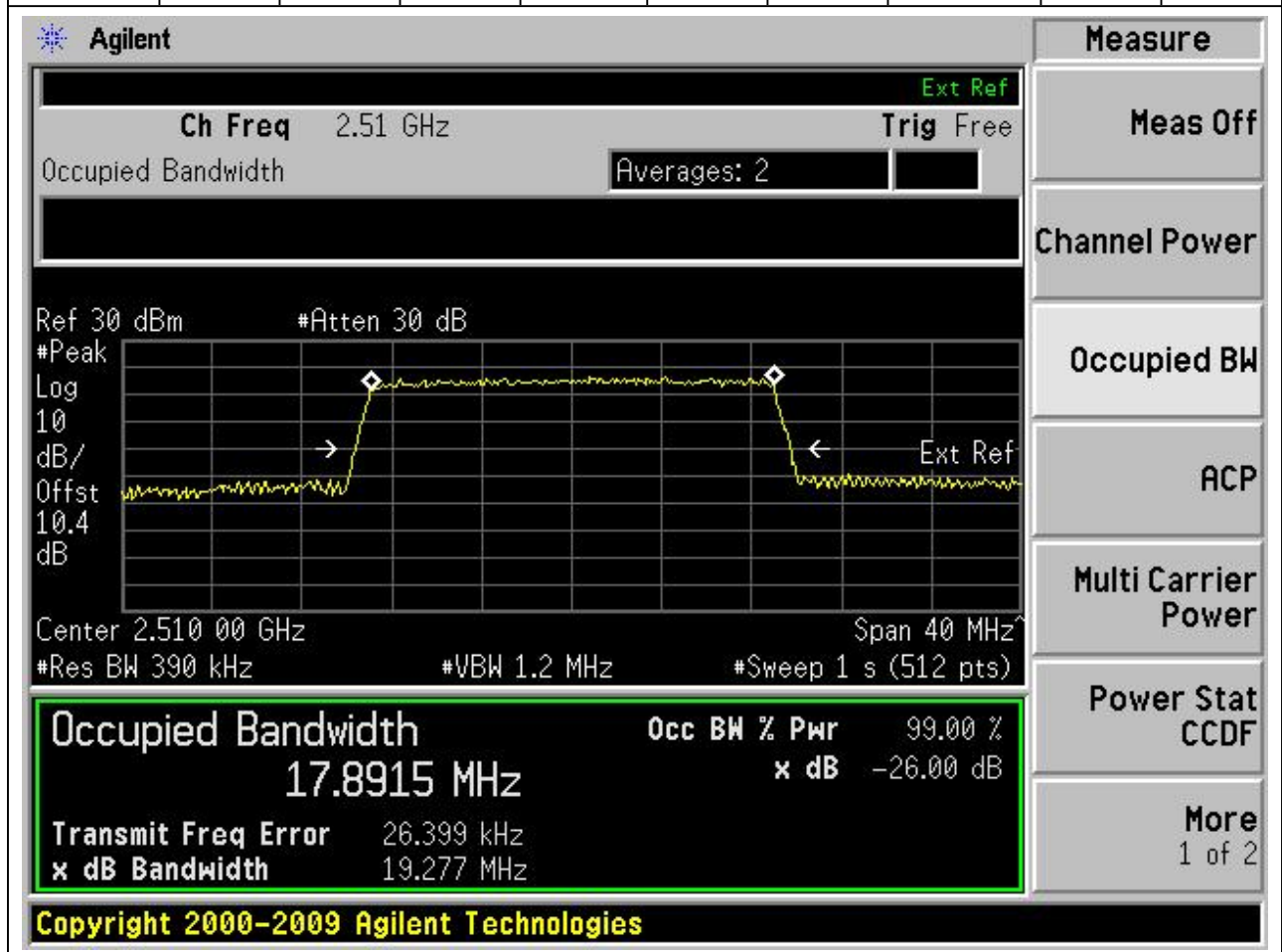
4.20. LTE Occupied Bandwidth_Part22-24-27(Channel:20850, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2510	99	26	0.39	Peak	10.41	17.89	19.28	20	Pass



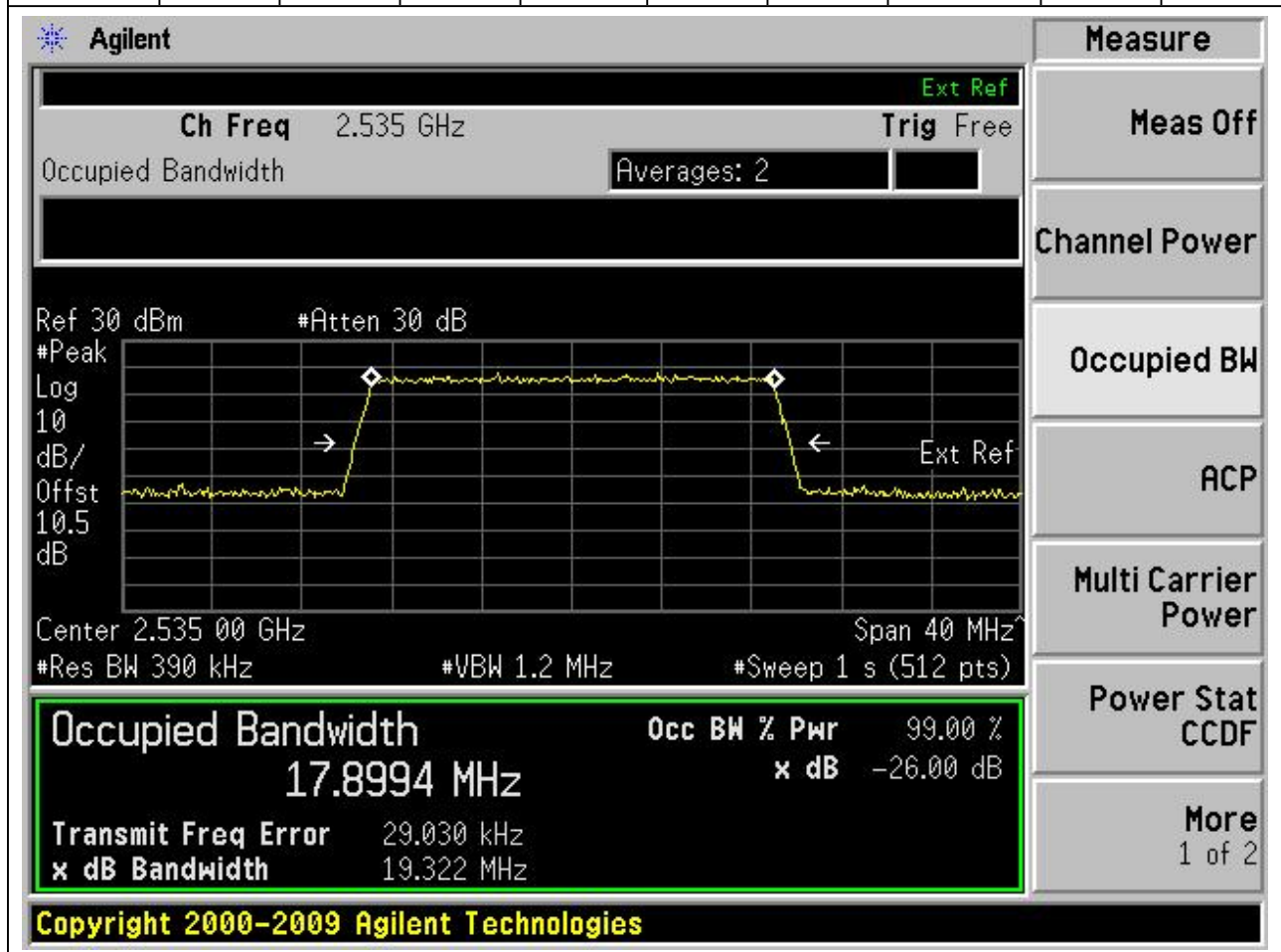
4.21. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.39	Peak	10.46	17.9	19.32	20	Pass



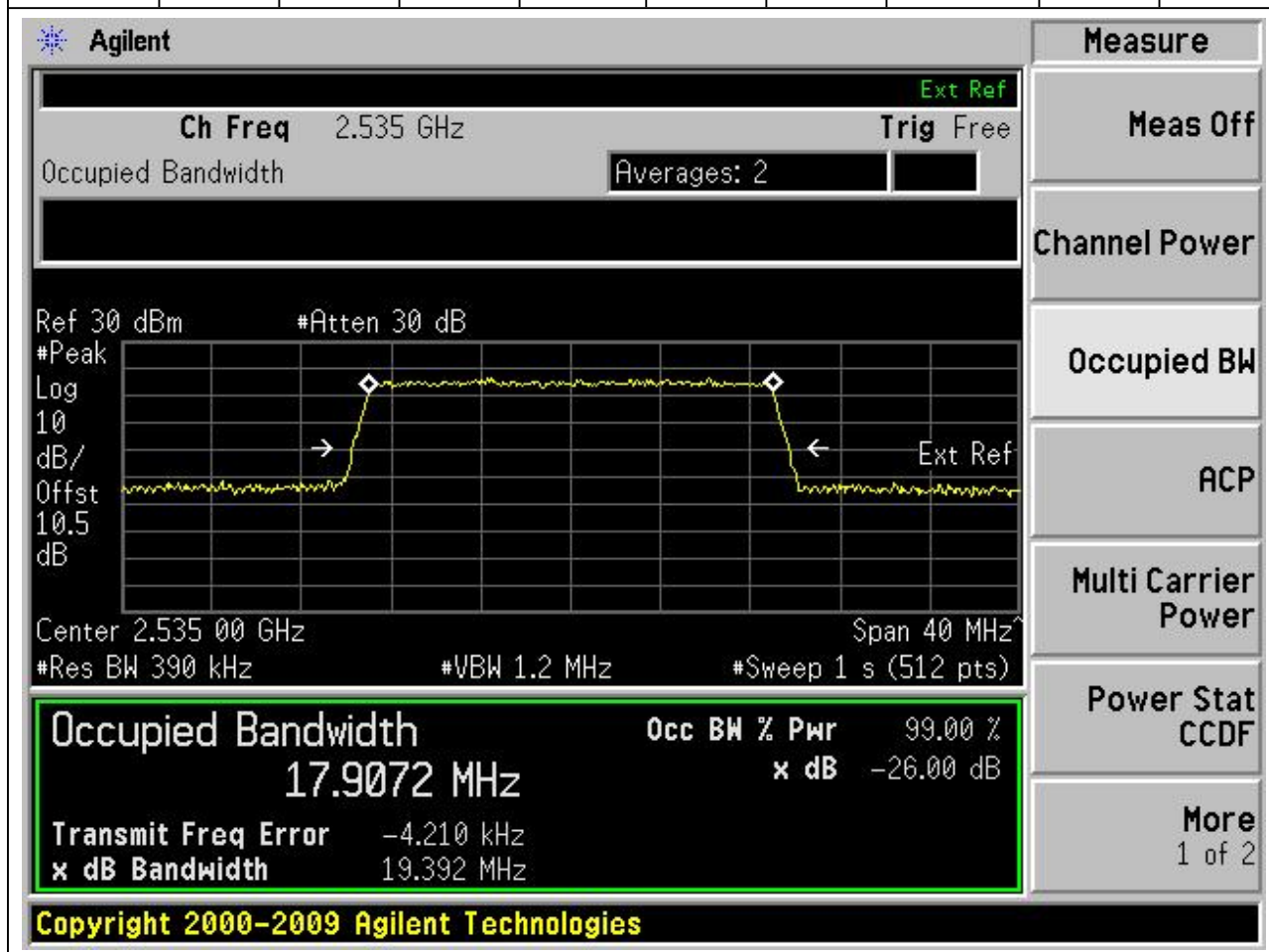
4.22. LTE Occupied Bandwidth_Part22-24-27(Channel:21100, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2535	99	26	0.39	Peak	10.46	17.91	19.39	20	Pass



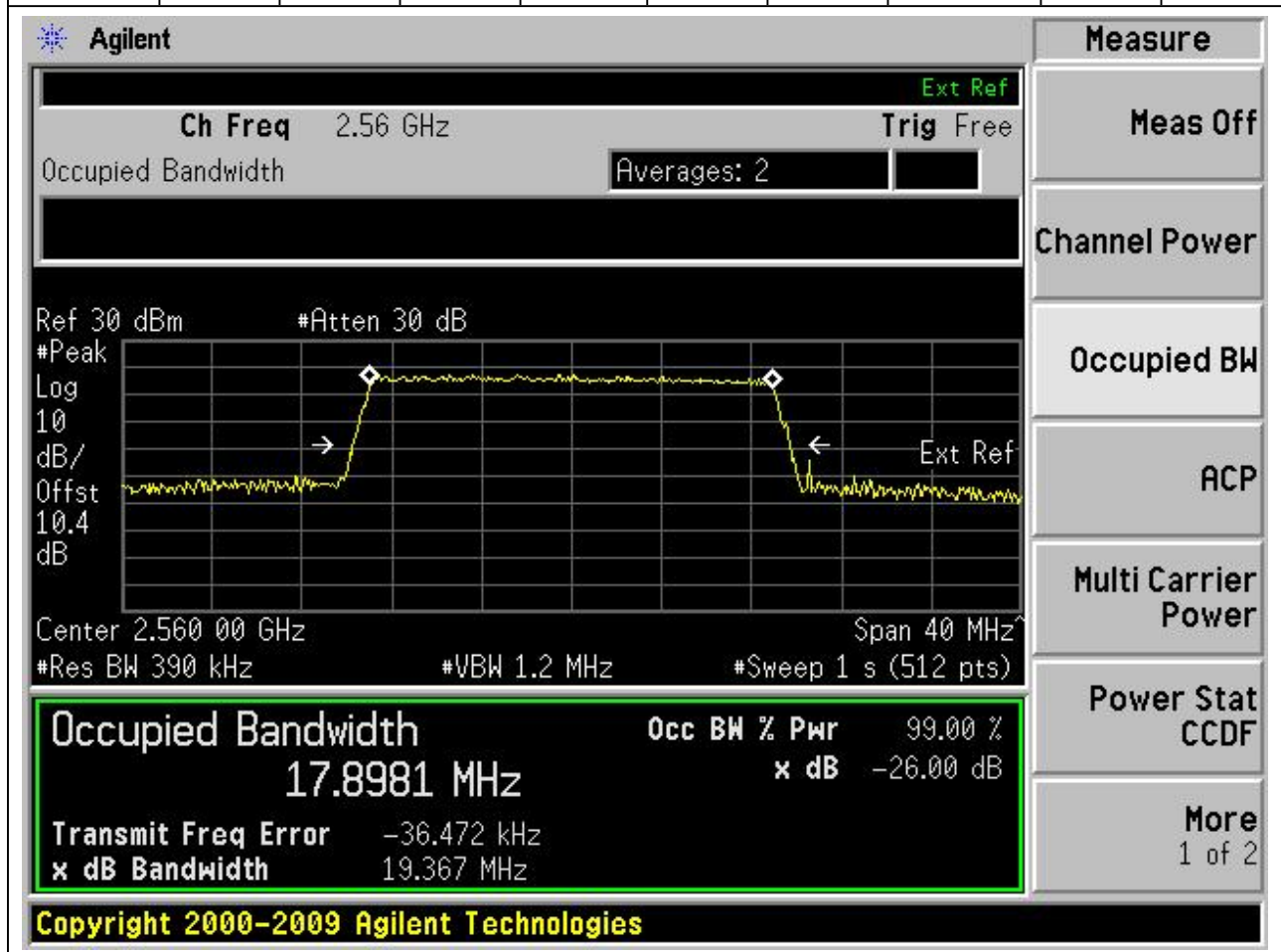
4.23. LTE Occupied Bandwidth_Part22-24-27(Channel:21350, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2560	99	26	0.39	Peak	10.4	17.9	19.37	20	Pass



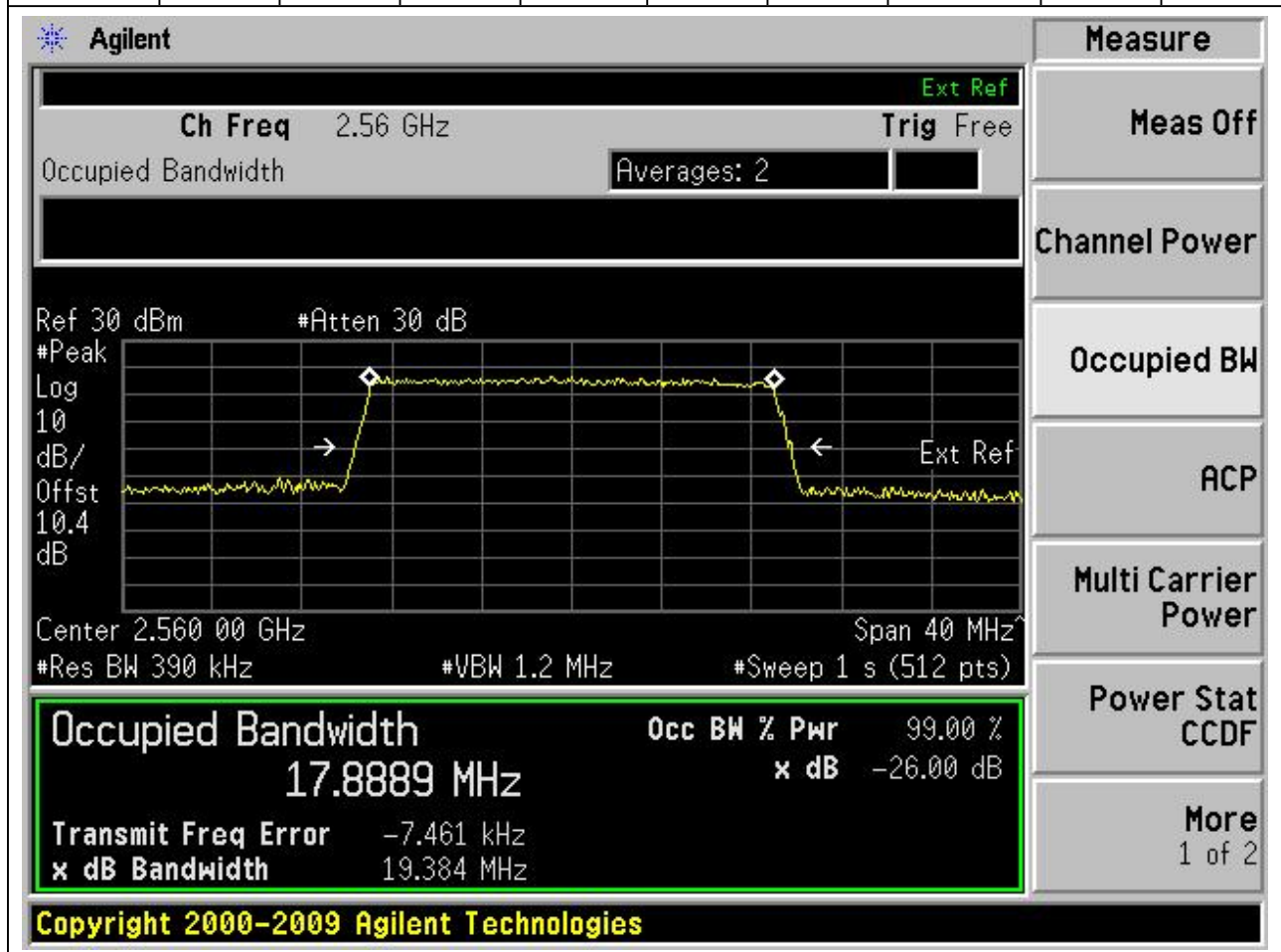
4.24. LTE Occupied Bandwidth_Part22-24-27(Channel:21350, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-29

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2560	99	26	0.39	Peak	10.4	17.89	19.38	20	Pass



5. LTE_Band38

EUT Sample No.:	
EUT Name:	
EUT Manufacturer:	
EUT Model:	
EUT Serial Number:	
EUT Hardware Version:	
EUT Software Version:	
Low Temperature(LT):	-10 °C
Normal Temperature(NT):	+25 °C
High Temperature(HT):	+55 °C
Low Voltage(LV):	3.6 V
Normal Voltage(NV):	3.8 V
High Voltage(HV):	4.2 V

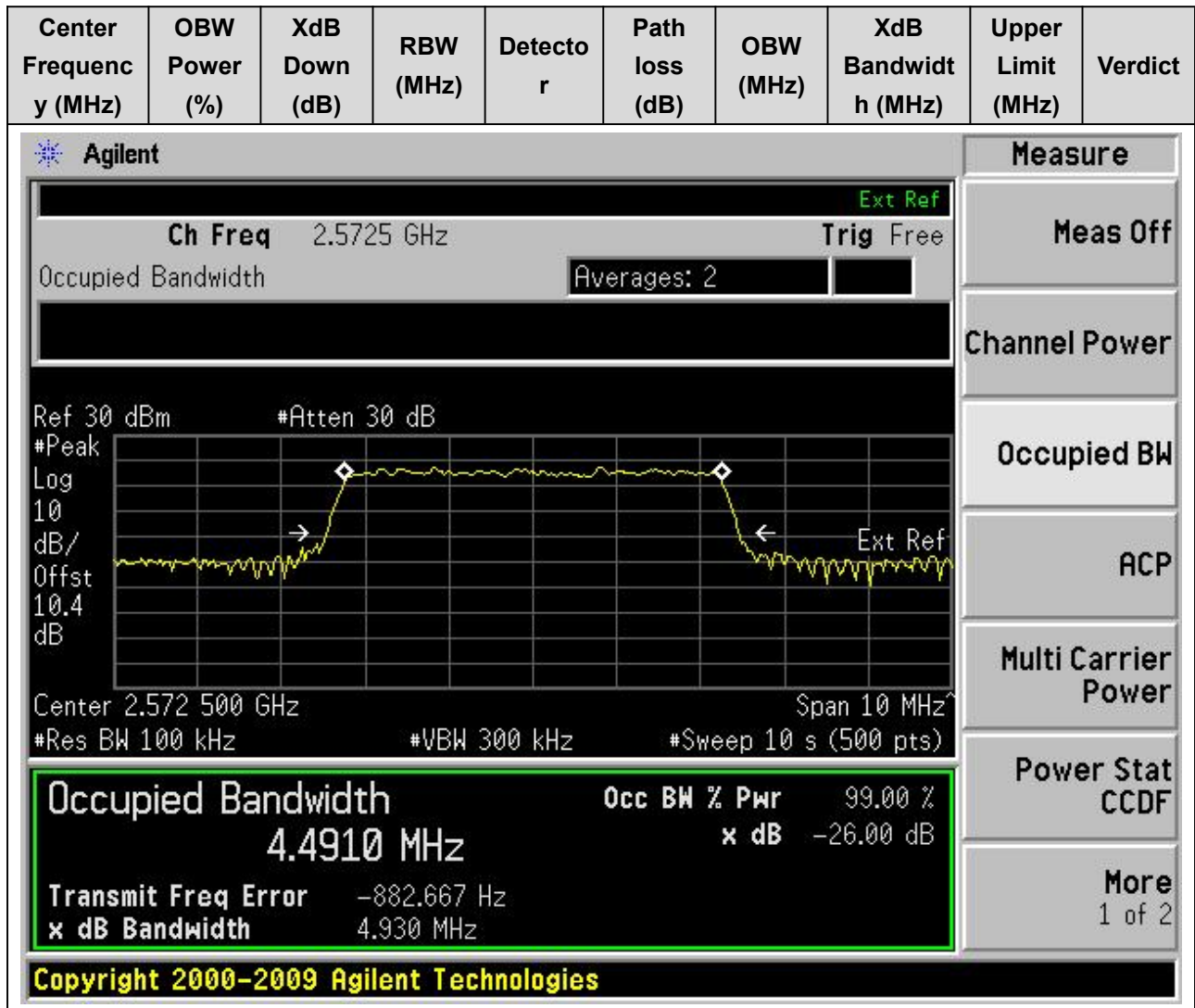
5.1. LTE Occupied Bandwidth_Part22-24-27(Channel:37775, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2572.5	99	26	0.1	Peak	10.43	4.49	4.93	5	Pass



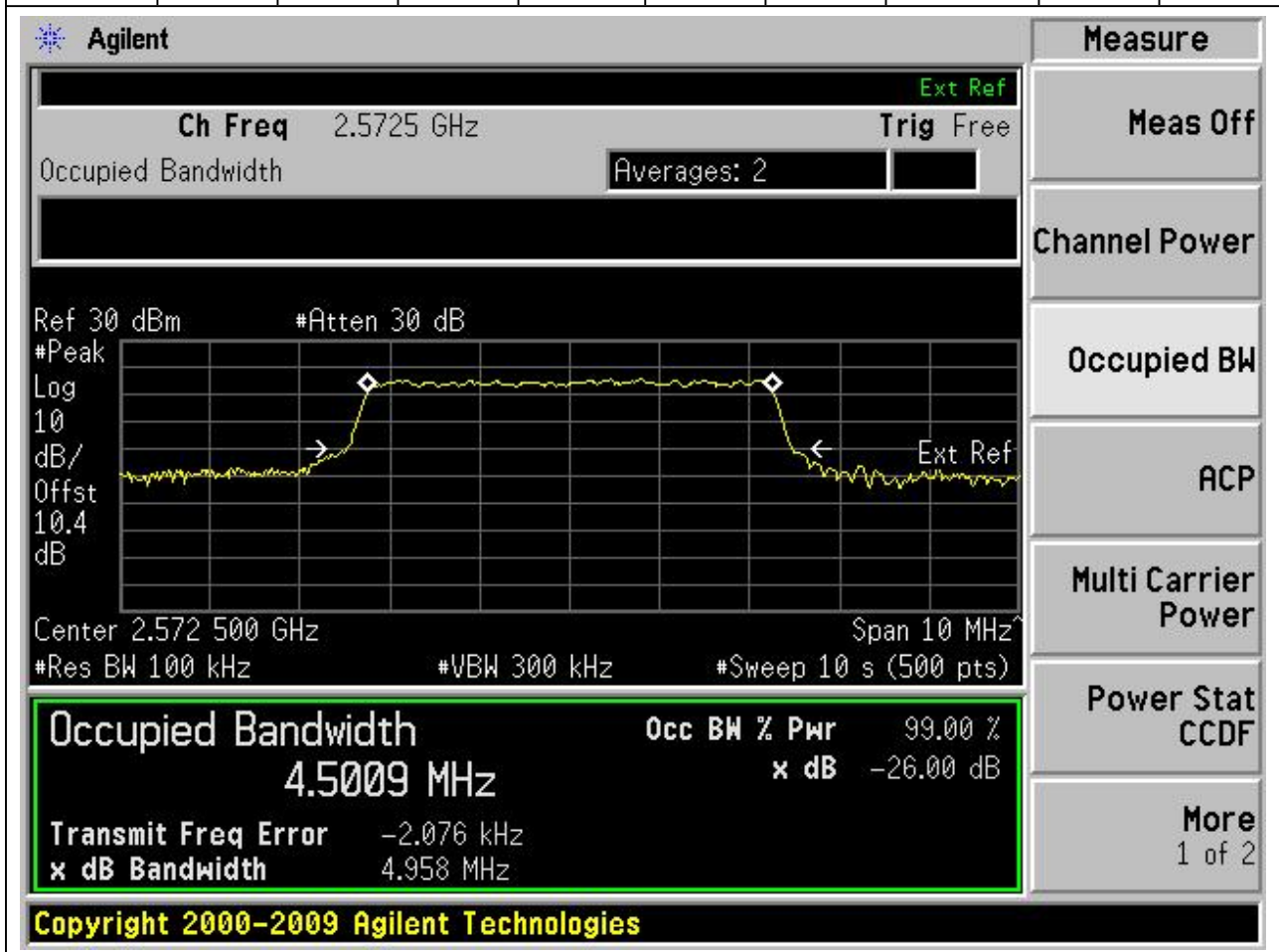
5.2. LTE Occupied Bandwidth_Part22-24-27(Channel:37775, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2572.5	99	26	0.1	Peak	10.43	4.5	4.96	5	Pass



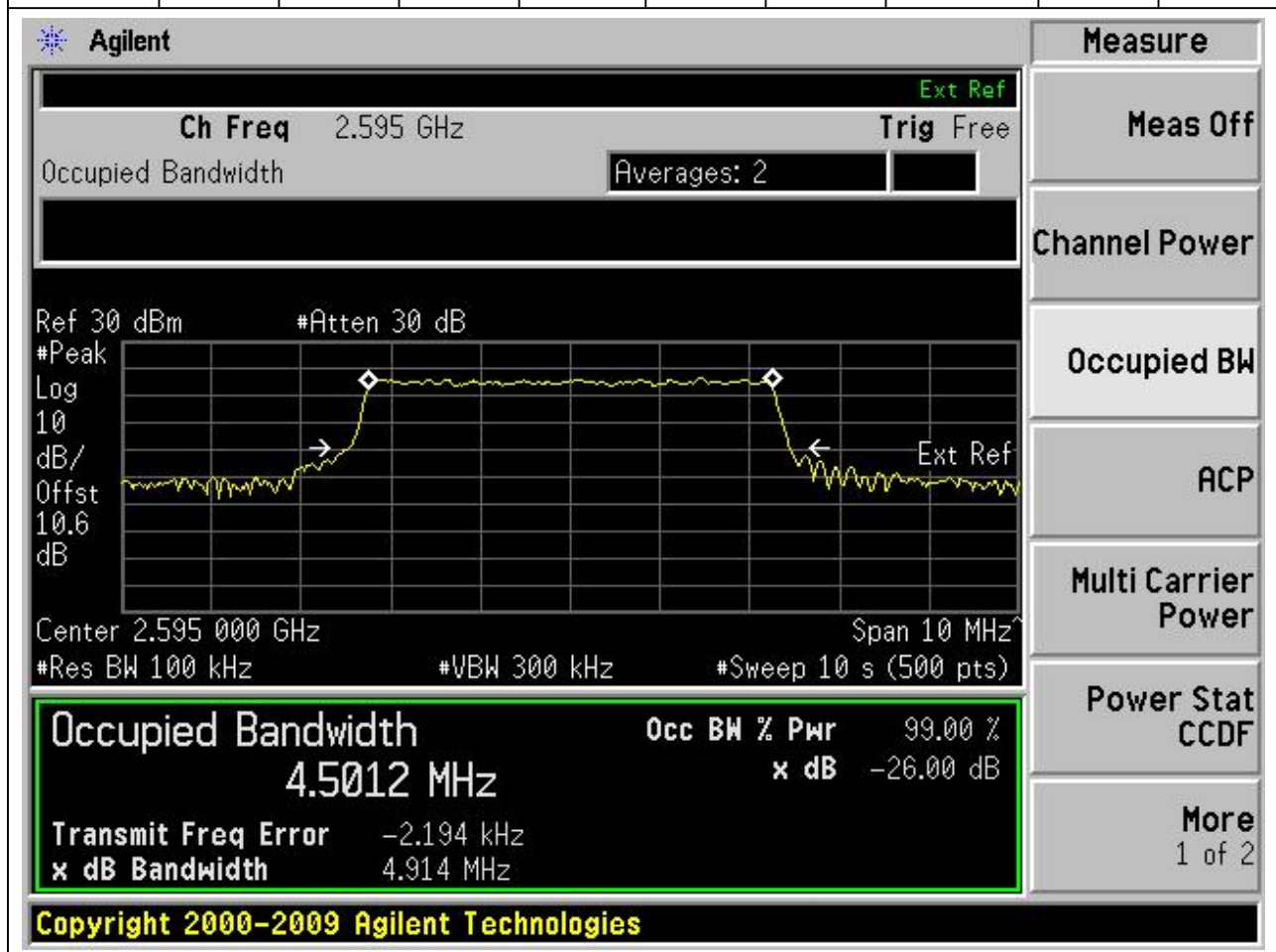
5.3. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.1	Peak	10.55	4.5	4.91	5	Pass



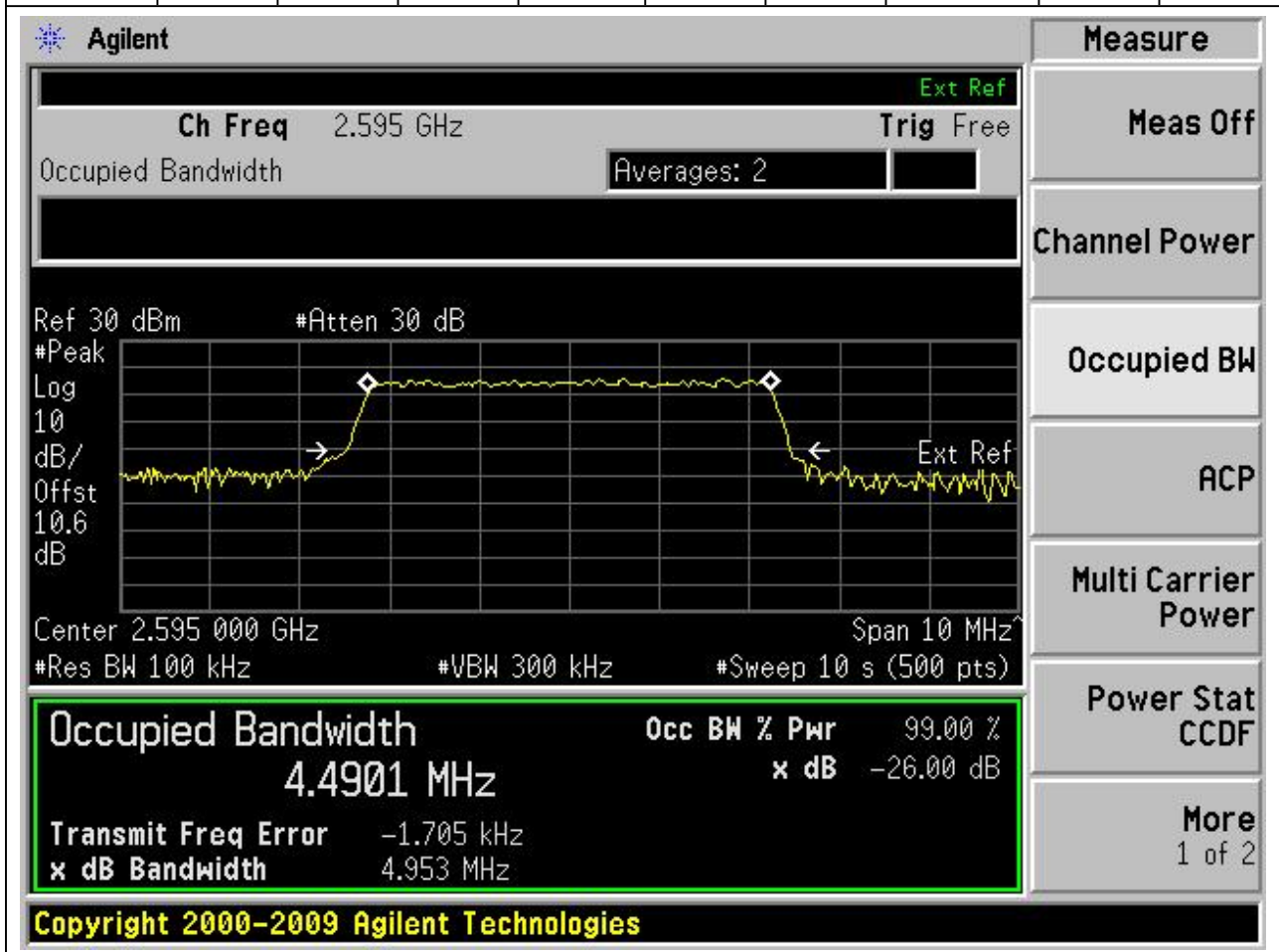
5.4. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.1	Peak	10.55	4.49	4.95	5	Pass



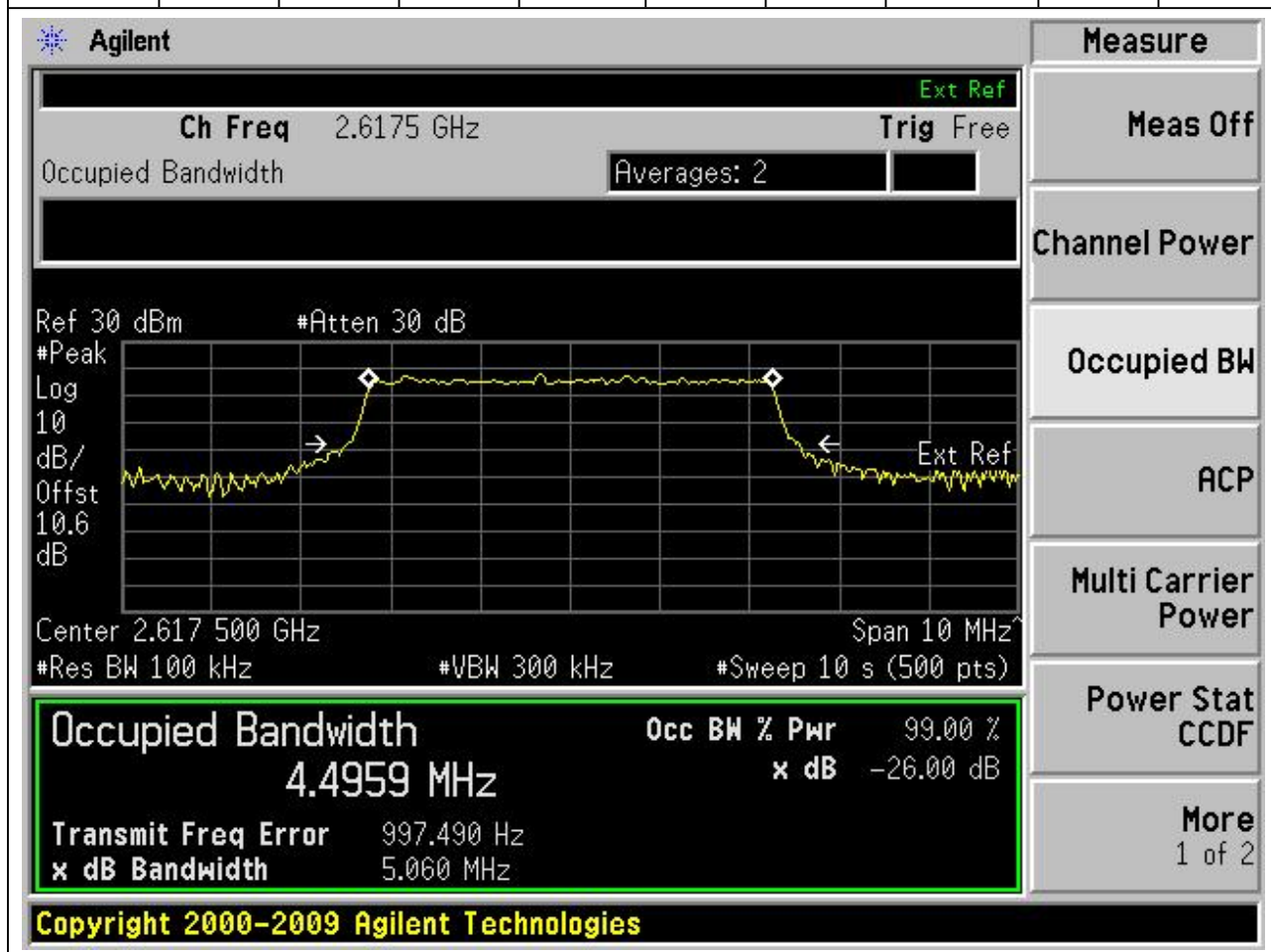
5.5. LTE Occupied Bandwidth_Part22-24-27(Channel:38225, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2617.5	99	26	0.1	Peak	10.64	4.5	5.06	5	Pass



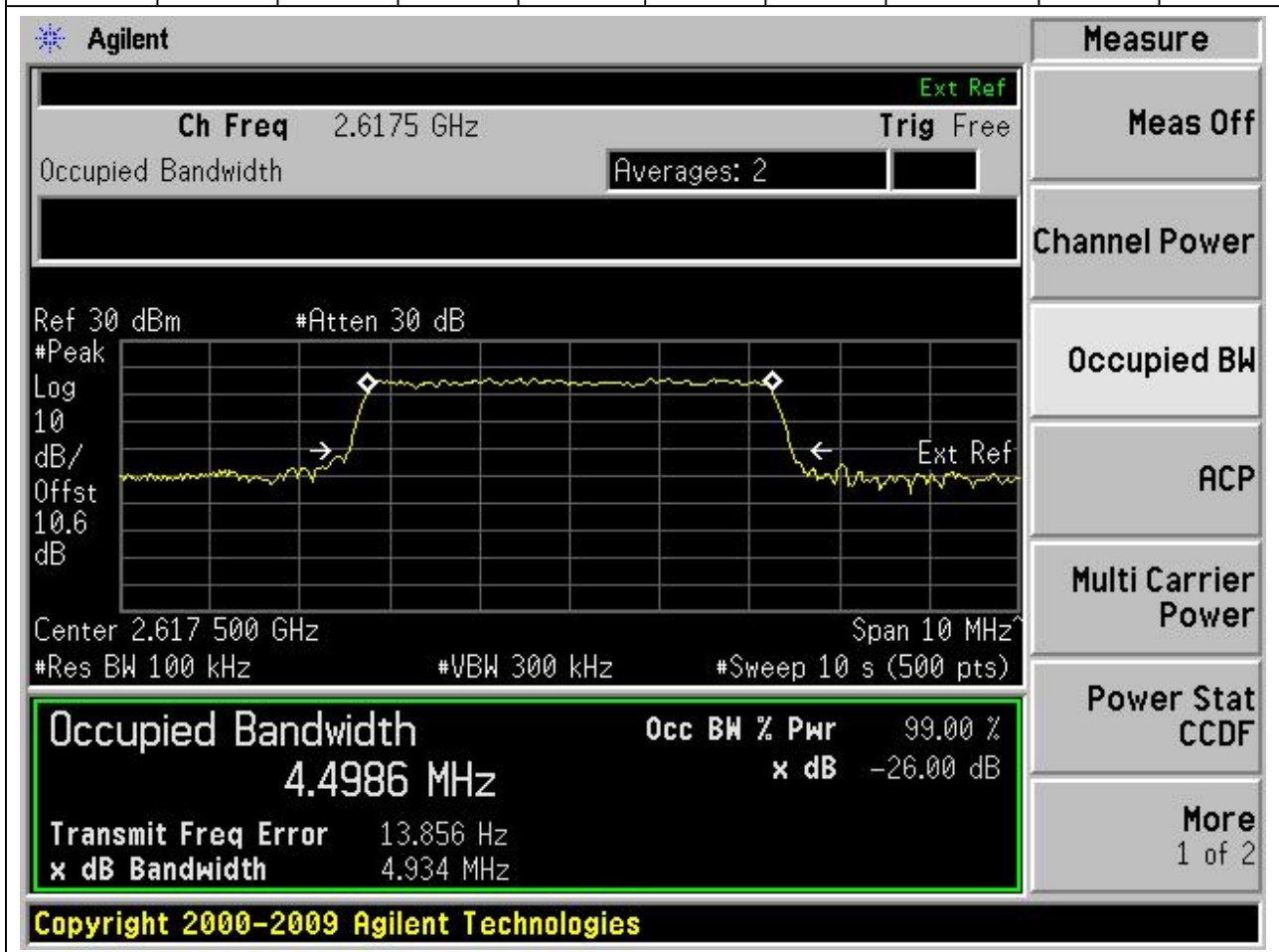
5.6. LTE Occupied Bandwidth_Part22-24-27(Channel:38225, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2617.5	99	26	0.1	Peak	10.64	4.5	4.93	5	Pass



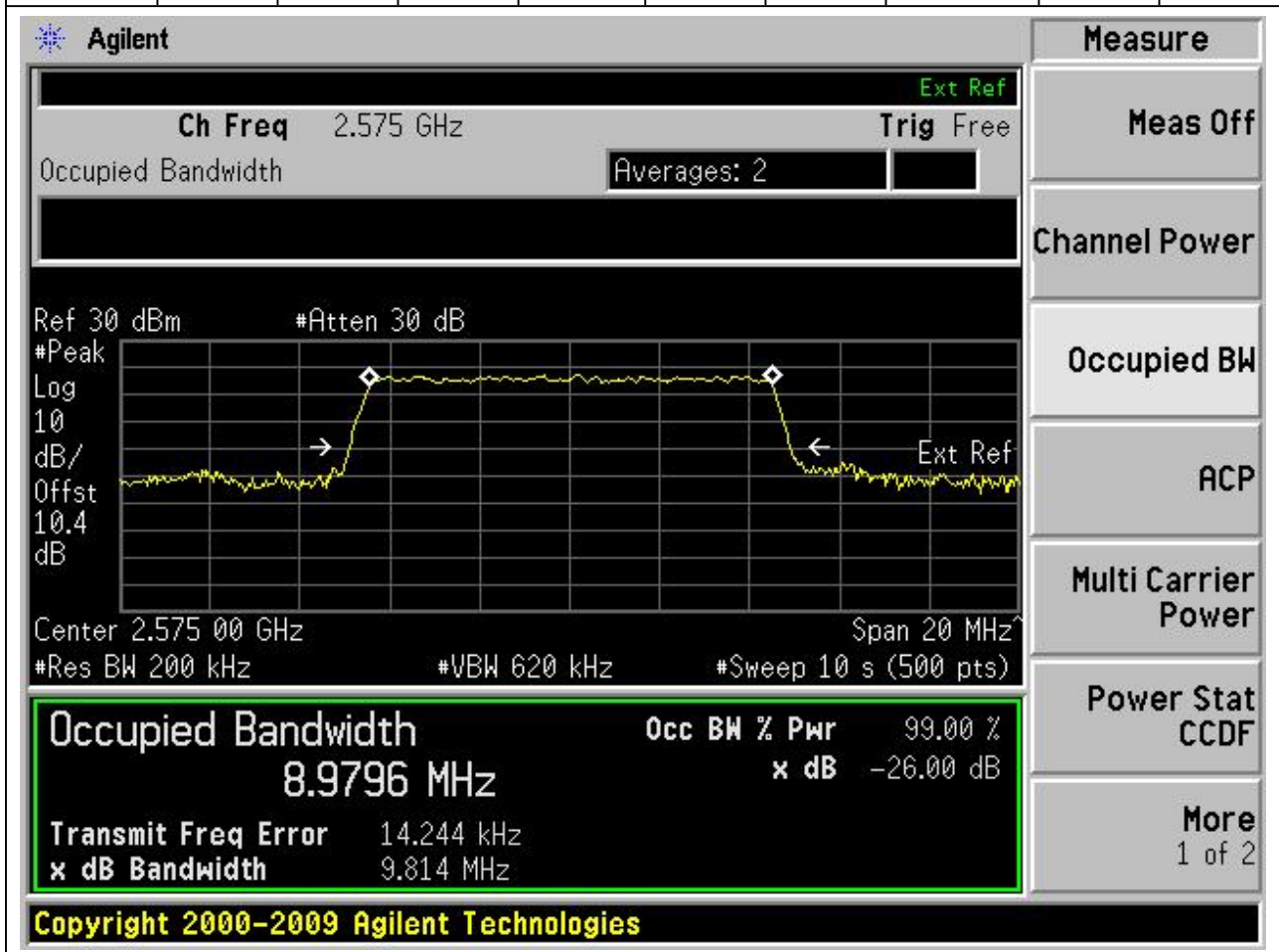
5.7. LTE Occupied Bandwidth_Part22-24-27(Channel:37800, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2575	99	26	0.2	Peak	10.43	8.98	9.81	10	Pass



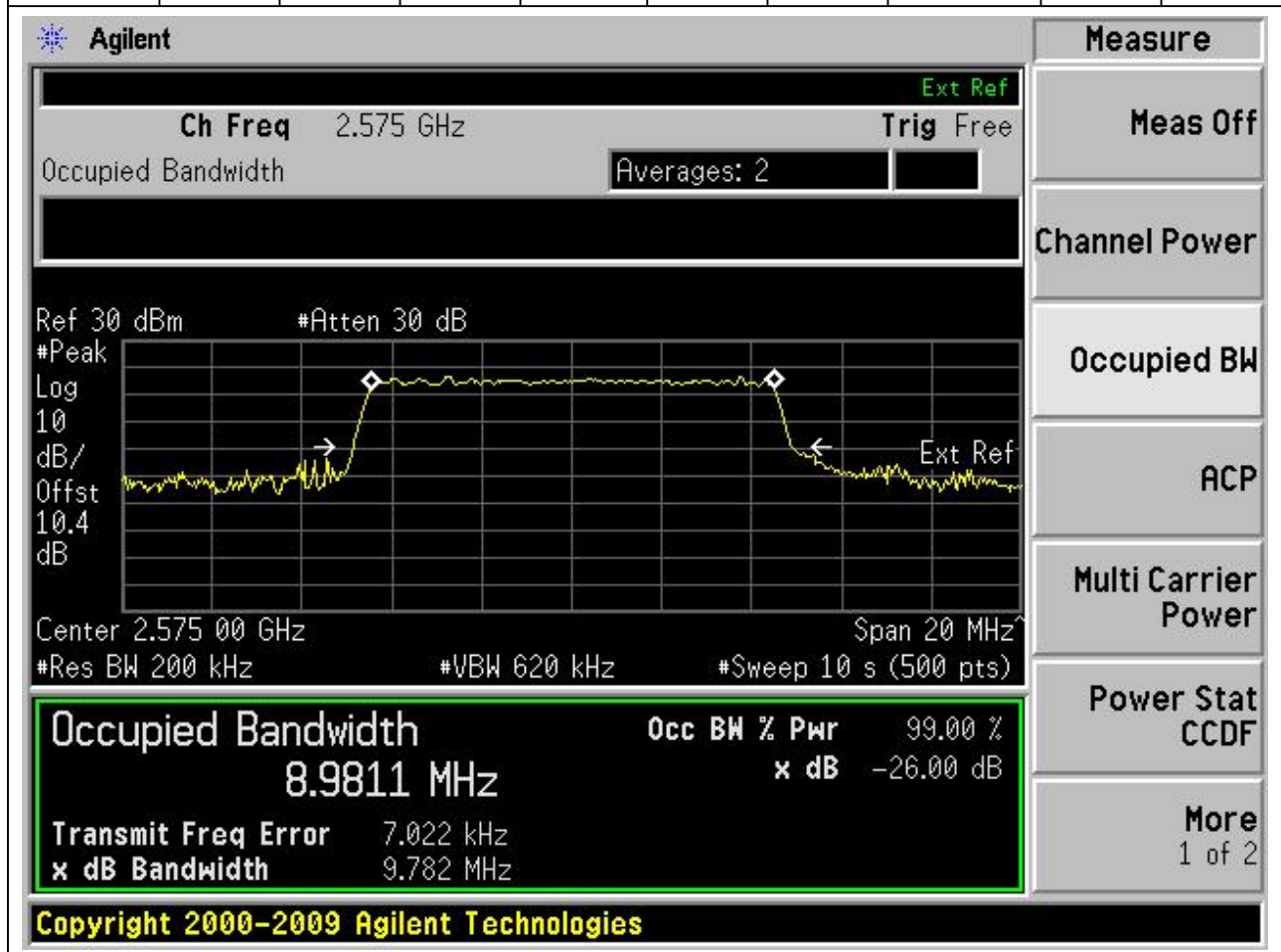
5.8. LTE Occupied Bandwidth_Part22-24-27(Channel:37800, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2575	99	26	0.2	Peak	10.43	8.98	9.78	10	Pass



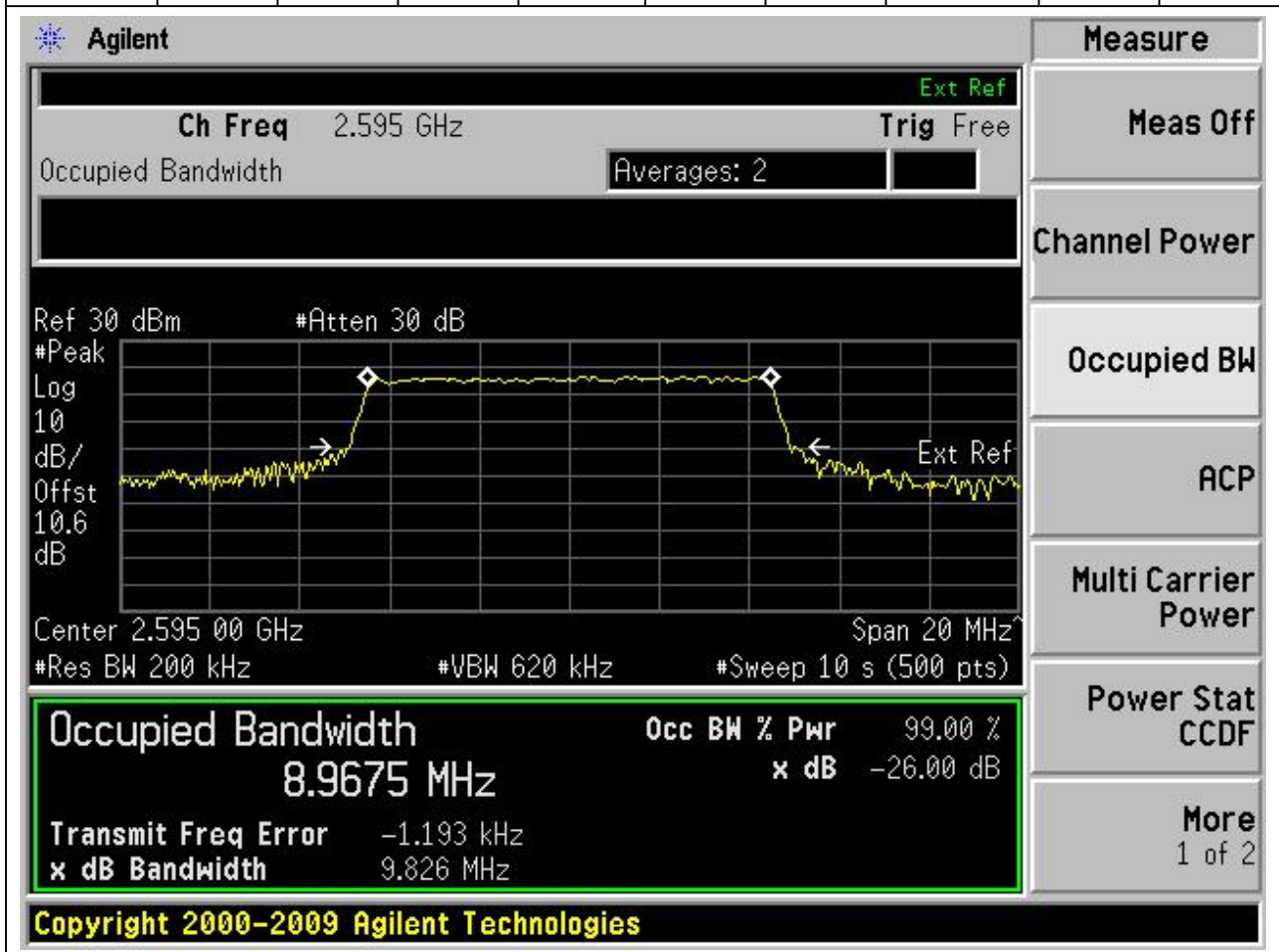
5.9. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.2	Peak	10.55	8.97	9.83	10	Pass



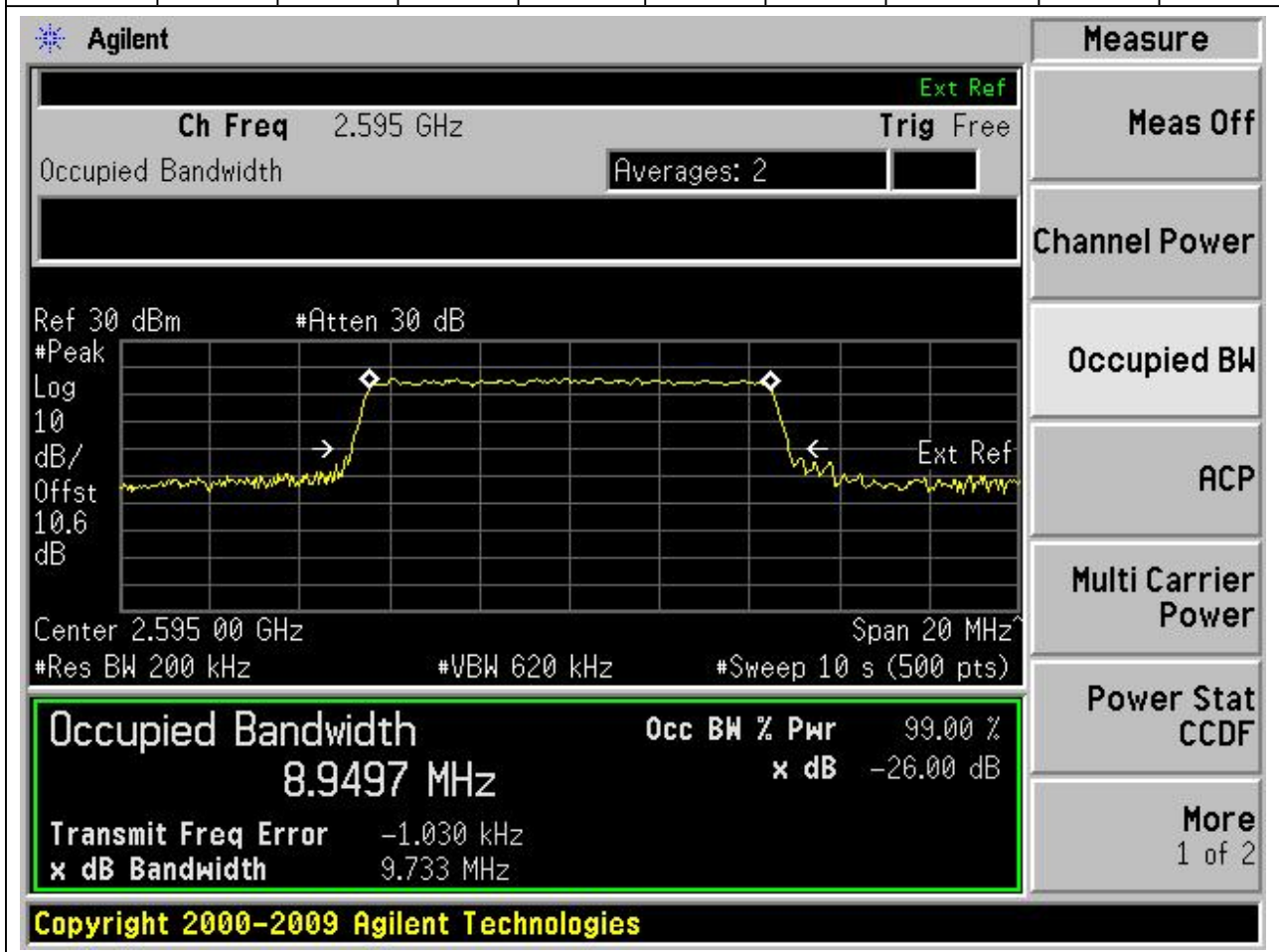
5.10. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.2	Peak	10.55	8.95	9.73	10	Pass



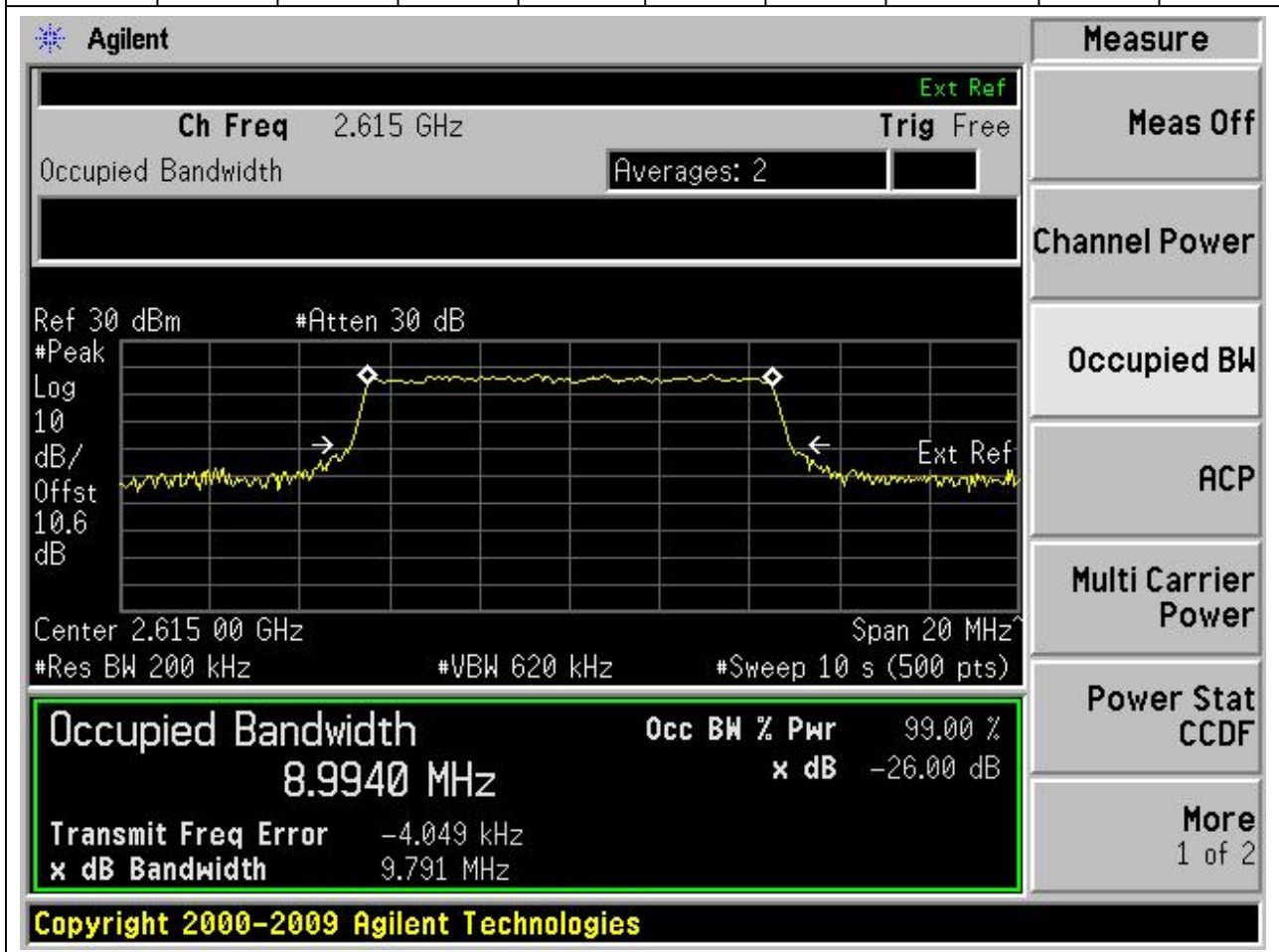
5.11. LTE Occupied Bandwidth_Part22-24-27(Channel:38200, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2615	99	26	0.2	Peak	10.62	8.99	9.79	10	Pass



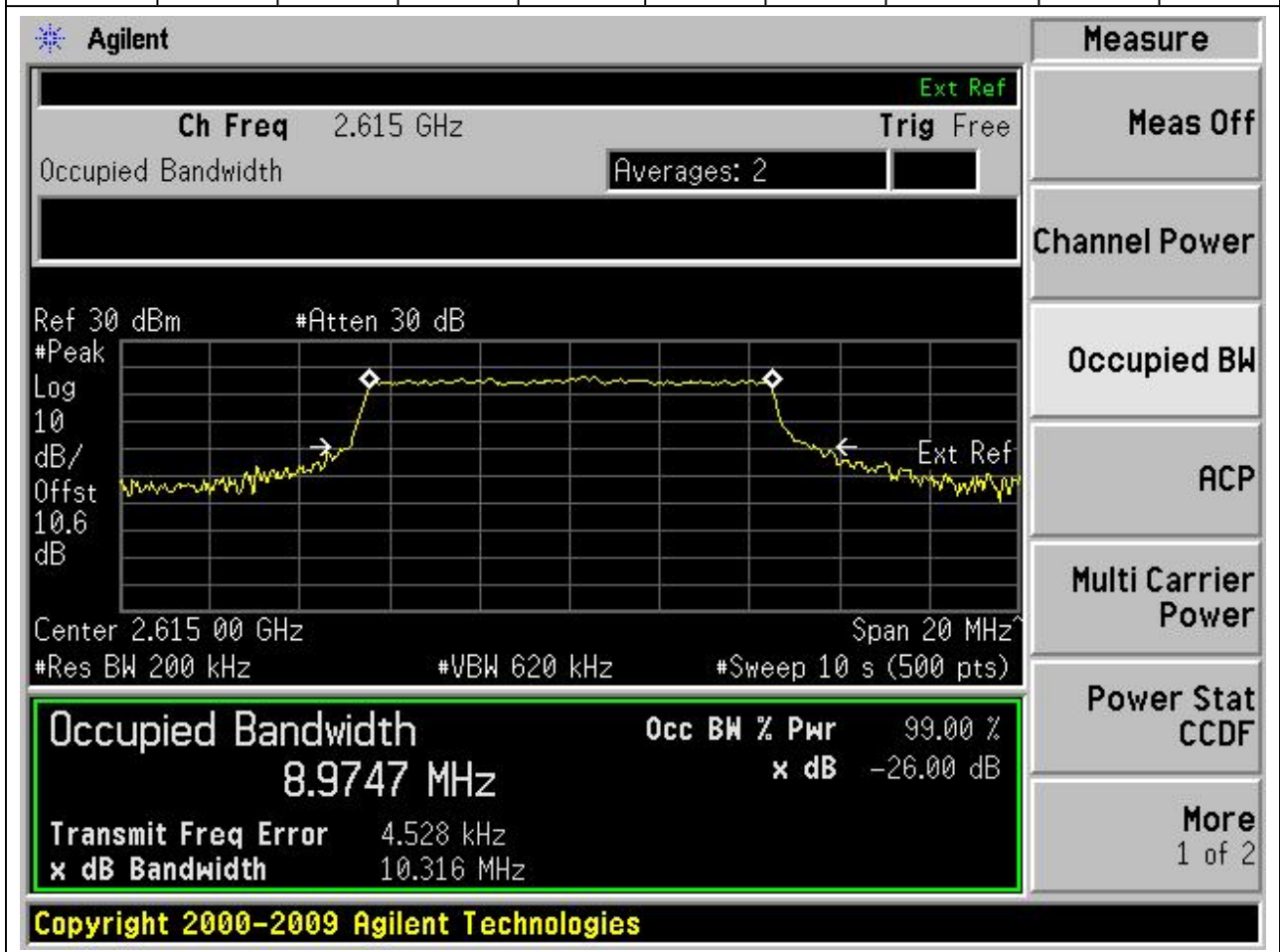
5.12. LTE Occupied Bandwidth_Part22-24-27(Channel:38200, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2615	99	26	0.2	Peak	10.62	8.97	10.32	10	Pass



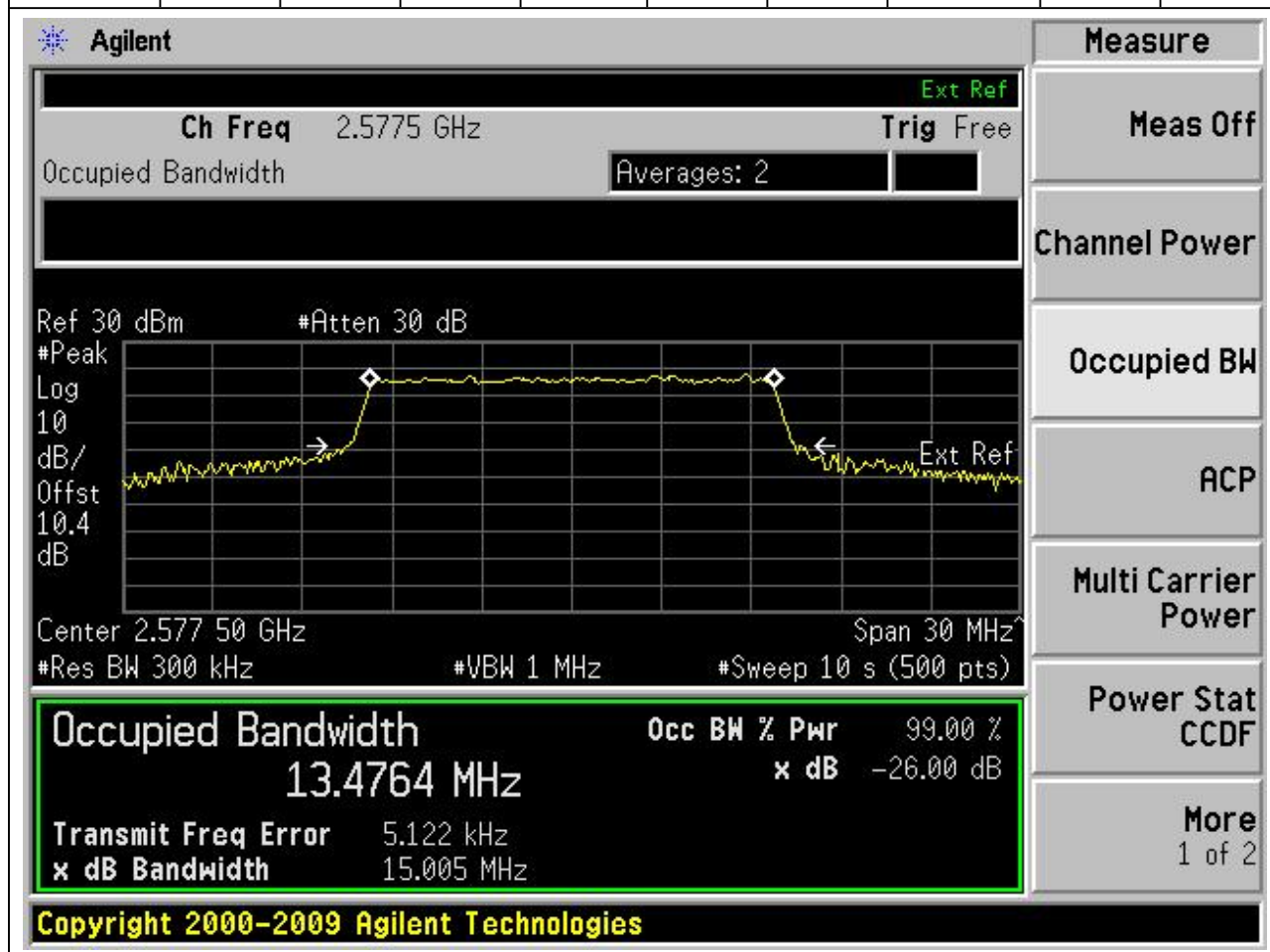
5.13. LTE Occupied Bandwidth_Part22-24-27(Channel:37825, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2577.5	99	26	0.3	Peak	10.43	13.48	15.01	15	Pass



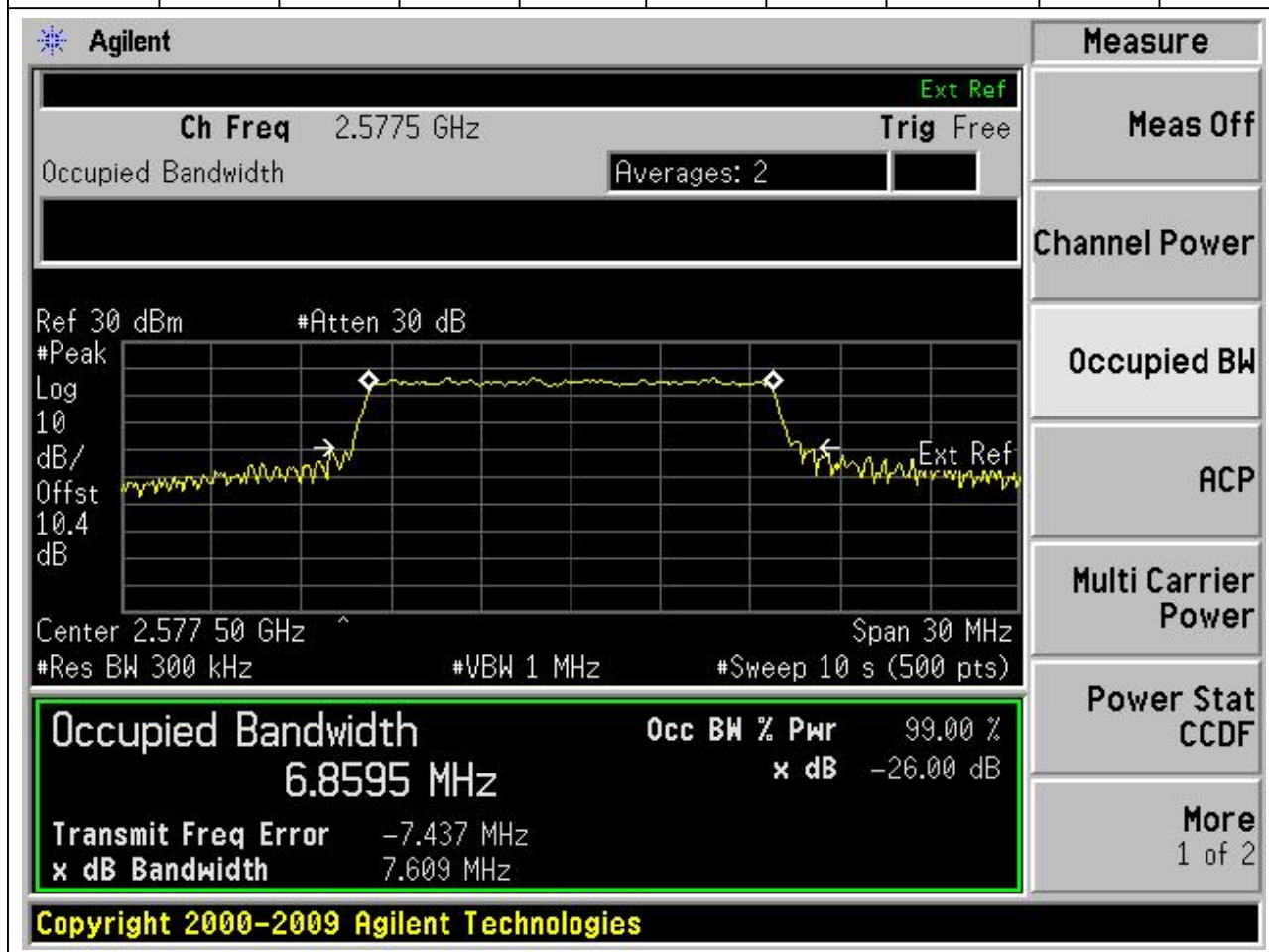
5.14. LTE Occupied Bandwidth_Part22-24-27(Channel:37825, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2577.5	99	26	0.3	Peak	10.43	6.86	7.61	15	Pass



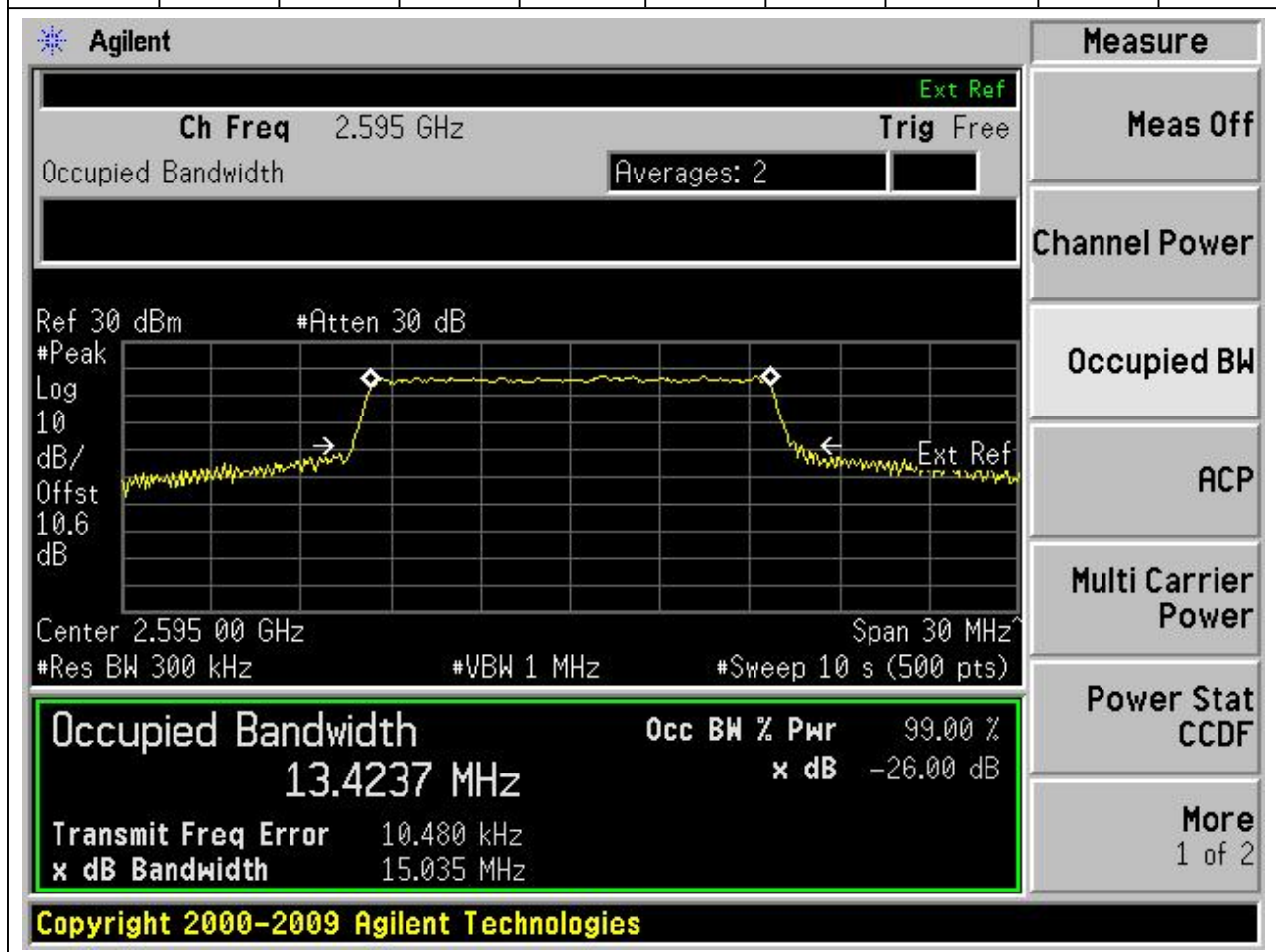
5.15. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.3	Peak	10.55	13.42	15.03	15	Pass



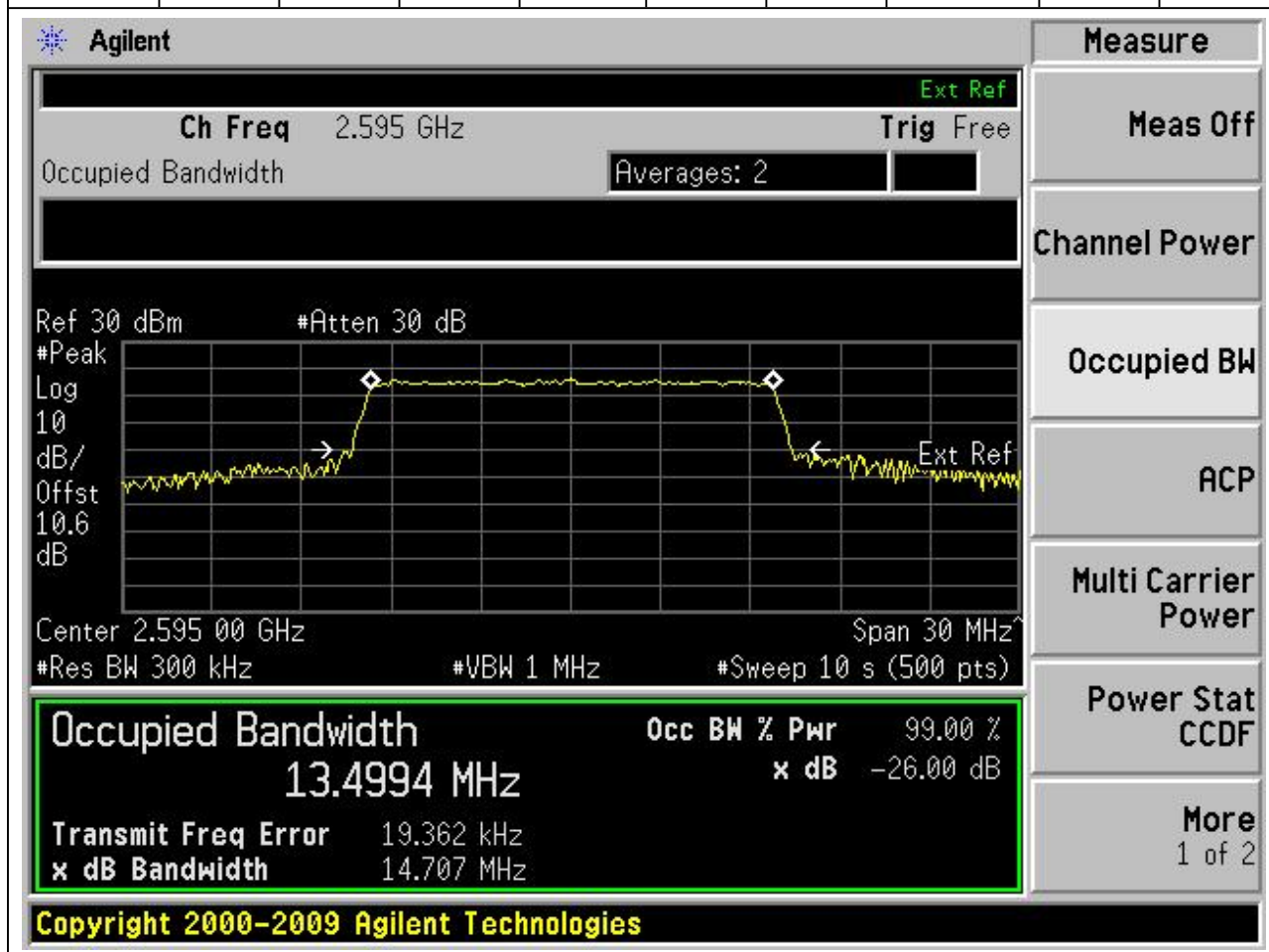
5.16. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.3	Peak	10.55	13.5	14.71	15	Pass



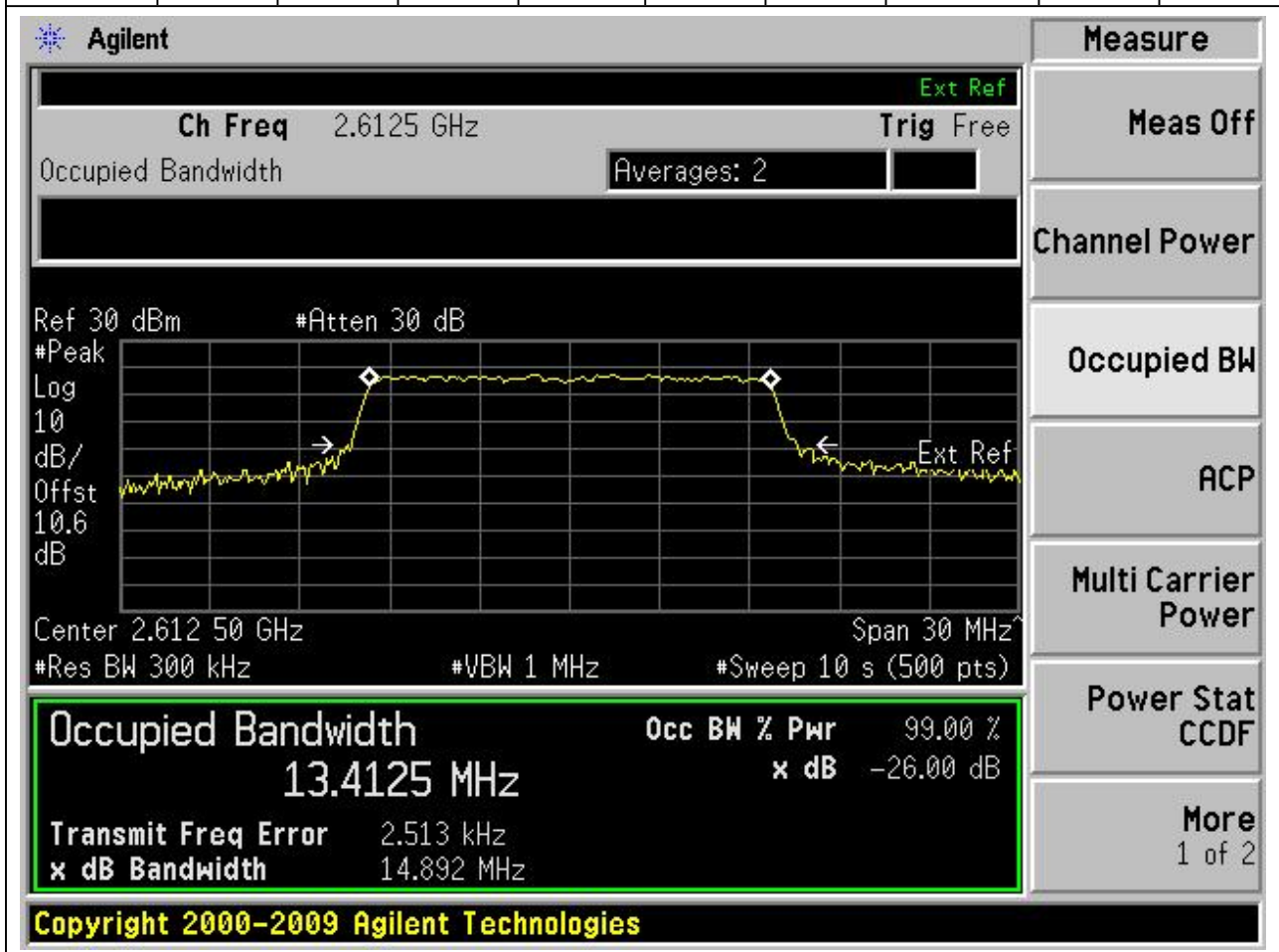
5.17. LTE Occupied Bandwidth_Part22-24-27(Channel:38175, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2612.5	99	26	0.3	Peak	10.59	13.41	14.89	15	Pass



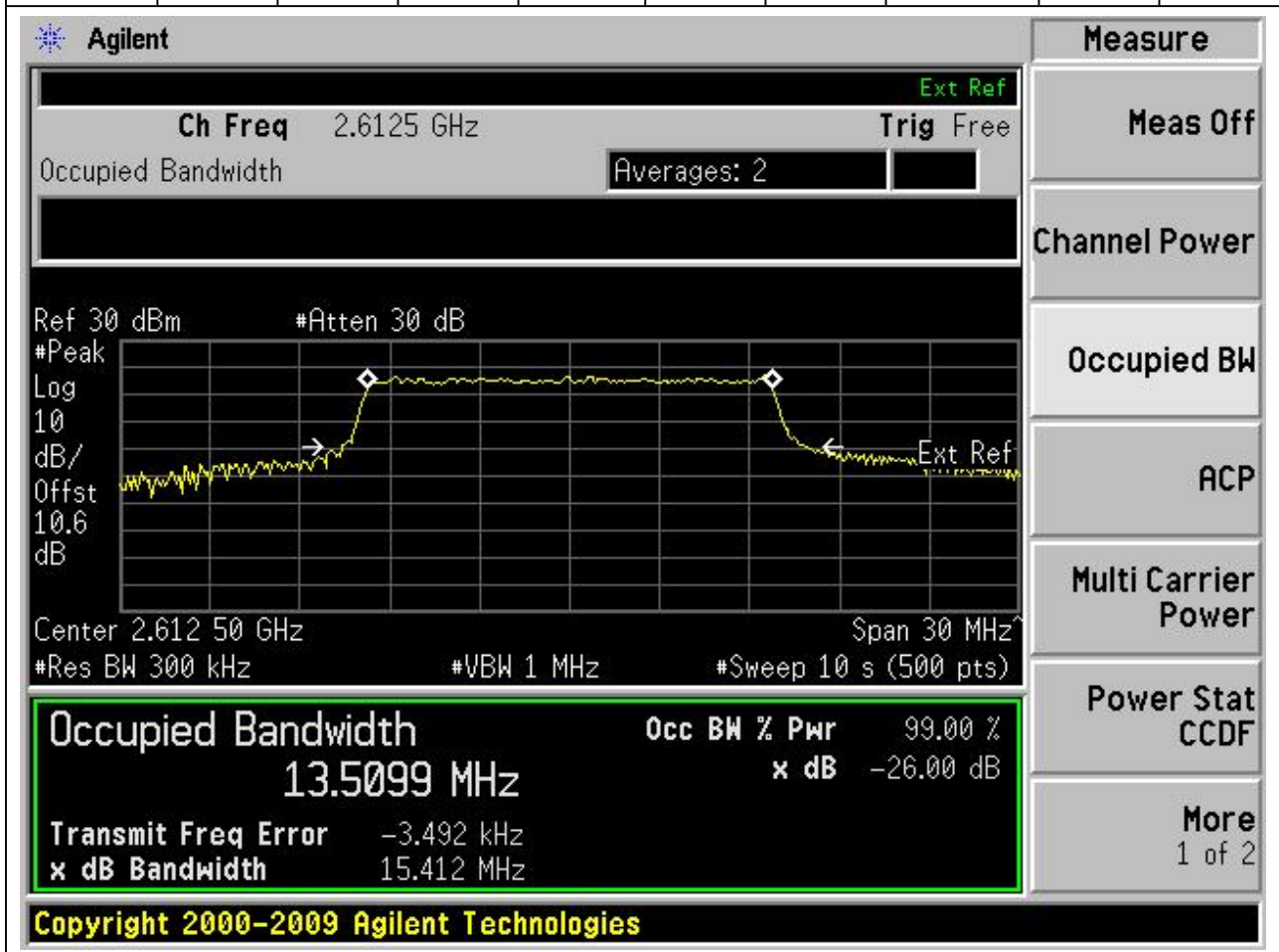
5.18. LTE Occupied Bandwidth_Part22-24-27(Channel:38175, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2612.5	99	26	0.3	Peak	10.59	13.51	15.41	15	Pass



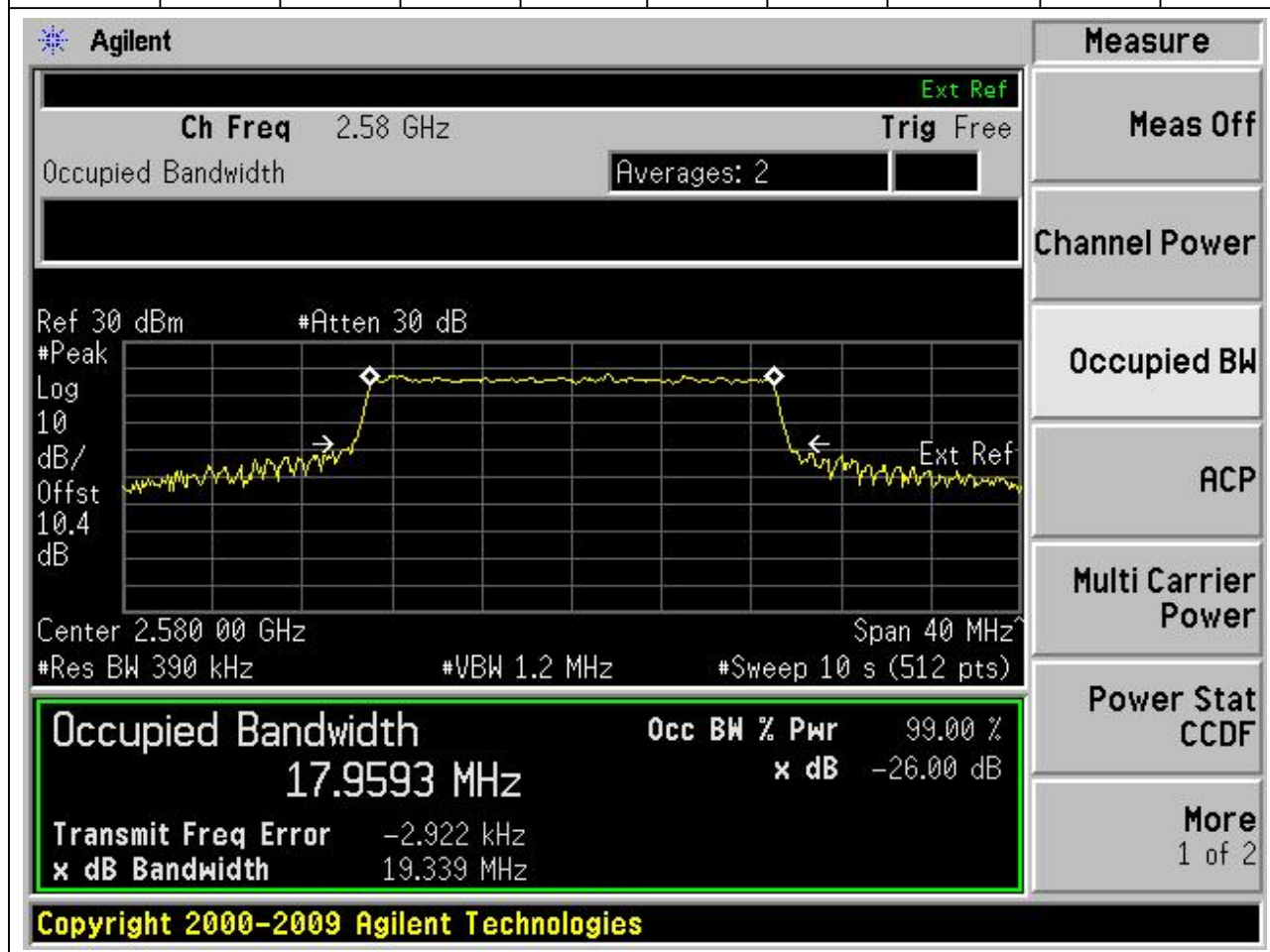
5.19. LTE Occupied Bandwidth_Part22-24-27(Channel:37850, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2580	99	26	0.39	Peak	10.43	17.96	19.34	20	Pass



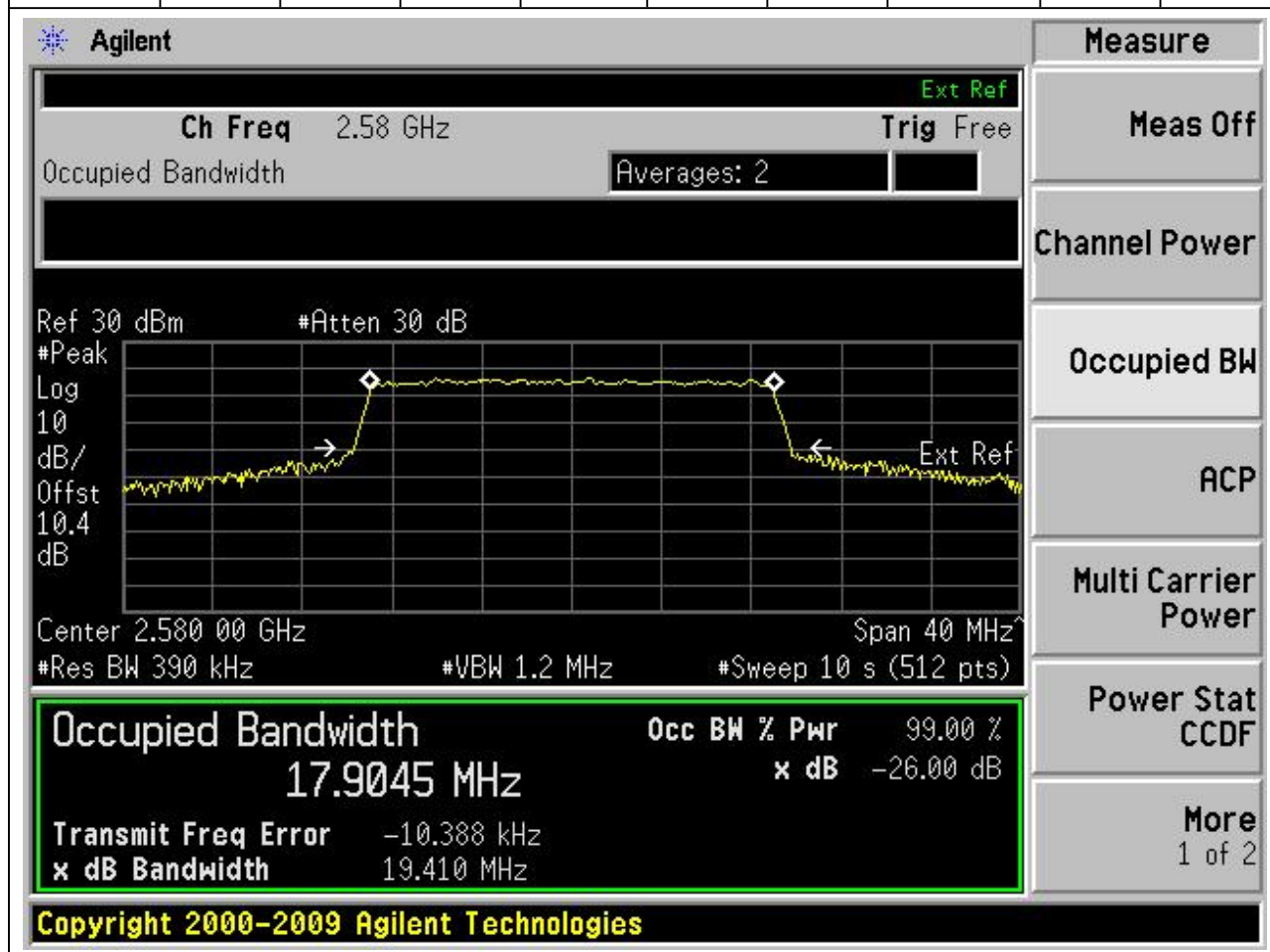
5.20. LTE Occupied Bandwidth_Part22-24-27(Channel:37850, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2580	99	26	0.39	Peak	10.43	17.9	19.41	20	Pass



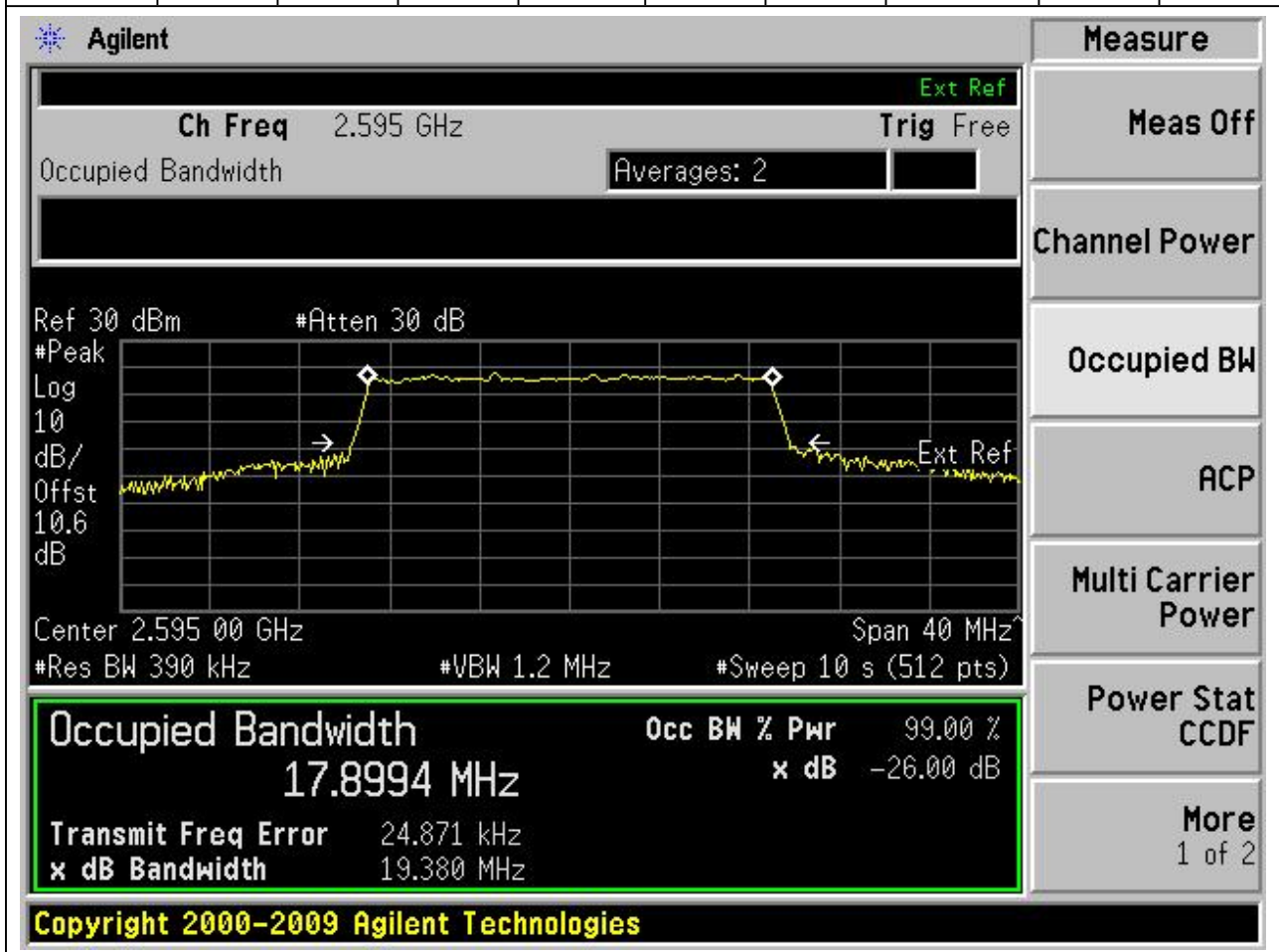
5.21. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.39	Peak	10.55	17.9	19.38	20	Pass



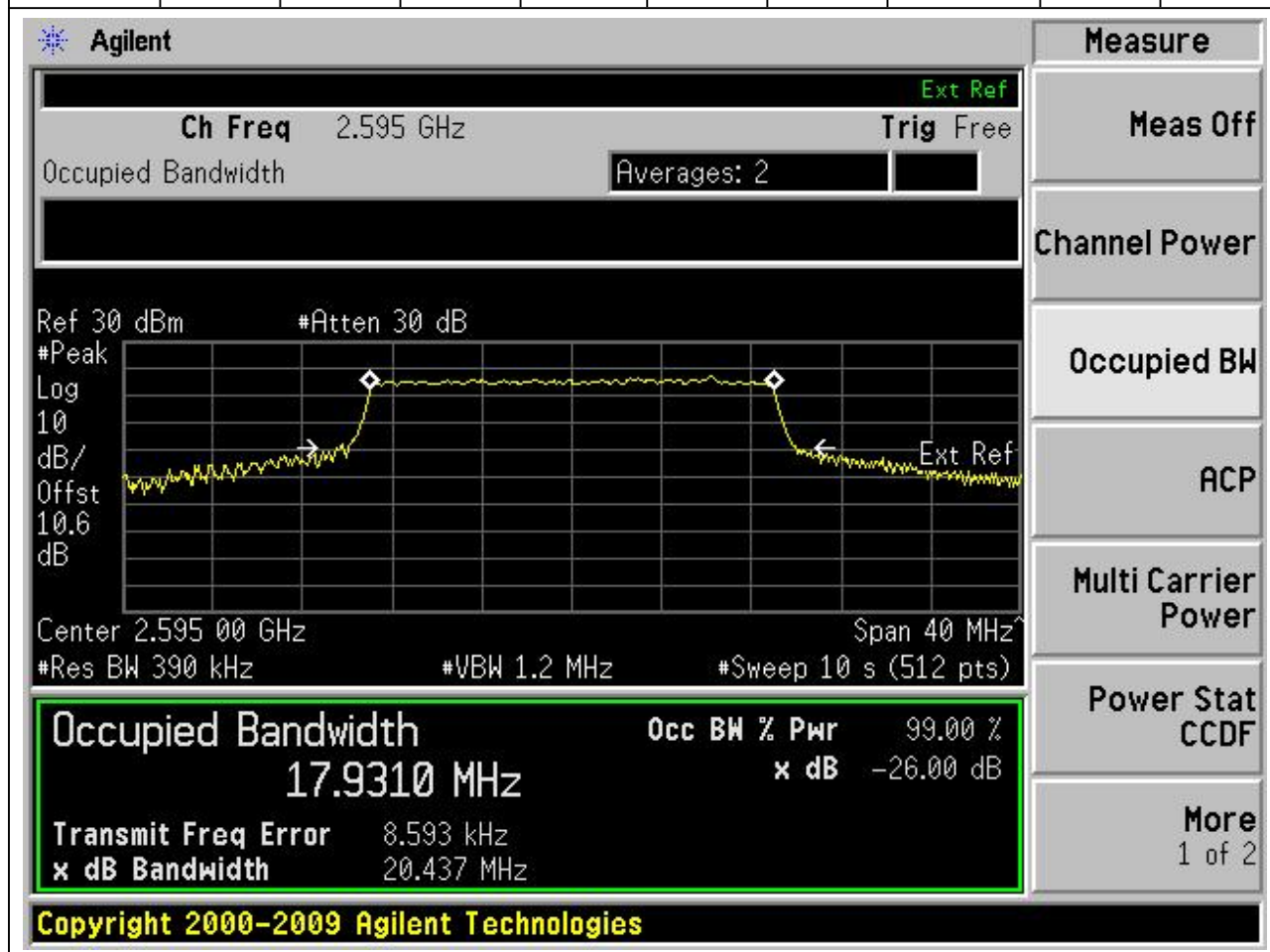
5.22. LTE Occupied Bandwidth_Part22-24-27(Channel:38000, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.39	Peak	10.55	17.93	20.44	20	Pass



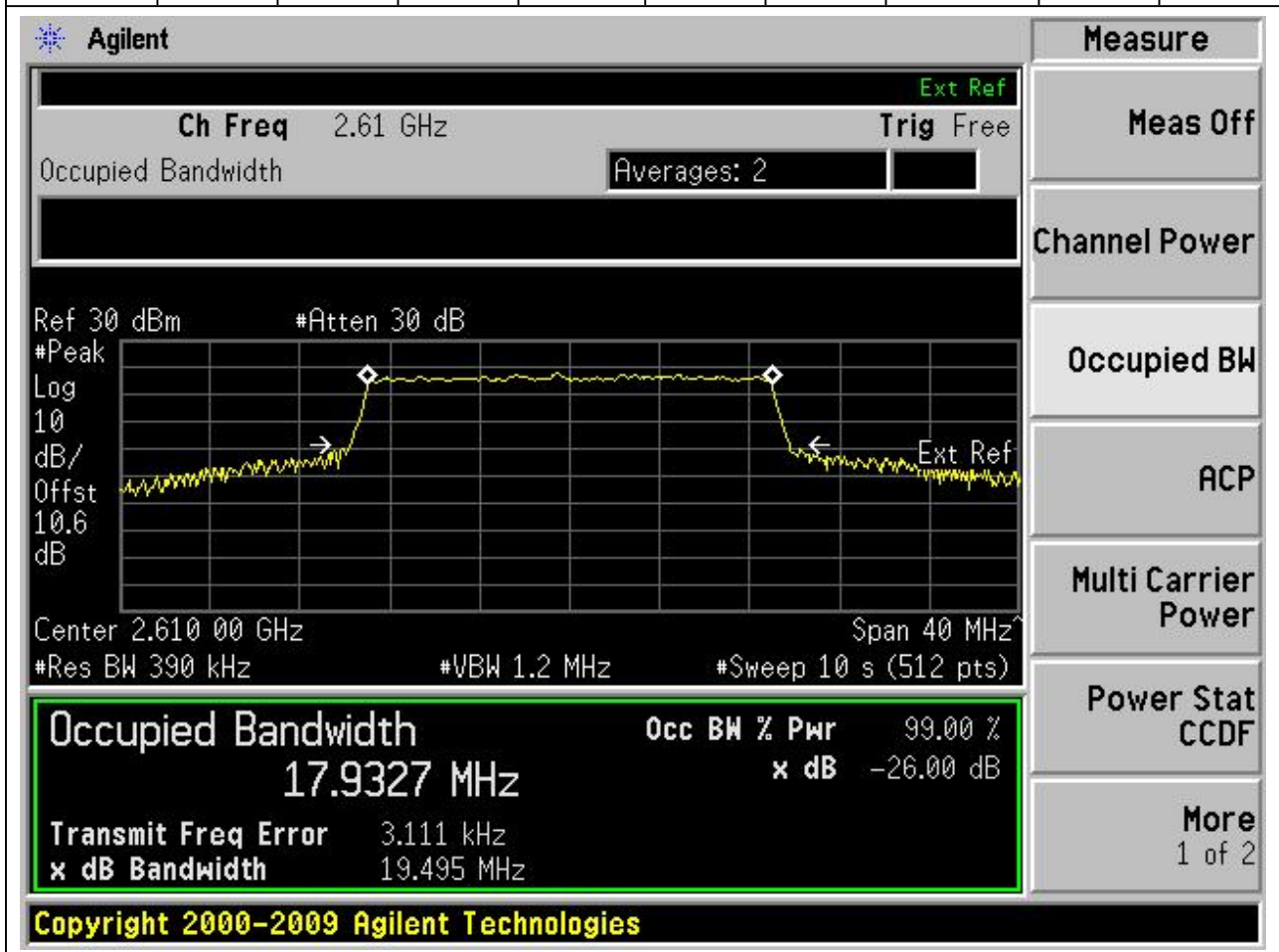
5.23. LTE Occupied Bandwidth_Part22-24-27(Channel:38150, Bandwidth:20, Modulation:QPSK, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2610	99	26	0.39	Peak	10.57	17.93	19.5	20	Pass



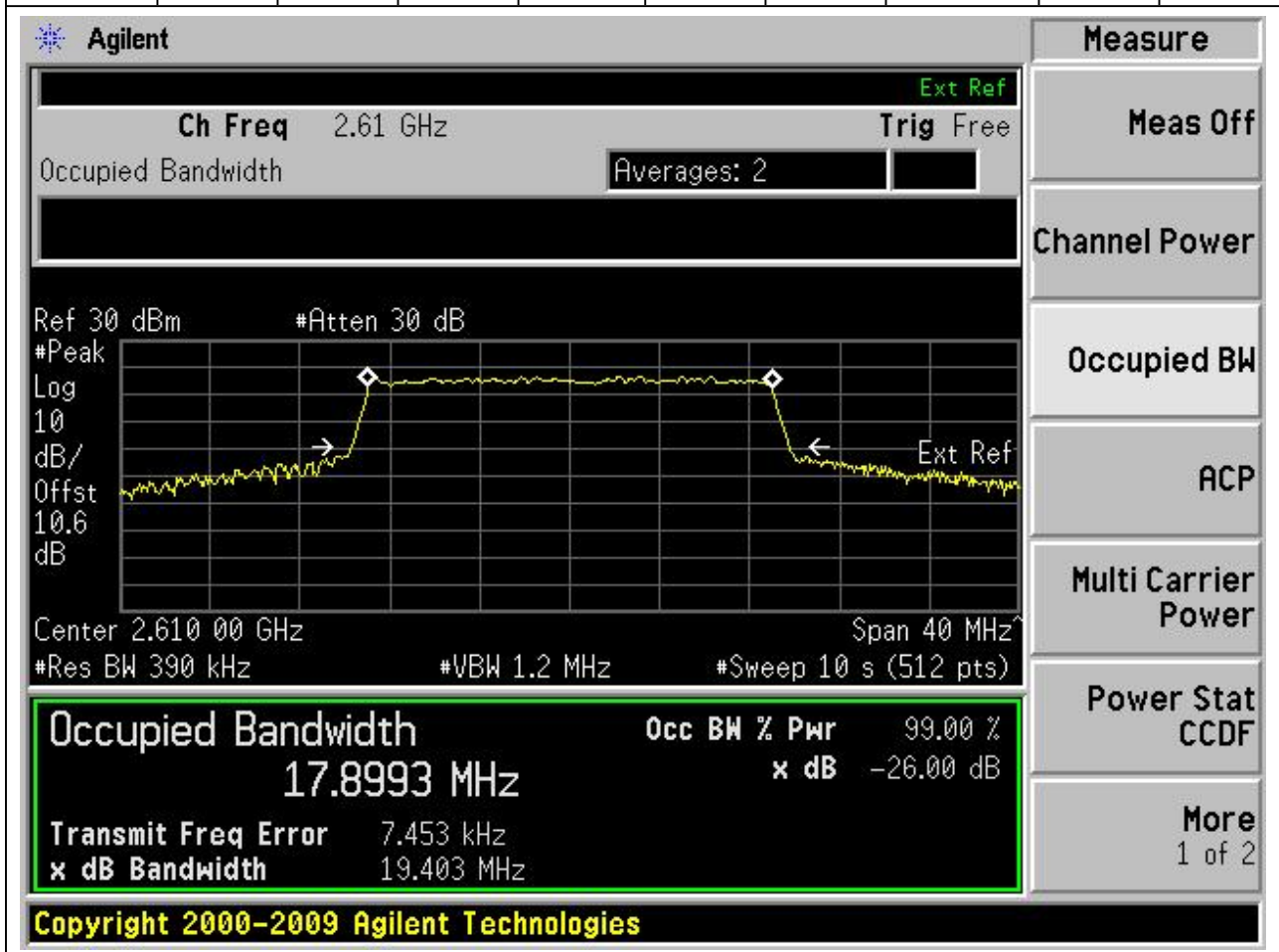
5.24. LTE Occupied Bandwidth_Part22-24-27(Channel:38150, Bandwidth:20, Modulation:16QAM, RB Number:100, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2610	99	26	0.39	Peak	10.57	17.9	19.4	20	Pass



6. LTE_Band41 120M

EUT Sample No.:	
EUT Name:	
EUT Manufacturer:	
EUT Model:	
EUT Serial Number:	
EUT Hardware Version:	
EUT Software Version:	
Low Temperature(LT):	-10 °C
Normal Temperature(NT):	+25 °C
High Temperature(HT):	+55 °C
Low Voltage(LV):	3.6 V
Normal Voltage(NV):	3.8 V
High Voltage(HV):	4.2 V

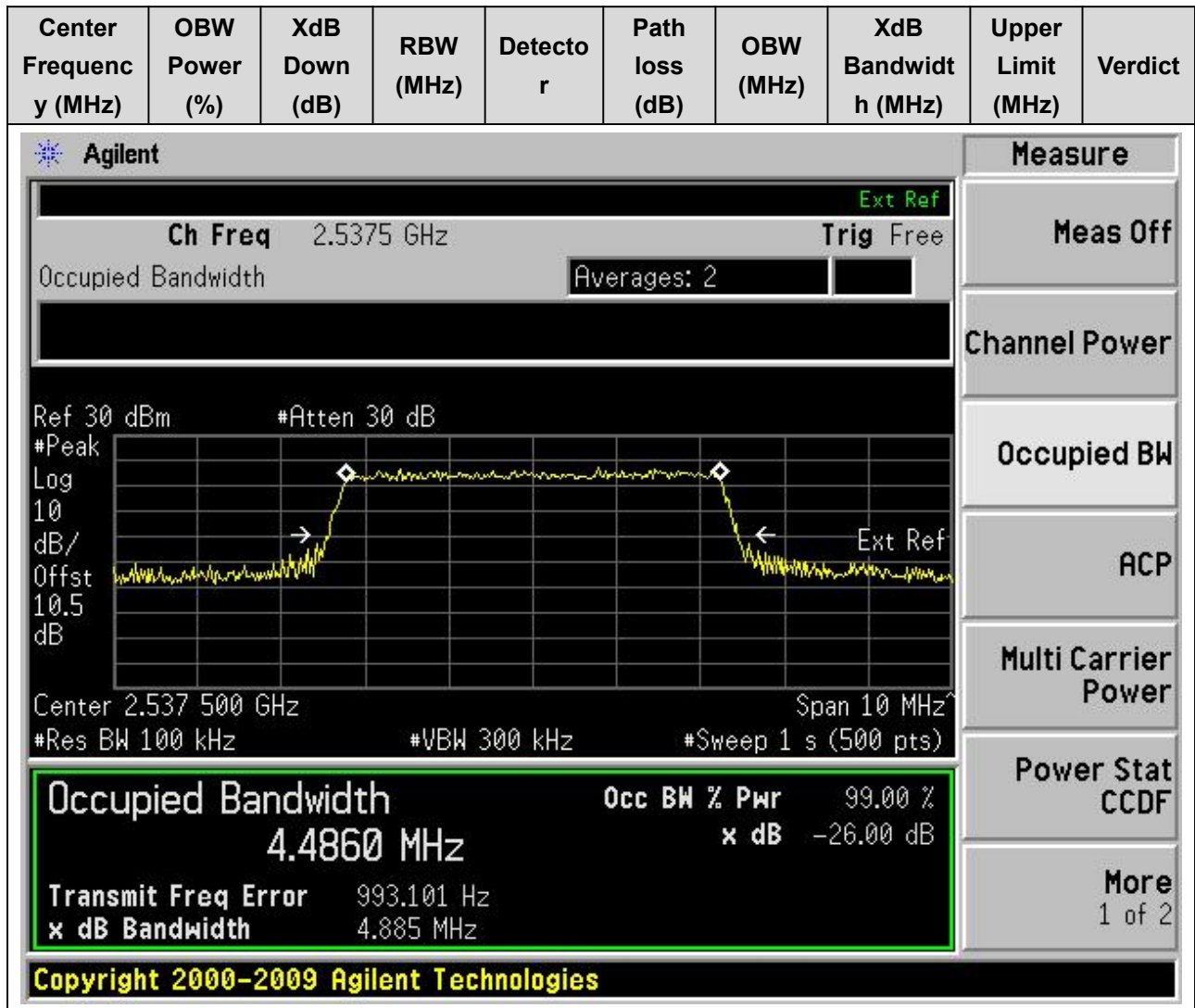
6.1. LTE Occupied Bandwidth_Part22-24-27(Channel:40065, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2537.5	99	26	0.1	Peak	10.46	4.49	4.88	5	Pass



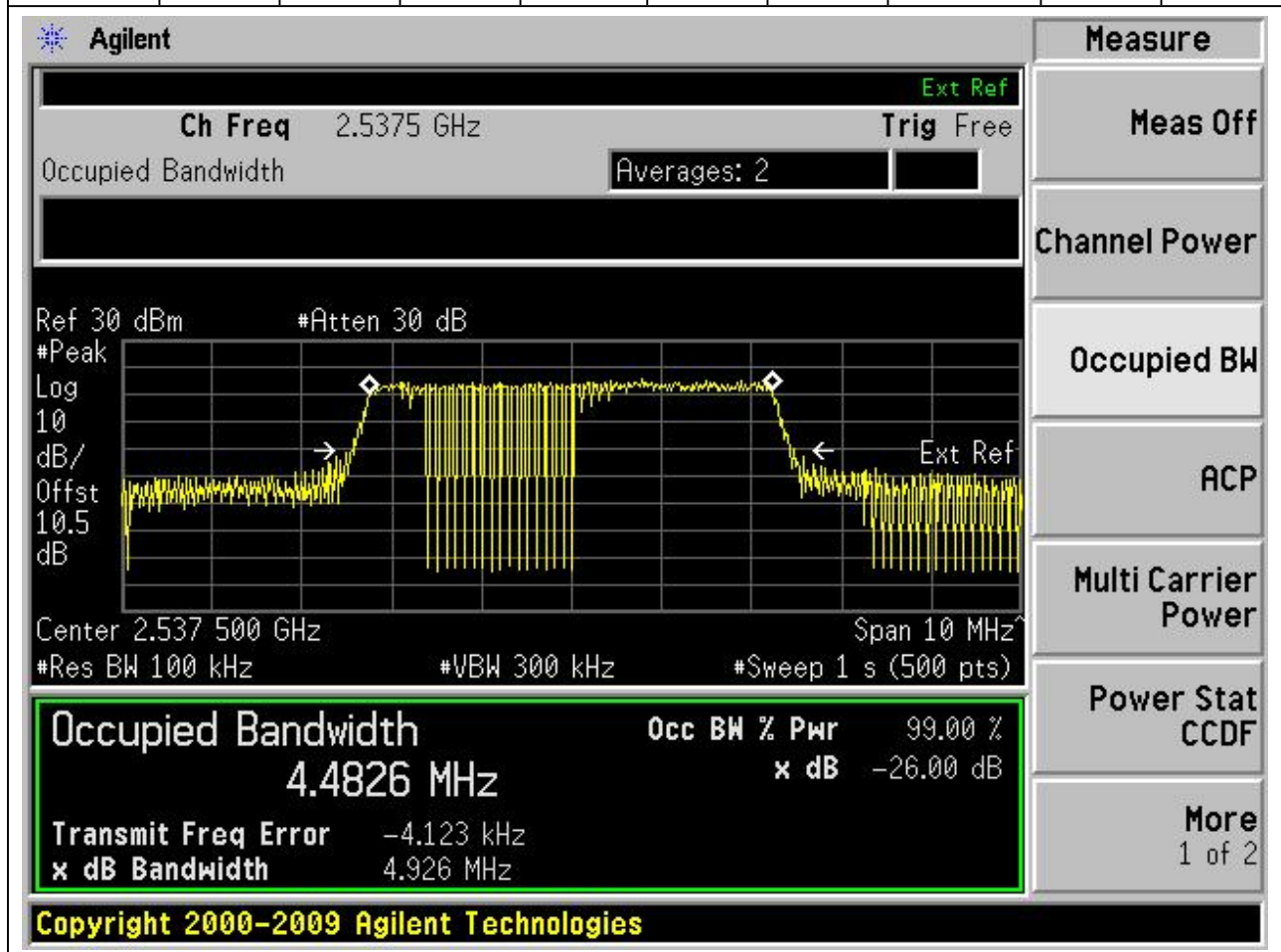
6.2. LTE Occupied Bandwidth_Part22-24-27(Channel:40065, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2537.5	99	26	0.1	Peak	10.46	4.48	4.93	5	Pass



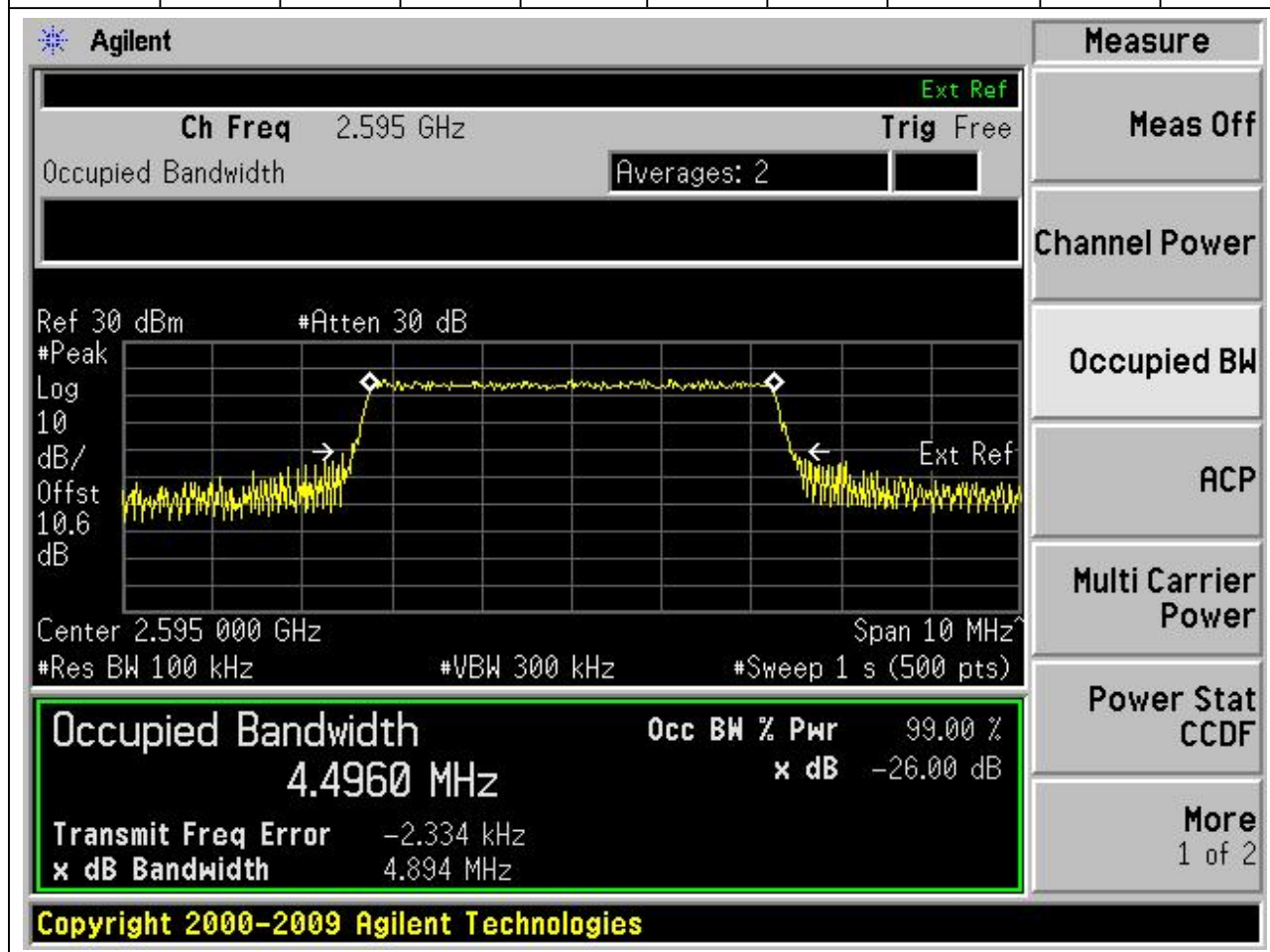
6.3. LTE Occupied Bandwidth_Part22-24-27(Channel:40640, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.1	Peak	10.55	4.5	4.89	5	Pass



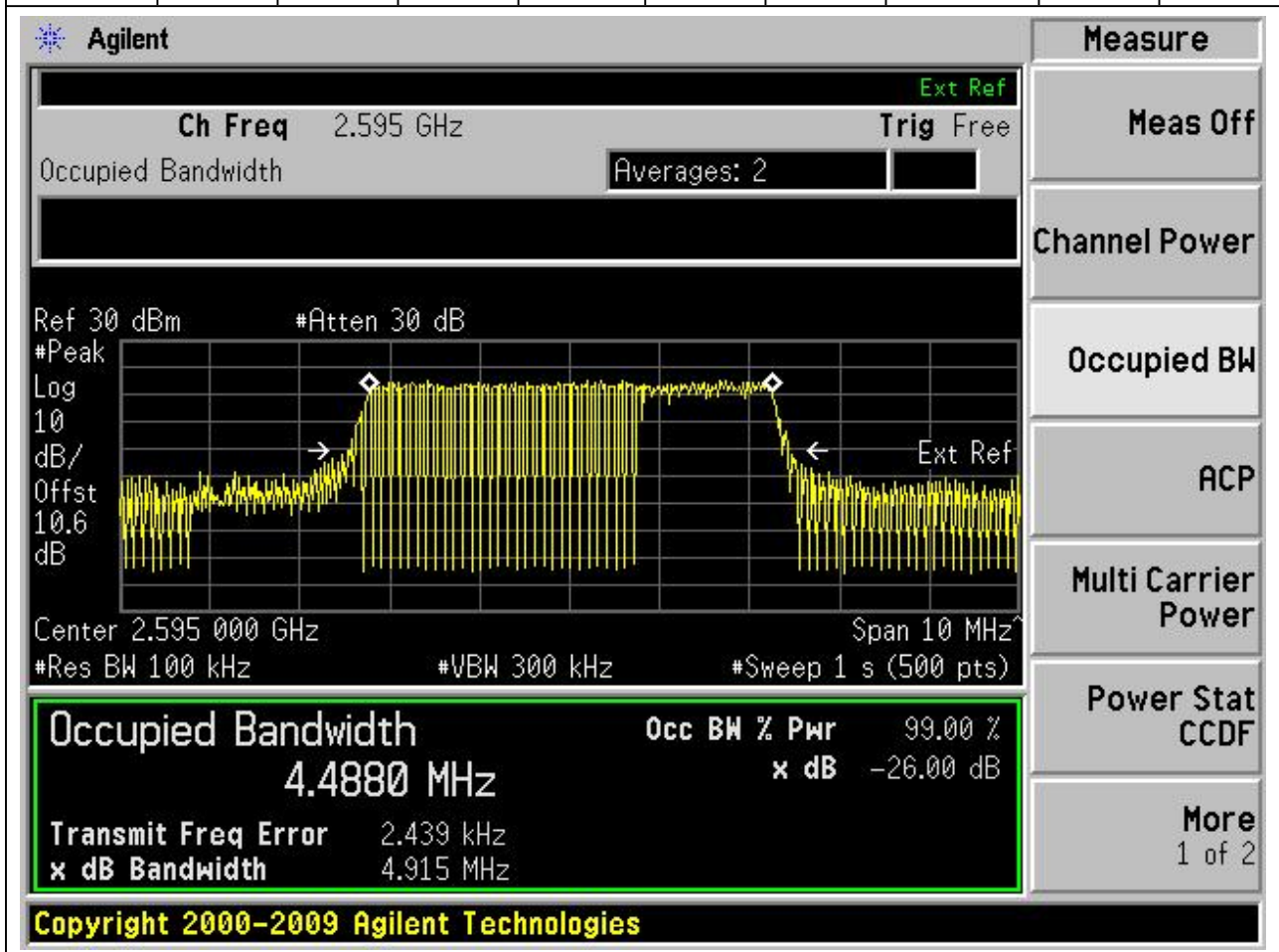
6.4. LTE Occupied Bandwidth_Part22-24-27(Channel:40640, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.1	Peak	10.55	4.49	4.91	5	Pass



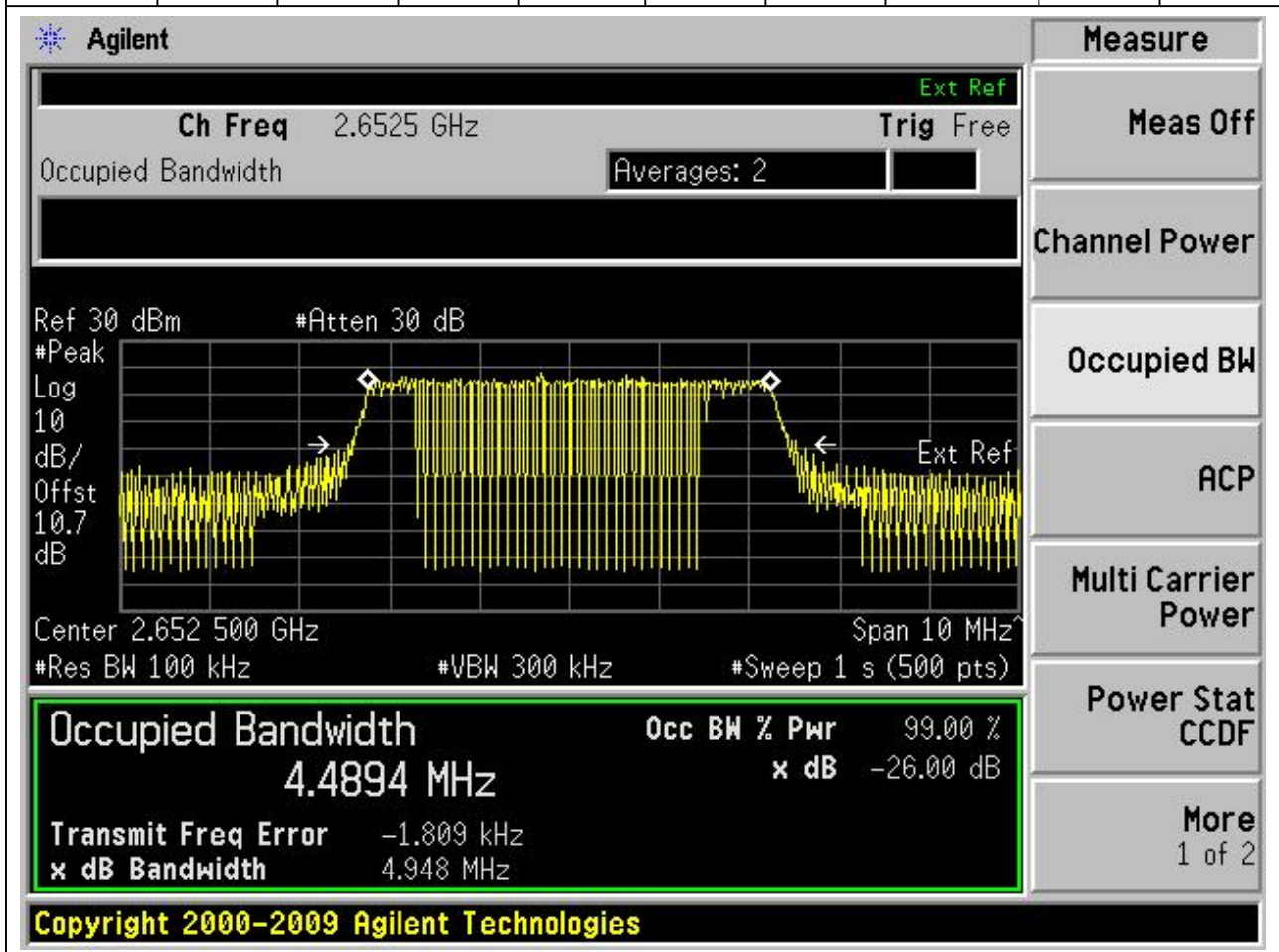
6.5. LTE Occupied Bandwidth_Part22-24-27(Channel:41215, Bandwidth:5, Modulation:QPSK, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2652.5	99	26	0.1	Peak	10.72	4.49	4.95	5	Pass



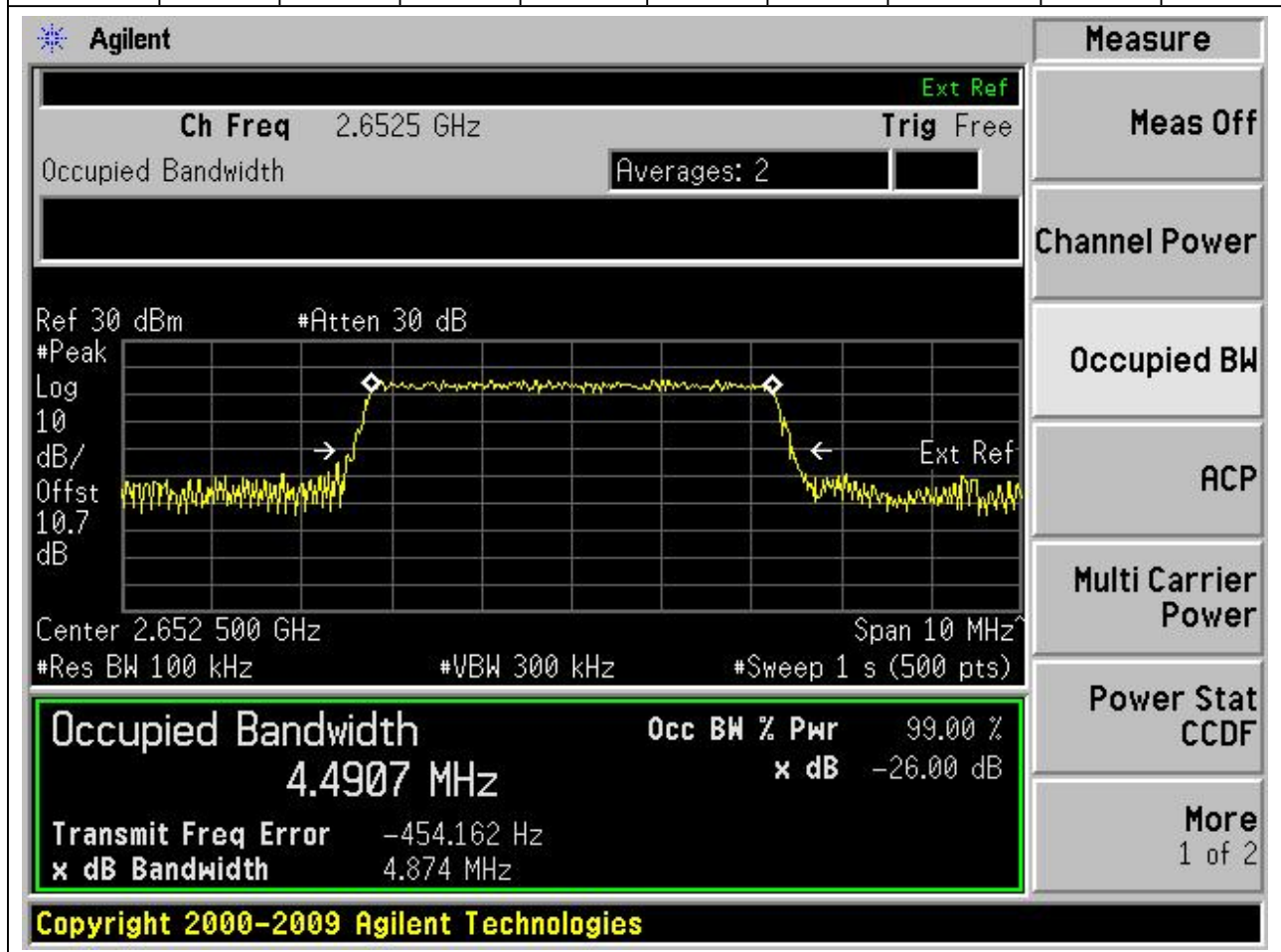
6.6. LTE Occupied Bandwidth_Part22-24-27(Channel:41215, Bandwidth:5, Modulation:16QAM, RB Number:25, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2652.5	99	26	0.1	Peak	10.72	4.49	4.87	5	Pass



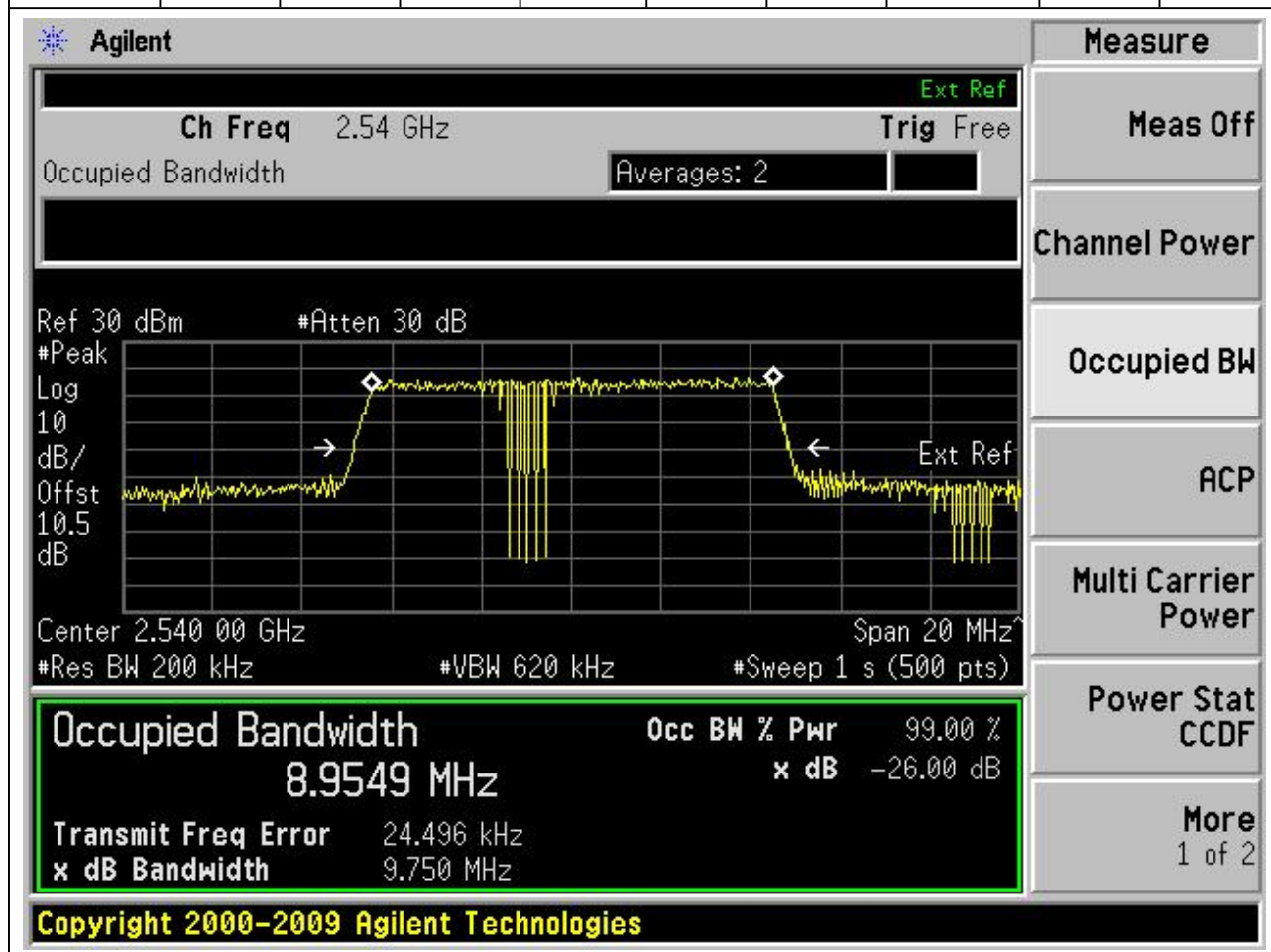
6.7. LTE Occupied Bandwidth_Part22-24-27(Channel:40090, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2540	99	26	0.2	Peak	10.45	8.95	9.75	10	Pass



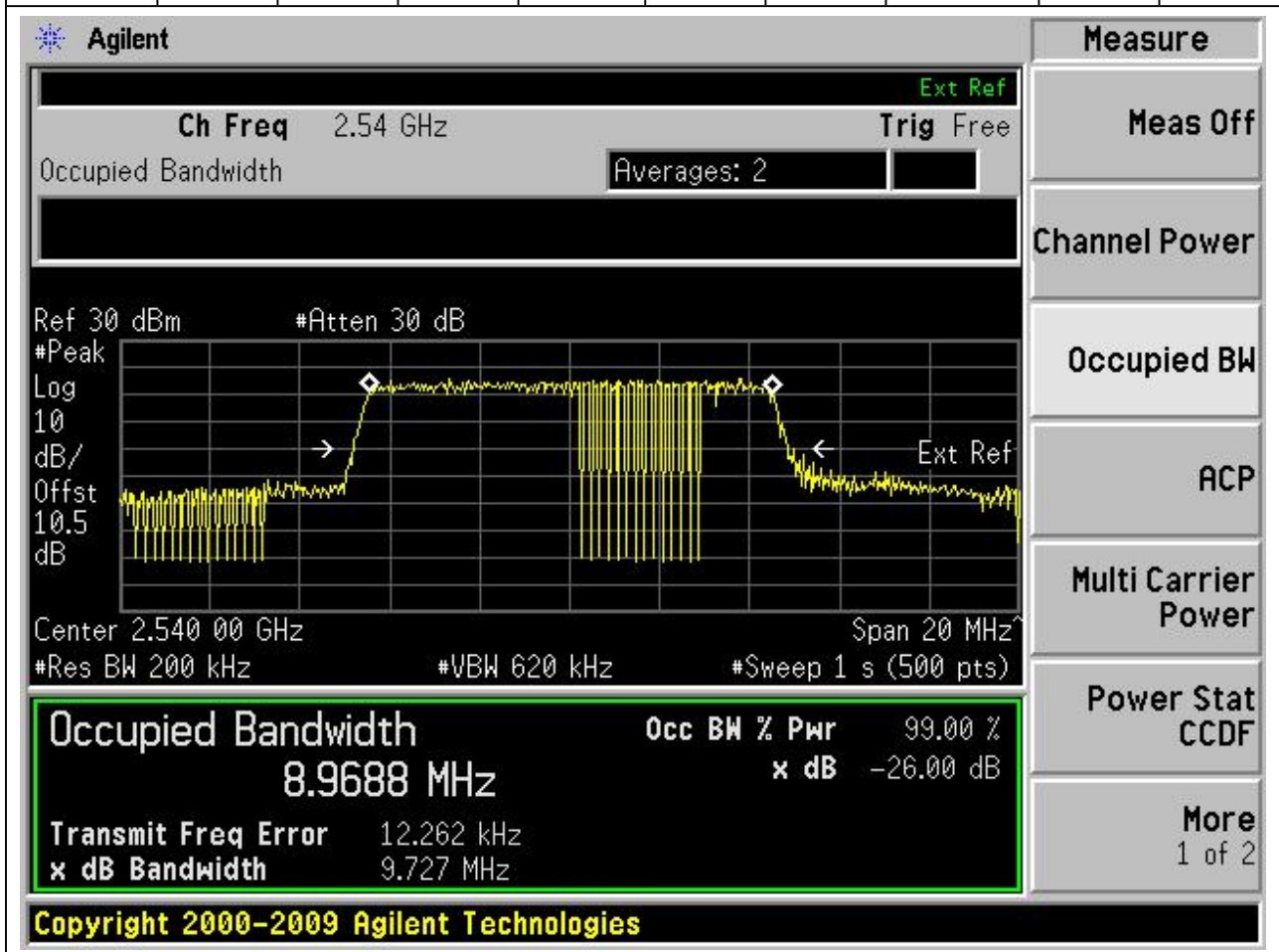
6.8. LTE Occupied Bandwidth_Part22-24-27(Channel:40090, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2540	99	26	0.2	Peak	10.45	8.97	9.73	10	Pass



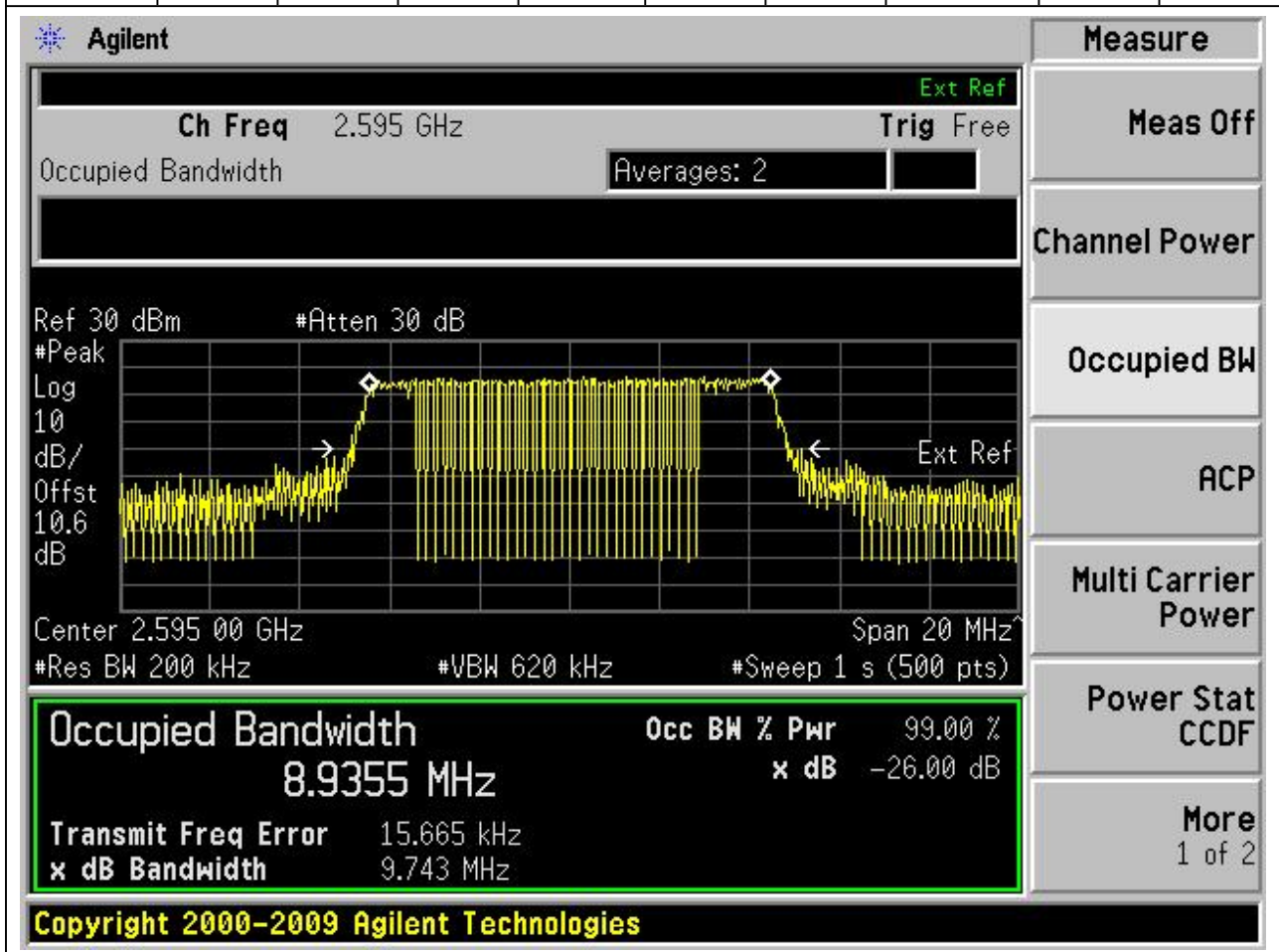
6.9. LTE Occupied Bandwidth_Part22-24-27(Channel:40640, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.2	Peak	10.55	8.94	9.74	10	Pass



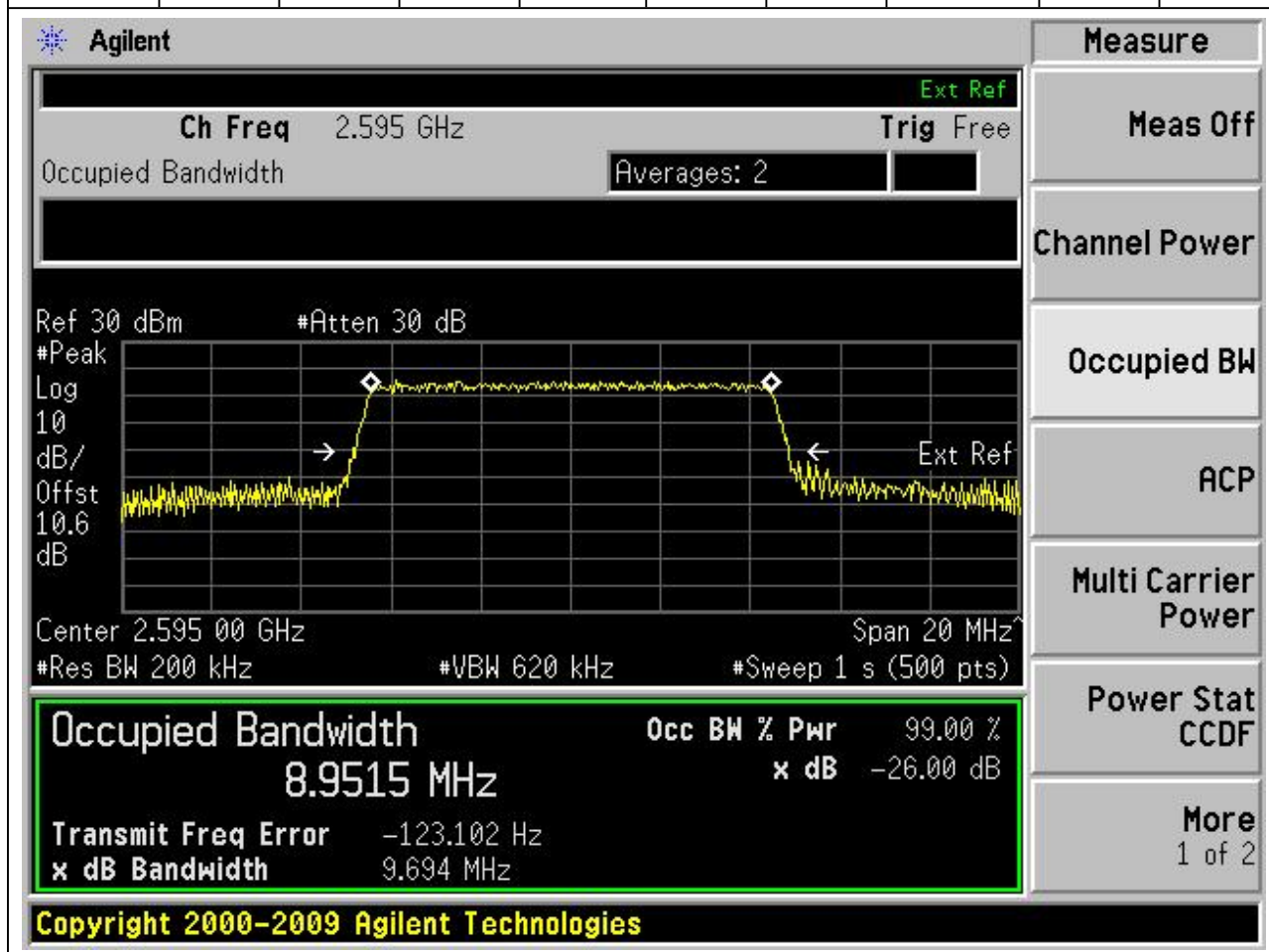
6.10. LTE Occupied Bandwidth_Part22-24-27(Channel:40640, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.2	Peak	10.55	8.95	9.69	10	Pass



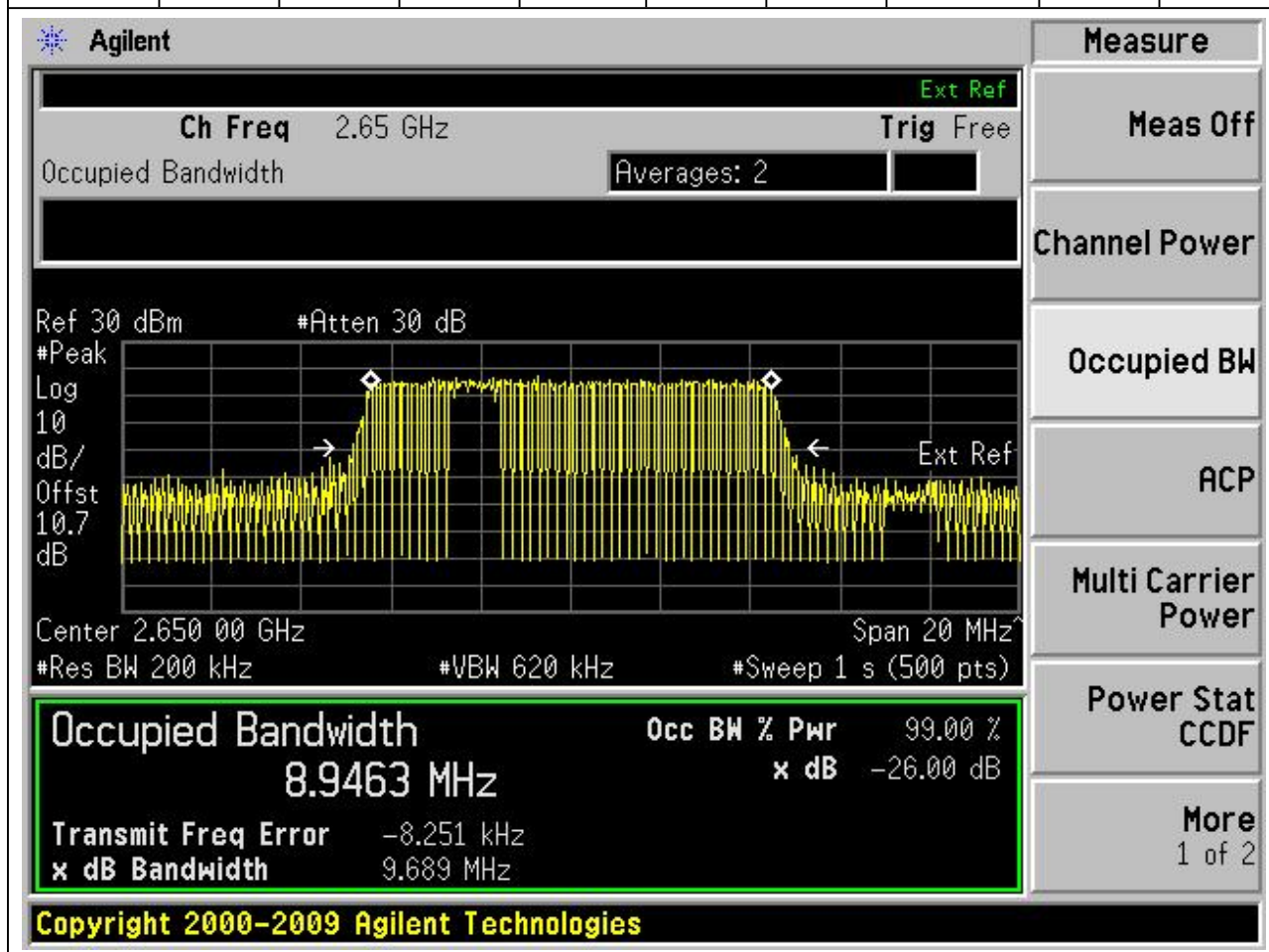
6.11. LTE Occupied Bandwidth_Part22-24-27(Channel:41190, Bandwidth:10, Modulation:QPSK, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2650	99	26	0.2	Peak	10.73	8.95	9.69	10	Pass



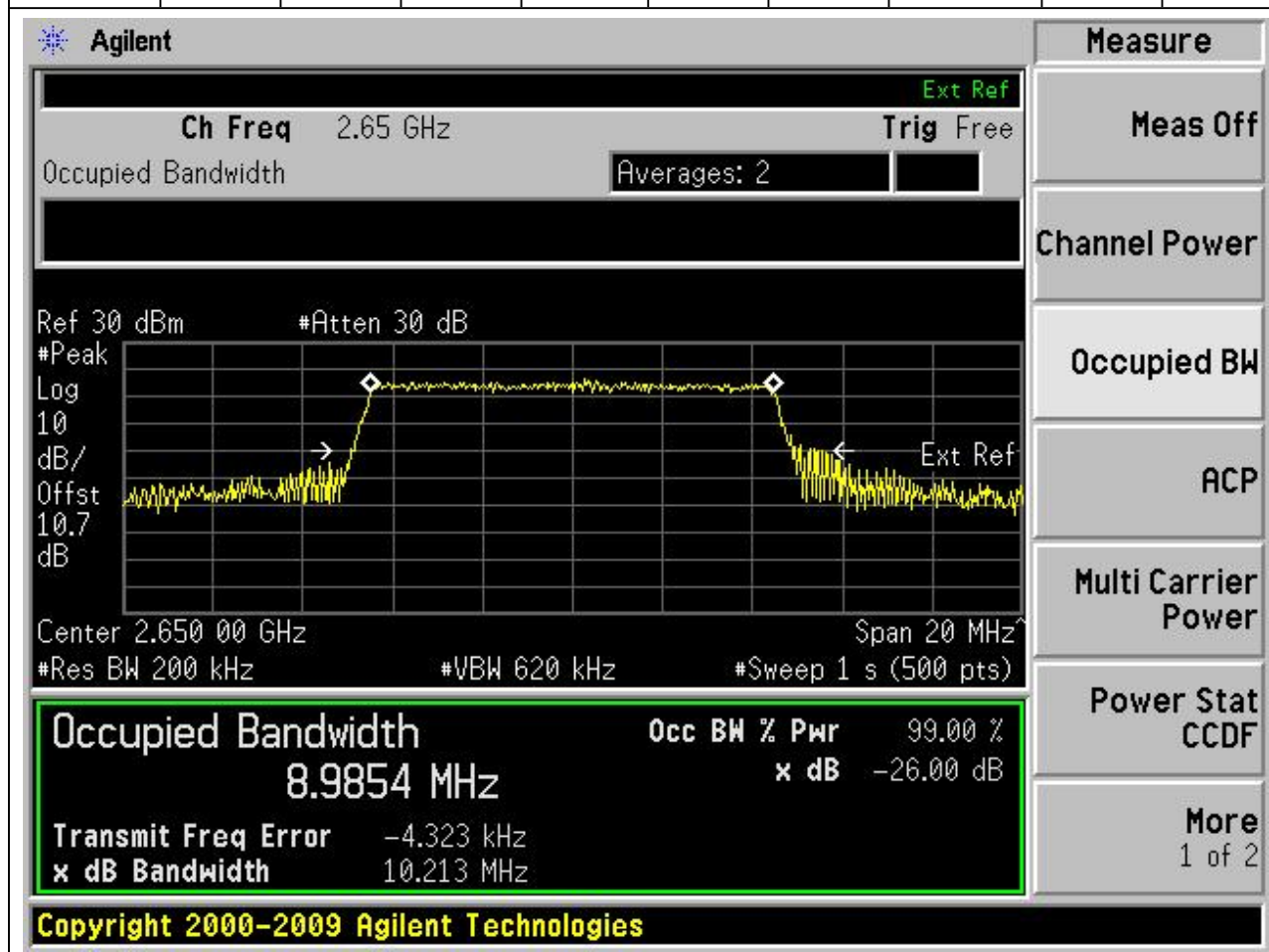
6.12. LTE Occupied Bandwidth_Part22-24-27(Channel:41190, Bandwidth:10, Modulation:16QAM, RB Number:50, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2650	99	26	0.2	Peak	10.73	8.99	10.21	10	Pass



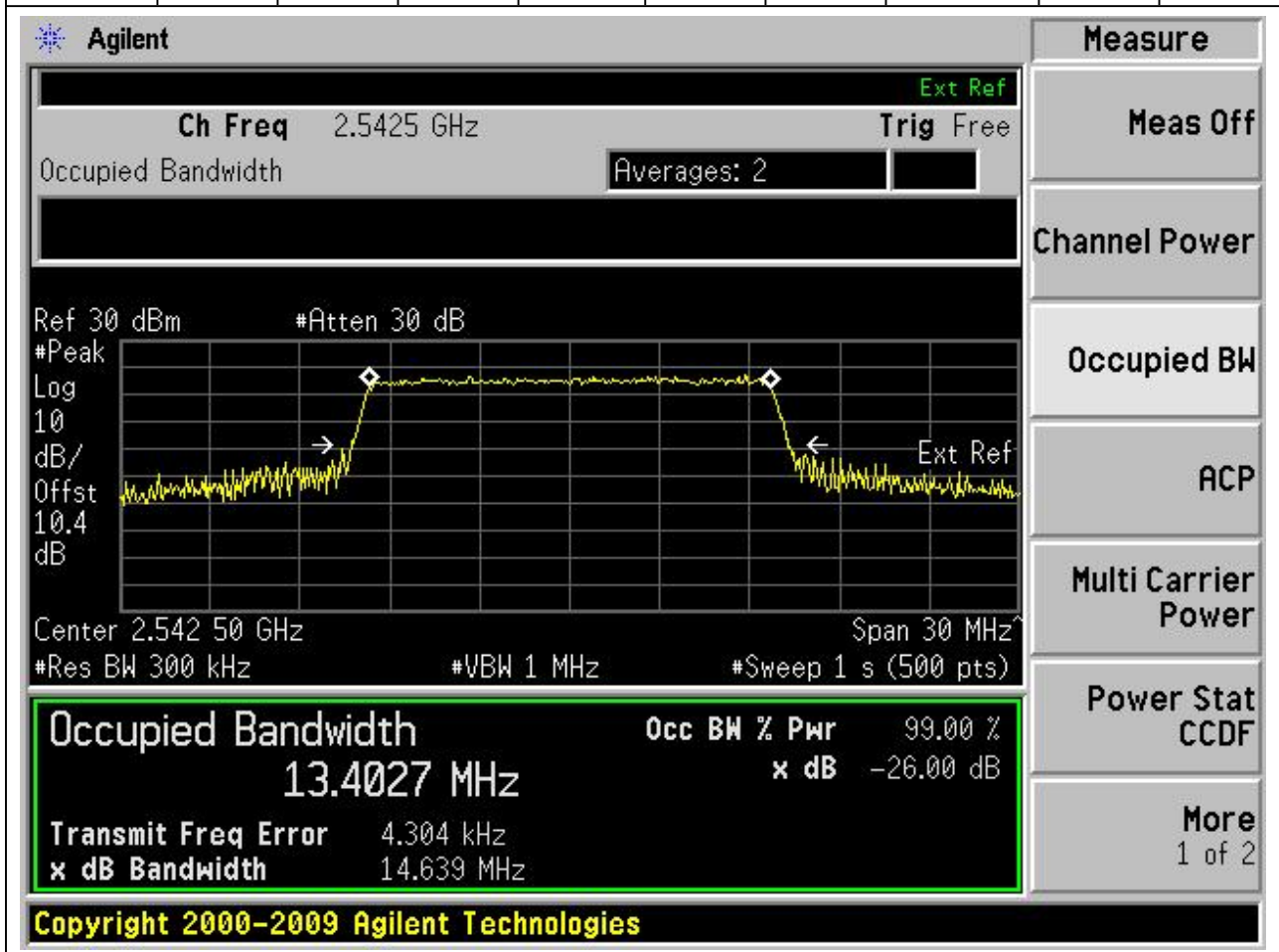
6.13. LTE Occupied Bandwidth_Part22-24-27(Channel:40115, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2542.5	99	26	0.3	Peak	10.44	13.4	14.64	15	Pass



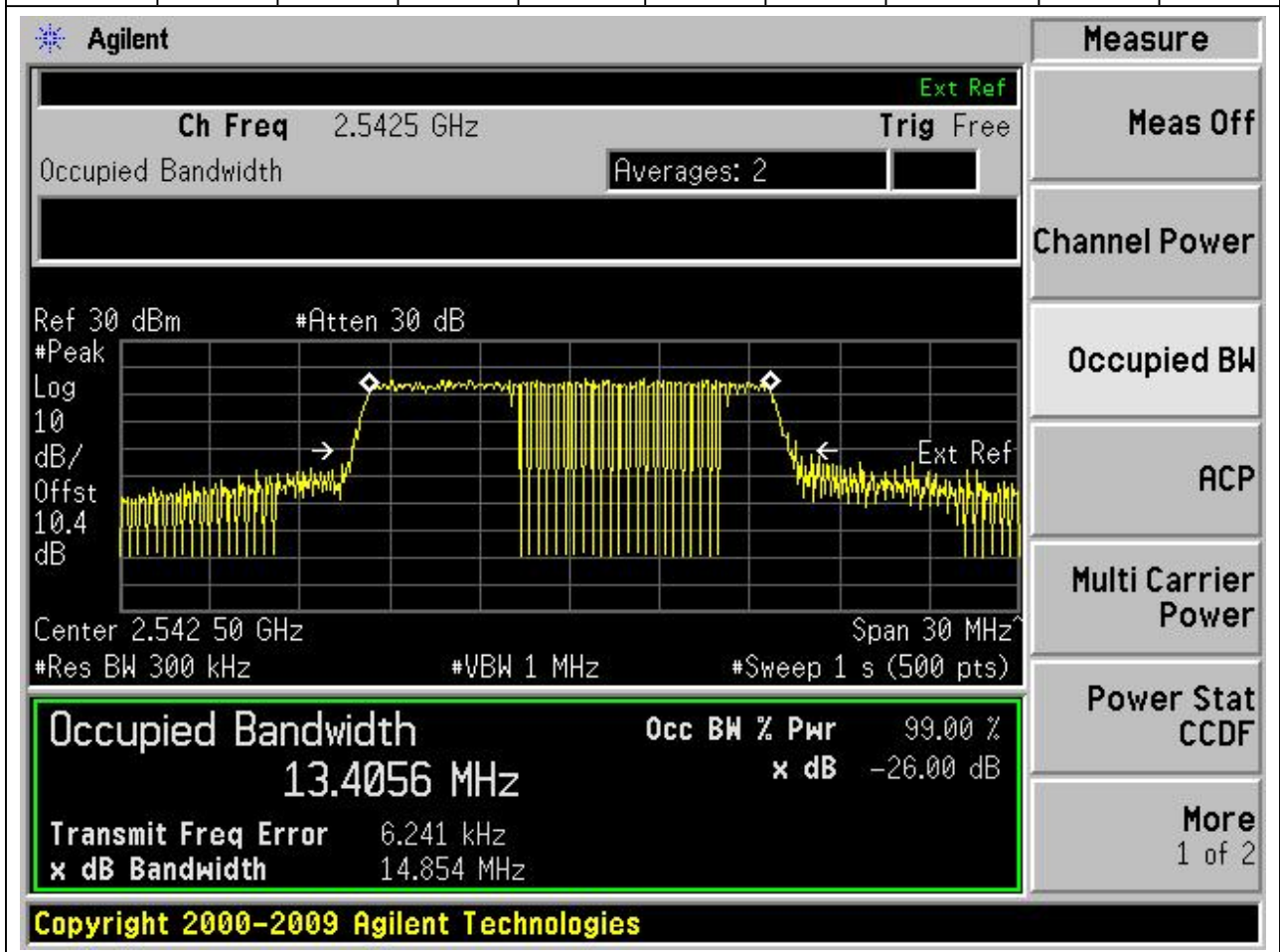
6.14. LTE Occupied Bandwidth_Part22-24-27(Channel:40115, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2542.5	99	26	0.3	Peak	10.44	13.41	14.85	15	Pass



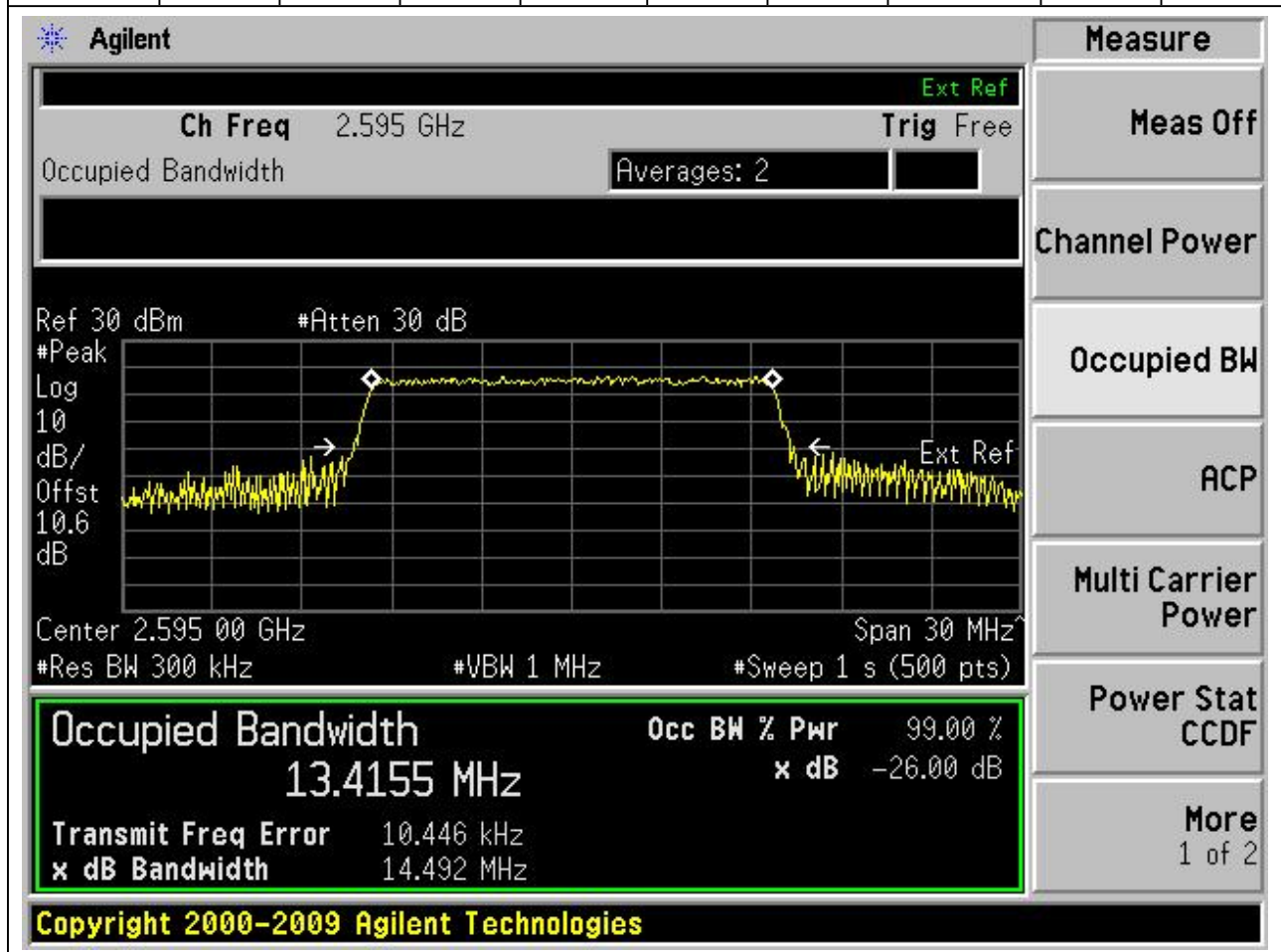
6.15. LTE Occupied Bandwidth_Part22-24-27(Channel:40640, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.3	Peak	10.55	13.42	14.49	15	Pass



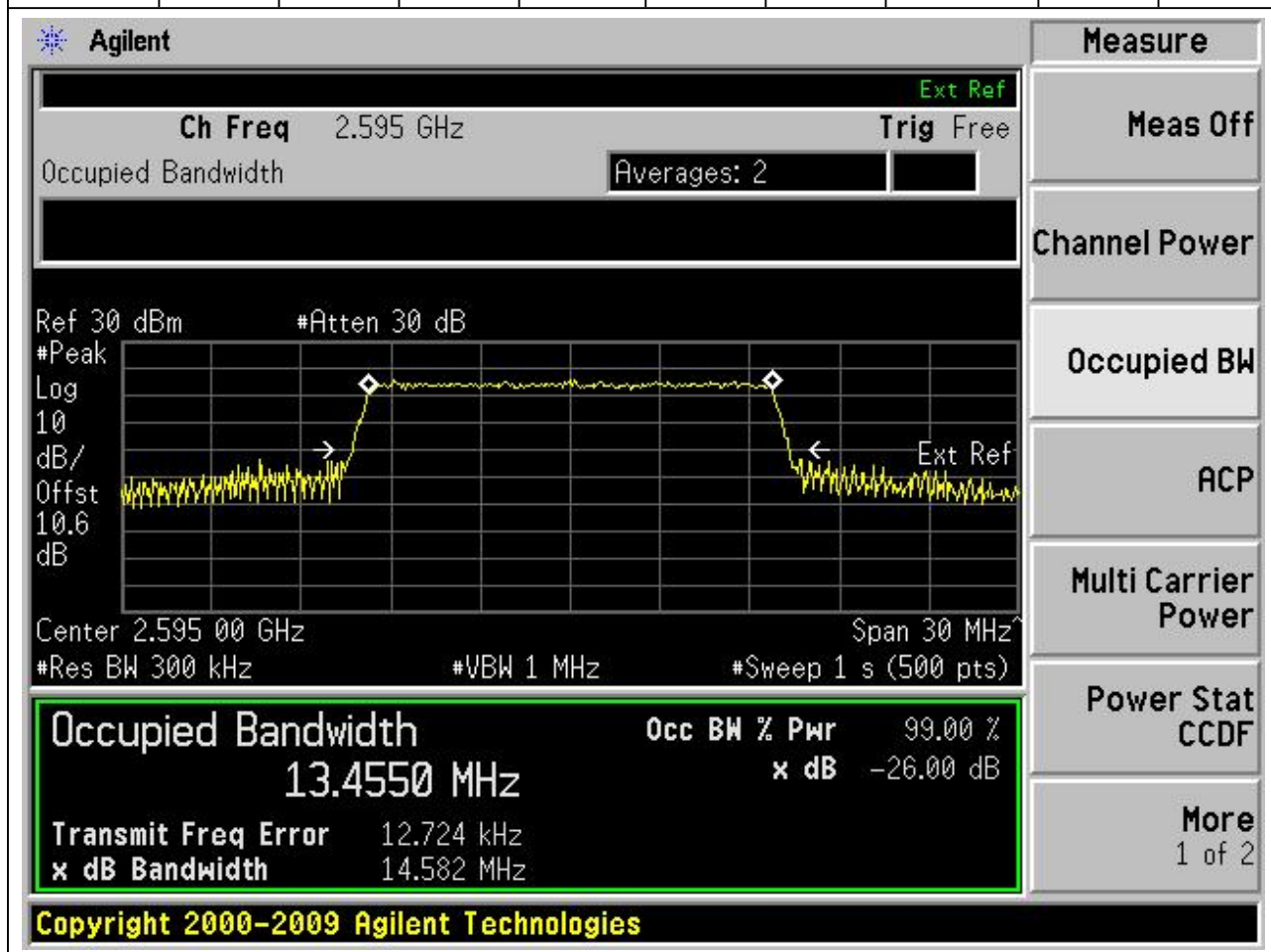
6.16. LTE Occupied Bandwidth_Part22-24-27(Channel:40640, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2595	99	26	0.3	Peak	10.55	13.46	14.58	15	Pass



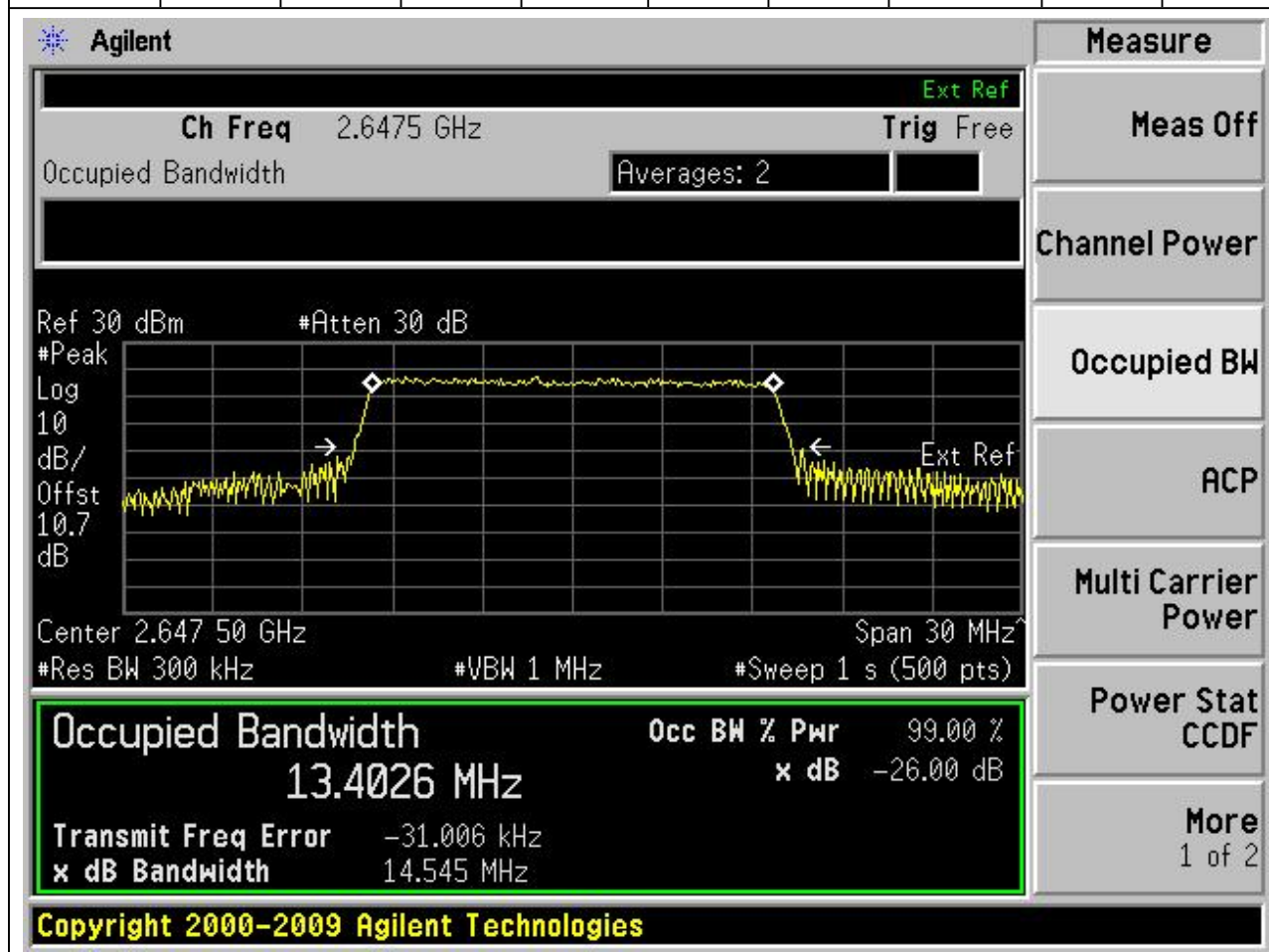
6.17. LTE Occupied Bandwidth_Part22-24-27(Channel:41165, Bandwidth:15, Modulation:QPSK, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2647.5	99	26	0.3	Peak	10.72	13.4	14.55	15	Pass



6.18. LTE Occupied Bandwidth_Part22-24-27(Channel:41165, Bandwidth:15, Modulation:16QAM, RB Number:75, RB Position:0)

Operator:

Test time: 2026-01-30

Instrument Type	Instrument Manufacturer	Instrument Model	Instrument Serial Number	Instrument Firmware Version
LTE Tester	Rohde&Schwarz	CMW	1201.0002k50/107917	3.7.110
Spectrum Analyzer	Agilent Technologies	E4440A	MY48250809	A.11.07

Center Frequency (MHz)	OBW Power (%)	XdB Down (dB)	RBW (MHz)	Detector	Path loss (dB)	OBW (MHz)	XdB Bandwidth (MHz)	Upper Limit (MHz)	Verdict
2647.5	99	26	0.3	Peak	10.72	13.46	15.21	15	Pass

